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This index covers all technical items - papers, correspondence, reviews, etc. - that appeared in this periodical during 1997, and items from previous years that were commented upon or corrected in 1997.

The Author Index contains the primary entry for each item, listed under the first author's name, and cross-references from all coauthors. The Subject Index contains several entries for each item under appropriate subject headings, and subject cross-references.

It is always necessary to refer to the primary entry in the Author Index for the exact title, coauthors, and comments/corrections.

AUTHOR INDEX

A

Abbas, F., *see* Gallop, J.C., *T-IM Apr 97* 122-125
Abdipour, A., *see* Bareau, P., *T-IM Aug 97* 1044-1048
Acef, O. CO$_2$/OsO$_4$ lasers as frequency standards in the 29 THz range; *T-IM Apr 97* 162-165
Ahlers, F.J., *see* Wolf, H., *T-IM Apr 97* 303-306
Ahmad, H., A.J. Al-Khalili, L.M. Landsberger, and M. Kahrizi. A two-dimensional micromachined accelerometer; *T-IM Feb 97* 18-26
Ahola, T., *see* Hu, J., *T-IM Apr 97* 186-190
Aida, M., *see* Morikawa, T., *T-IM Apr 97* 216-219
Akhiezer, A.N., A.P. Senko, and V.P. Seredniy. Millimeter wave power standards; *T-IM Apr 97* 495-498
Alam, M.S., *see* Mauritzen, D.W., *T-IM Dec 97* 1300-1301
Alexander, M.J., and M.J. Salter. The design of dipole and monopole antennas with low uncertainties; *T-IM Apr 97* 539-543
Al-Khalili, A.J., *see* Ahmad, H., *T-IM Feb 97* 18-26
Aman, J., *see* Zarka, A., *T-IM Apr 97* 145-148
Anderson, K.F. The new current loop: an instrumentation and measurement circuit topology; *T-IM Oct 97* 1061-1067
Andreev, K.E., *see* Gudoshnikov, S.A., *T-IM Apr 97* 624-628
Andreone, D., *see* Godone, A., *T-IM Apr 97* 246-249
Andreone, D., L. Brunetti, C. Giordanino, and M. Petrizzelli. Calorimetric measurements of microwave surface resistance at cryogenic temperatures; *T-IM Apr 97* 535-538
Aoki, T., and K. Yokoi. Capacitance scaling system; *T-IM Apr 97* 474-476
Arpaia, P., A. Baccigalupi, and F. Cennamo. Techniques of improved signal extraction in scan conversion-based transient digitizers; *T-IM Aug 97* 893-898
Arseneau, R., P.S. Filipski, and J.J. Zelle. An improved three-phase digital recorder system for calibrating power instrumentation; *T-IM Apr 97* 399-402
Arya, V., D.W. Sherrer, A. Wang, R.O. Claus, and M. Jones. Application of thin-film optical filters to the temperature compensation of optical fiber grating-based devices; *T-IM Oct 97* 1173-1177
Ascarrunz, F.G., S.R. Jefferts, and T.E. Parker. Earth station errors in two-way time and frequency transfer; *T-IM Apr 97* 205-208
Avramov-Zamurovic, S., *see* Oldham, N.M., *T-IM Apr 97* 352-355
Avramov-Zamurovic, S., *see* Oldham, N.M., *T-IM Apr 97* 395-398

B

Bacakoglu, H., and M.S. Kamel. A three-step camera calibration method; *T-IM Oct 97* 1165-1172
Baccigalupi, A., A. Bernieri, and A. Pietrosanto. A digital-signal-processor-based measurement system for on-line fault detection; *T-IM Jun 97* 731-736
Baccigalupi, A., *see* Arpaia, P., *T-IM Aug 97* 893-898
Baltag, O., and D. Costandache. Sensor with ferrofluid for magnetic measurements; *T-IM Apr 97* 629-631
Banning, R. Spectral analysis methods for Poisson sampled measurements; *T-IM Aug 97* 882-887
Baracchino, L., G. Basso, C. Ciofi, and B. Neri. Ultralow-noise programmable voltage source; *T-IM Dec 97* 1256 -1261
Bareau, P., A. Abdipour, and A. Pacaud. A new noise measurement method of noise parameters at microwave frequencies; *T-IM Aug 97* 1044-1048
Bartley, P.G., Jr., *see* Nelson, S.O., *T-IM Aug 97* 941-946
Barwicz, A., *see* Massicotte, D., *T-IM Jun 97* 678-684
Barwicz, A., *see* Slima, M.B., *T-IM Jun 97* 685-689
Barwicz, A., *see* Szczecinski, L., *T-IM Aug 97* 922-928
Barwicz, A., *see* Miekina, A., *T-IM Aug 97* 1049-1053
Barwood, G.P., P. Gill, H.A. Klein, and W.R.C. Rowley. Clearly resolved secular sidebands on the ${}^{2}S_{1}2/$-${}^{2}D_{5}2/$ 674-nm clock transition in a single trapped Sr^{+} ion; *T-IM Apr 97* 133-136
Basso, G., *see* Baracchino, L., *T-IM Dec 97* 1256 -1261
Begems, M., *see* Jeanneret, B., *T-IM Apr 97* 285-288
Bell, E.W., *see* Jefferts, S.R., *T-IM Apr 97* 209-211
Bennett, D.A., *see* So, E., *T-IM Apr 97* 454-458
Benz, S.P., *see* Hamilton, C.A., *T-IM Apr 97* 224-228
Bergamin, A., G. Cavagnero, L. Cordiali, and G. Mana. Beam-astigmatism in laser interferometry; *T-IM Apr 97* 196-200
Bergamin, A., G. Cavagnero, L. Cordiali, G. Mana, and G. Zosi. Scanning X-ray interferometry over a millimeter baseline; *T-IM Apr 97* 576-579
Bergeault, E., *see* Wiedmann, F., *T-IM Apr 97* 527-530
Bergeault, E., *see* Berghoff, G., *T-IM Oct 97* 1111-1114
Bergeault, E., *see* Deshours, F., *T-IM Dec 97* 1251-1255
Berghoff, G., E. Bergeault, B. Huyart, and L. Jallet. On-wafer calibration of a double six-port reflectometer including constants for absolute power measurements; *T-IM Oct 97* 1111-1114
Bernard, J.E., *see* Marmet, L., *T-IM Apr 97* 169-173
Bernieri, A., *see* Baccigalupi, A., *T-IM Jun 97* 731-736
Bertinetto, F., *see* Bisi, M., *T-IM Apr 97* 153-156
Bertocco, M., and C. Narduzzi. Sine-fit versus discrete Fourier transform-based algorithms in SNR testing of waveform digitizers; *T-IM Apr 97* 445-448
Bertocco, M., C. Narduzzi, and D. Petri. Optimized sinewave test of waveform digitizers by a DFT approach; *T-IM Aug 97* 970-974
Bertocco, M., C. Narduzzi, P. Paglierani, and D. Petri. Accuracy of effective bit estimation methods; *T-IM Aug 97* 1011-1015
Bettin, H., M. Glaser, F. Spieweck, H. Toth, A. Sacconi, A. Peuto, K. Fujii, M. Tanaka, and Y. Nezu. International intercomparison of silicon density standards; *T-IM Apr 97* 556-559
Bettin, H., *see* De Bievre, P., *T-IM Apr 97* 592-595
Bickley, C.J., *see* Flowers, J.L., *T-IM Apr 97* 104-107
Biebl, E.M., *see* Friedsam, G.L., *T-IM Apr 97* 515-518
Bingxin Jie, *see* Ken Xu, *T-IM Oct 97* 1081-1083
Bisceglie, M.D., *see* Conte, E., *T-IM Aug 97* 836-841
Bisi, M., and F. Bertinetto. Amplitude noise and linewidth reduction of an Ar^{+} laser; *T-IM Apr 97* 153-156
Blache, F., *see* Deshours, F., *T-IM Dec 97* 1251-1255
Blackham, D.V., and R.D. Pollard. An improved technique for permittivity measurements using a coaxial probe; *T-IM Oct 97* 1093-1099
Blair, D.G., *see* Taylor, C.T., *T-IM Apr 97* 183-185
Blanchard, H., *see* Schott, C., *T-IM Apr 97* 613-616
Bobbio, A., P. Tavella, A. Montefusco, and S. Costamagna. Monitoring the calibration status of a measuring instrument by a stochastic model; *T-IM Aug 97* 747-751
Boche, H., and M. Protzmann. A new algorithm for the reconstruction of bandlimited functions and their Hilbert transform; *T-IM Apr 97* 442-444
Bock, W.J., W. Urbanczyk, and M. Fontaine. Characterization of highly birefringent optical fibers using interferometric techniques; *T-IM Aug 97* 903-907
Boella, G., and G.M. Reedtz. Change of the working temperature of the IEN primary group of standard resistors; *T-IM Apr 97* 311-313
Bohacek, J., P. Svoboda, and P. Vasek. AC QHE-based calibration of resistance standards; *T-IM Apr 97* 273-275
Bok Lee Chan, *see* Morikawa, T., *T-IM Apr 97* 216-219
Boni, A., *see* Chiorboli, G., *T-IM Aug 97* 975-979
Bonsch, G., *see* Nicolaus, R.A., *T-IM Apr 97* 563-565
Bosch, T., *see* Servagent, N., *T-IM Aug 97* 847-850
Bosch, T., and M. Lescure. Crosstalk analysis of 1 m to 10 m laser phase-shift range finder; *T-IM Dec 97* 1224-1228
Bosco, G.C., *see* Pogliano, U., *T-IM Apr 97* 373-376
Bosse, V., *see* Weyand, K., *T-IM Apr 97* 617-620
Bregni, S. Clock stability characterization and measurement in telecommunications; *T-IM Dec 97* 1284-1294
Brida, G., *see* Levi, F., *T-IM Apr 97* 126-129
Brown, C., and K. Feher. Measuring metastability and its effect on communication signal processing systems; *T-IM Feb 97* 61-64
Brunetti, L., *see* Andreone, D., *T-IM Apr 97* 535-538
Bucci, G., F. Franciosi, and P. Valocchi. An objective test for speech codecs; *T-IM Aug 97* 831-835

Bucci, G., and C. Landi. Numerical method for transit time measurement in ultrasonic sensor applications; *T-IM Dec 97* 1241-1246
Buchholz, F.-I., *see* Kessel, W., *T-IM Apr 97* 477-481
Buchmayr, M., *see* Garn, H., *T-IM Apr 97* 544-548
Buckman, A.B., *see* Narayanan, C., *T-IM Oct 97* 1137-1144
Budovsky, I. A micropotentiometer-based system for low-voltage calibration of alternating voltage measurement standards; *T-IM Apr 97* 356-360
Budovsky, N., *see* Shapiro, E.Z., *T-IM Apr 97* 412-415
Buhlmann, H.-J., *see* Jeanneret, B., *T-IM Apr 97* 285-288
Burroughs, C.J., *see* Hamilton, C.A., *T-IM Apr 97* 224-228
Burroughs, C.J., *see* Hamilton, C.A., *T-IM Apr 97* 237-241
Busch-Vishniac, I., *see* Narayanan, C., *T-IM Oct 97* 1137-1144
Butler, C., *see* Zhang, K., *T-IM Aug 97* 899-902

C

Cabral, E., *see* Carlosena, A., *T-IM Aug 97* 862-867
Caddemi, A., A. Di Paola, and M. Sannino. Full characterization of microwave low-noise packaged HEMT's: measurements versus modeling; *T-IM Apr 97* 490-494
Carbone, P. Quantitative criteria for the design of dither-based quantizing systems; *T-IM Jun 97* 656-659
Carlosena, A., and E. Cabral. Novel transimpedance filter topology for instrumentation; *T-IM Aug 97* 862-867
Cartaleva, S.S., Y.V. Dancheva, and V.P. Gerginov. The influence of Ne isotopes on the single mode operation of He-Ne and He-Ne/I_2 lasers; *T-IM Apr 97* 149-152
Carullo, A., and M. Parvis. Power meter for highly distorted three-phase systems; *T-IM Dec 97* 1262-1267
Castelli, F. The potential transformer bridge with current comparator for measuring the voltage dependence of compressed-gas capacitors; *T-IM Aug 97* 822-825
Cavagnero, G., *see* Bergamin, A., *T-IM Apr 97* 196-200
Cavagnero, G., *see* Bergamin, A., *T-IM Apr 97* 576-579
Cennamo, F., *see* Arpaia, P., *T-IM Aug 97* 893-898
Chan Bok Lee, *see* Morikawa, T., *T-IM Apr 97* 216-219
Chang Chih-Wei, *see* Chih-Wei Chang, *T-IM Oct 97* 1084-1092
Chang Ho Choi, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100
Chartier, J.-M., *see* Zarka, A., *T-IM Apr 97* 145-148
Chatard-Moulin, M., *see* Tantot, O., *T-IM Apr 97* 519-522
Chavand, F., E. Colle, Y. Chekhar, and E.C. N'zi. 3-D measurements using a video camera and a range finder; *T-IM Dec 97* 1229-1235
Chavez, J.A., J.A. Ortega, M.A. Perez, and M.J. Garcia. Low-cost and minimal-conditioning interface for a PbSe photoconductor array; *T-IM Aug 97* 817-821
Chekhar, Y., *see* Chavand, F., *T-IM Dec 97* 1229-1235
Chen Chern-Lin, *see* Chern-Lin Chen, *T-IM Oct 97* 1145-1149
Cheng, Q.H., *see* Xue, S.Q., *T-IM Apr 97* 250-252
Cheng-Yung Chiang, and Huey-Ru Chuang. A simple and effective load-pull system for RF power transistor large-signal measurements for wireless communication power amplifier design; *T-IM Oct 97* 1150-1155
Chen Kun-Mu, *see* Chih-Wei Chang, *T-IM Oct 97* 1084-1092
Chen Shiping, *see* Yiqun Hu, *T-IM Oct 97* 1160-1164
Chen Wen-Shiung, *see* Ho-En Liao, *T-IM Aug 97* 868-872
Cheol Gi Kim, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100
Chern-Lin Chen, and Shun-Chung Wang. A PC-based adaptive software for automatic calibration of power transducers; *T-IM Oct 97* 1145-1149
Chiang Cheng-Yung, *see* Cheng-Yung Chiang, *T-IM Oct 97* 1150-1155
Chih-Hsien Kung, M.J. Devaney, and Chung-Ming Huang. The design of a hand-held K-factor meter using an air-core current transformer; *T-IM Aug 97* 811-816
Chih-Wei Chang, Kun-Mu Chen, and Jian Qian. Nondestructive determination of electromagnetic parameters of dielectric materials at X-band frequencies using a waveguide probe system; *T-IM Oct 97* 1084-1092
Childers, C.B., *see* Kinard, J.R., *T-IM Apr 97* 391-394
Chin-Long Wey Built-in self-test design of current-mode algorithmic analog-to-digital converters; *T-IM Jun 97* 667-671
Chiorboli, G., G. Franco, and C. Morandi. Uncertainties in quantization-noise estimates for analog-to-digital converters; *T-IM Feb 97* 56-60
Chiorboli, G., A. Boni, and G. Franco. Test of subranging A/D converters with digital correction; *T-IM Aug 97* 975-979
Chiriac, H., *see* Hristoforou, E., *T-IM Apr 97* 632-635
Chizhov, V.V., *see* Yushchenko, A.G., *T-IM Apr 97* 507-510
Choi Chang Ho, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100
Cho Yong Myung, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780
Chuang Huey-Ru, *see* Cheng-Yung Chiang, *T-IM Oct 97* 1150-1155
Chung, S., *see* Kang, T.W., *T-IM Dec 97* 1247-1250
Chung-Ming Huang, *see* Chih-Hsien Kung, *T-IM Aug 97* 811-816
Cibbes, A.M., *see* Shapiro, E.Z., *T-IM Apr 97* 412-415
Cilingiroglu, U., *see* Onat, B.M., *T-IM Jun 97* 672-677
Ciofi, C., M. De Marinis, and B. Neri. Ultralow-noise PC-Based measurement system for the characterization of the metallizations of integrated circuits; *T-IM Aug 97* 789-793
Ciofi, C., *see* Baracchino, L., *T-IM Dec 97* 1256 -1261
Clark, A.F., *see* Zimmerman, N.M., *T-IM Apr 97* 294-298
Clark, R.F., P.S. Filipski, and D.C. Paulusse. Improvements in the NRC AC-DC transfer capabilities; *T-IM Apr 97* 365-368
Claus, R.O., *see* Arya, V., *T-IM Oct 97* 1173-1177
Cobb, J.L., *see* Zimmerman, N.M., *T-IM Apr 97* 294-298
Colle, E., *see* Chavand, F., *T-IM Dec 97* 1229-1235
Collins, J.G., W.J. Giardini, A.J. Leistner, and M.J. Kenny. The influence of Young's modulus on roundness in silicon sphere fabrication [Avogadro constant]; *T-IM Apr 97* 572-575
Conte, E., M.D. Bisceglie, C. Galdi, and G. Ricci. A procedure for measuring the coherence length of the sea texture; *T-IM Aug 97* 836-841
Cook, R.J. Guest editorial [intro. to special issue on selected papers CPEM'96]; *T-IM Apr 97* 95-96
Cordiali, L., *see* Bergamin, A., *T-IM Apr 97* 196-200
Cordiali, L., *see* Bergamin, A., *T-IM Apr 97* 576-579
Correia, C.M.B.A., *see* Simoes, J.B., *T-IM Dec 97* 1274-1279
Cosart, L.D., L. Peregrino, and A. Tambe. Time domain analysis and its practical application to the measurement of phase noise and jitter; *T-IM Aug 97* 1016-1019
Costamagna, S., *see* Bobbio, A., *T-IM Aug 97* 747-751
Costandache, D., *see* Baltag, O., *T-IM Apr 97* 629-631
Cote, M., *see* Wood, H.M., *T-IM Apr 97* 269-272
Coughlin, J., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259
Cyr, N., *see* Poulin, M., *T-IM Apr 97* 157-161

D

Dagys, M., Z. Kancleris, V. Orsevski, and R. Simniskis. High-power microwave pulse measurement using resistive sensors; *T-IM Apr 97* 499-502
Dancheva, Y.V., *see* Cartaleva, S.S., *T-IM Apr 97* 149-152
de Bievre, P., *see* Gonfiantini, R., *T-IM Apr 97* 566-571
De Bievre, P., S. Valkiers, R. Gonfiantini, P.D.P. Taylor, H. Bettin, F. Spieweck, A. Peuto, S. Pettorruso, M. Mosca, K. Fujii, M. Tanaka, Y. Nezu, A.J. Leistner, and W.J. Giardini. The molar volume of silicon [Avogadro constant]; *T-IM Apr 97* 592-595
De Clercq, E., *see* Makdissi, A., *T-IM Apr 97* 112-116
Deep, G.S., *see* Turnell, D.J., *T-IM Aug 97* 986-990
de Graaf, G., and R.F. Wolffenbuttel. Light-to-frequency converter using integrating mode photodiodes; *T-IM Aug 97* 933-936
de Jong, G., *see* Xiujun Li, *T-IM Feb 97* 8-14
de Jong, G.W., *see* Li, X., *T-IM Aug 97* 888-892
de Jong, P.C., and G.C.M. Meijer. Absolute voltage amplification using dynamic feedback control; *T-IM Aug 97* 758-763
De Marinis, M., *see* Ciofi, C., *T-IM Aug 97* 789-793
den Dekker, A.J. Model-based optical resolution; *T-IM Aug 97* 798-802
Deshours, F., E. Bergeault, F. Blache, J.-P. Villotte, and B. Villeforceix. Experimental comparison of load-pull measurement systems for nonlinear power transistor characterization; *T-IM Dec 97* 1251-1255
Deslattes, R.D., *see* Kessler, E.G., Jr., *T-IM Apr 97* 551-555
Devaney, M.J., *see* Chih-Hsien Kung, *T-IM Aug 97* 811-816
De Vreede, J.P.M., *see* Van Mullem, C., *T-IM Apr 97* 361-364
De Xiang Huang, G. Rebuldela, and J.D. Harper. RF-DC differences of micropotentiometers; *T-IM Apr 97* 337-341
De-Xiang Huang, *see* Kinard, J.R., *T-IM Apr 97* 347-351
De-Xiang Huang, *see* Kinard, J.R., *T-IM Apr 97* 391-394
Deyst, J.P., *see* Souders, T.M., *T-IM Aug 97* 947-953
Dilla, S., *see* Jefferts, S.R., *T-IM Apr 97* 209-211
Dimitriev, A., *see* Udem, T., *T-IM Apr 97* 166-168
Di Paola, A., *see* Caddemi, A., *T-IM Apr 97* 490-494
Dobrowiecki, T.P., F. Louage, T.C. Meszaros, G. Roman, and B. Pataki. Will measuring instruments turn into agents?; *T-IM Aug 97* 991-995
Dolata, R., *see* Kessel, W., *T-IM Apr 97* 477-481
Duk Lee Rae, *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336
Dunschede, F.-W., *see* Muller, F., *T-IM Apr 97* 229-232
Dupuis, P., *see* Gueuning, F., *T-IM Dec 97* 1236-1240
Dziuba, R.F., *see* Jeffery, A.-M., *T-IM Apr 97* 264-268
Dziuba, R.F., *see* Elmquist, R.E., *T-IM Apr 97* 322-324

E

Early, M.D., and K. Jones. Optimum sensitivity of an externally shielded cryogenic current comparator; *T-IM Apr 97* 459-462
Eklund, G., *see* Reymann, D., *T-IM Apr 97* 220-223
Elandaloussi, H., *see* Juncar, P.P., *T-IM Jun 97* 690-695

Elmquist, R.E., *see* Jeffery, A.-M., *T-IM Apr 97* 264-268
Elmquist, R.E., and R.F. Dziuba. Loading effects in resistance scaling; *T-IM Apr 97* 322-324
Endo, T., *see* Yoshida, H., *T-IM Feb 97* 72-78
Endo, T., *see* Murayama, Y., *T-IM Apr 97* 233-236
Eng Kiong Wong, *see* Taylor, C.T., *T-IM Apr 97* 183-185
Epele, L., *see* Lorrondo, H.A., *T-IM Oct 97* 1183-1188
Eren, H., C.C. Fung, K.W. Wong, and A. Gupta. Artificial neural networks in estimation of hydrocyclone parameter d50$_c$ with unusual input variables; *T-IM Aug 97* 908-912
Eren, H., and C.C. Fung. Position estimation of mobile robots based on coded infrared signal transmission; *T-IM Dec 97* 1280-1283
Eren, H., *see* Fung, C.C., *T-IM Dec 97* 1295-1299
Escotte, L., *see* Roux, J.-P., *T-IM Oct 97* 1100-1104
Eugene, C., *see* Gueuning, F., *T-IM Dec 97* 1236-1240

F

Fasoli, L.G., F.R. Riedijk, and J.H. Huijsing. A general circuit for resistive bridge sensors with bitstream output; *T-IM Aug 97* 954-960
Feher, K., *see* Brown, C., *T-IM Feb 97* 61-64
Filipski, P.S., *see* Clark, R.F., *T-IM Apr 97* 365-368
Filipski, P.S., *see* Arseneau, R., *T-IM Apr 97* 399-402
Fiorillo, A.S. A piezoresistive tactile sensor; *T-IM Feb 97* 15-17
Fisher, M.A., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259
FitzPatrick, G.J., *see* Petersons, O., *T-IM Apr 97* 430-434
Flowers, J.L., C.J. Bickley, P.W. Josephs-Franks, and B.W. Petley. Optically pumped ^{3}He NMR and atomic hydrogen ESR at 0.6 T; *T-IM Apr 97* 104-107
Fontaine, M., *see* Bock, W.J., *T-IM Aug 97* 903-907
Franciosi, F., *see* Bucci, G., *T-IM Aug 97* 831-835
Franco, G., *see* Chiorboli, G., *T-IM Feb 97* 56-60
Franco, G., *see* Chiorboli, G., *T-IM Aug 97* 975-979
Freire, R.C.S., *see* Turnell, D.J., *T-IM Aug 97* 986-990
Friedsam, G.L., and E.M. Biebl. A broadband free-space dielectric properties measurement system at millimeter wavelengths; *T-IM Apr 97* 515-518
Fujii, K., E.R. Williams, R.L. Steiner, and D.B. Newell. A new refractometer by combining a variable length vacuum cell and a double-pass Michelson interferometer; *T-IM Apr 97* 191-195
Fujii, K., *see* Bettin, H., *T-IM Apr 97* 556-559
Fujii, K., *see* De Bievre, P., *T-IM Apr 97* 592-595
Fujii, K., *see* Steiner, R.L., *T-IM Apr 97* 601-604
Fujii, K., *see* Gillespie, *T-IM Apr 97* 605-608
Fujii, Y., F. Shiota, Y. Miki, Y. Nezu, G. Makishita, and K. Hara. A buoyancy-free mass comparator with precision better than 10^{-6} for use in a superconducting magnetic levitation system; *T-IM Apr 97* 609-612
Fujimoto, H., *see* Nakayama, K., *T-IM Apr 97* 580-583
Fukushima, A., A. Sato, A. Iwasa, Y. Nakamura, T. Komatsuzaki, and Y. Sakamoto. Attenuation of microwave filters for single-electron tunneling experiments; *T-IM Apr 97* 289-293
Funck, T., *see* Hebrank, F.X., *T-IM Apr 97* 242-245
Fung, C.C., *see* Eren, H., *T-IM Aug 97* 908-912
Fung, C.C., *see* Eren, H., *T-IM Dec 97* 1280-1283
Fung, C.C., K.W. Wong, and H. Eren. Modular artificial neural network for prediction of petrophysical properties from well log data; *T-IM Dec 97* 1295-1299

G

Gajda, J., and M. Szyper. Parametric optimization of measuring systems according to the joint error criterion; *T-IM Aug 97* 769-775
Galdi, C., *see* Conte, E., *T-IM Aug 97* 836-841
Gallop, J.C., C.D. Langham, Ling Hao, and F. Abbas. Dielectric loaded HTS resonators as frequency standards and low-phase noise oscillators; *T-IM Apr 97* 122-125
Gallop, J.C., *see* Langham, C.D., *T-IM Apr 97* 130-132
Galwas, B.A., J.K. Piotrowski, and J. Skulski. Dielectric measurements using a coaxial resonator opened to a waveguide below cut-off; *T-IM Apr 97* 511-514
Garcia, M.J., *see* Chavez, J.A., *T-IM Aug 97* 817-821
Garcia, R., *see* Laiz, H., *T-IM Apr 97* 420-422
Garn, H., M. Buchmayr, W. Mullner, and J. Rasinger. Primary standards for antenna factor calibration in the frequency range of (30 to 1000) MHz; *T-IM Apr 97* 544-548
Gaviot, E., *see* Machut, C., *T-IM Oct 97* 1128-1132
Geiger, H., *see* Udem, T., *T-IM Apr 97* 166-168
Gerginov, V.P., *see* Cartaleva, S.S., *T-IM Apr 97* 149-152
Giaquinto, N., and A. Trotta. Fast and accurate ADC testing via an enhanced sine wave fitting algorithm; *T-IM Aug 97* 1020-1025
Giardini, W.J., *see* Collins, J.G., *T-IM Apr 97* 572-575
Giardini, W.J., *see* De Bievre, P., *T-IM Apr 97* 592-595
Gi Kim Cheol, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100
Gill, P., *see* Barwood, G.P., *T-IM Apr 97* 133-136
Gillespie, K. Fujii, D.B. Newell, P.T. Olsen, O.A. Picard, R.L. Steiner, G.N. Stenbakken, and E.R.]Williams. Alignment uncertainties of the NIST watt experiment; *T-IM Apr 97* 605-608
Gillespie, A.D., *see* Steiner, R.L., *T-IM Apr 97* 601-604
Ginley, R.A. Line-reflect-match calibration technique for the dual six-port automatic network analyzer; *T-IM Apr 97* 523-526
Giordanino, C., *see* Andreone, D., *T-IM Apr 97* 535-538
Glaser, M., *see* Bettin, H., *T-IM Apr 97* 556-559
Glaser, M., *see* Ratschko, D., *T-IM Apr 97* 588-591
Glimm, J., *see* Munter, K., *T-IM Apr 97* 549-550
Godone, A., *see* Levi, F., *T-IM Apr 97* 126-129
Godone, A., and D. Andreone. Microwave phase-noise influence on Josephson-junction array voltage standards; *T-IM Apr 97* 246-249
Godts, P., *see* Machut, C., *T-IM Oct 97* 1128-1132
Gonfiantini, R., P. de Bievre, S. Valkiers, and P.D.P. Taylor. Measuring the molar mass of silicon for a better Avogadro constant: reduced uncertainty; *T-IM Apr 97* 566-571
Gonfiantini, R., *see* De Bievre, P., *T-IM Apr 97* 592-595
Graffeuil, J., *see* Roux, J.-P., *T-IM Oct 97* 1100-1104
Gray, J.O., *see* Ming Yang, *T-IM Jun 97* 711-716
Greenhall, C.A. The third-difference approach to modified Allan variance; *T-IM Jun 97* 696-703
Grimm, L., *see* Muller, F., *T-IM Apr 97* 229-232
Groen, F.C.A., *see* Vos, F.M., *T-IM Aug 97* 794-797
Gubisch, A., P.L. Lualdi, Jr., P.N. Miljanic, and J.L. West. Power calibrator using sampled feedback for current and voltage; *T-IM Apr 97* 403-407
Gudoshnikov, S.A., N. Ukhansky, I.I. Vengrus, L.V. Matveets, K.E. Andreev, O. Snigirev, and S.I. Krasnosvobodtsev. Direct-coupled electronics for high-temperature superconductor DC SQUID-based magnetometer; *T-IM Apr 97* 624-628
Gueuning, F., M. Varlan, C. Eugene, and P. Dupuis. Accurate distance measurement by an autonomous ultrasonic system combining time-of-flight and phase-shift methods; *T-IM Dec 97* 1236-1240
Guillon, P., *see* Tantot, O., *T-IM Apr 97* 519-522
Guo Wei Estimations of frequency and its drift rate; *T-IM Feb 97* 79-82
Gupta, A., *see* Eren, H., *T-IM Aug 97* 908-912
Gupta, A.S., and B.S. Mathur. Standard time and frequency signal broadcast via INSAT-accuracy improvements using differential mode; *T-IM Apr 97* 212-215
Gutmann, P., *see* Muller, F., *T-IM Apr 97* 229-232
Gutmann, P., *see* Hebrank, F.X., *T-IM Apr 97* 242-245
Gyu Park Po, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100

H

Haga, A., *see* Kawamata, K., *T-IM Aug 97* 918-921
Hall, J.L., *see* Jun Ye, *T-IM Apr 97* 178-182
Hamilton, C.A., C.J. Burroughs, S.P. Benz, and J.R. Kinard. AC Josephson voltage standard: progress report; *T-IM Apr 97* 224-228
Hamilton, C.A., C.J. Burroughs, S.L. Kupferman, G.A. Naujoks, and A. Vickery. A compact transportable Josephson voltage standard; *T-IM Apr 97* 237-241
Han Kwon Soo, *see* Kyu-Tae Kim, *T-IM Apr 97* 314-317
Hansch, T.W., *see* Udem, T., *T-IM Apr 97* 166-168
Hao Ling, *see* Gallop, J.C., *T-IM Apr 97* 122-125
Hara, K., *see* Fujii, Y., *T-IM Apr 97* 609-612
Harper, J.D., *see* De Xiang Huang, *T-IM Apr 97* 337-341
Haslett, J.W., *see* Trofimenkoff, F.N., *T-IM Oct 97* 1208-1211
Hatzopoulos, A.A., *see* Siskos, S., *T-IM Dec 97* 1301-1304
Hau Jun Kim, *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336
Hayasaka, K., *see* Tanaka, U., *T-IM Apr 97* 137-140
Hayashi, N., *see* Yamazaki, S., *T-IM Aug 97* 873-876
Hebrank, F.X., E. Vollmer, T. Funck, J. Kohlmann, P. Gutmann, and J. Niemeyer. Hybrid integration of a Josephson series array and a 10 GHz planar oscillator; *T-IM Apr 97* 242-245
Hejn, K., and A. Pacut. Statistical analysis of autoscaling feedback in mixed-signal circuits; *T-IM Aug 97* 913-917
Hermanne, A., *see* Sonck, M., *T-IM Aug 97* 857-861
Hesselbarth, J., F. Wiedmann, and B. Huyart. Two new six-port reflectometers covering very large bandwidths; *T-IM Aug 97* 966-969
Heuermann, H., and B. Schiek. 15-term self-calibration methods for the error-correction of on-wafer measurements; *T-IM Oct 97* 1105-1110
Heuermann, H., and B. Schiek. Results of network analyzer measurements with leakage errors-corrected with direct calibration techniques; *T-IM Oct 97* 1120-1127
Hidalgo, R.M., *see* Lorrondo, H.A., *T-IM Oct 97* 1183-1188
Hill, S.L., *see* Ming Yang, *T-IM Jun 97* 711-716
Himbert, M.E., *see* Juncar, P.P., *T-IM Jun 97* 690-695

Ho Choi Chang, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100

Ho-En Liao, and Wen-Shiung Chen. Determination of nonlinear delay elements within NARMA models using dispersion functions; *T-IM Aug 97* 868-872

Holicek, L.M., *see* Zupunski, I.Z., *T-IM Apr 97* 408-411

Honigbaum, R., *see* Kang, T.W., *T-IM Dec 97* 1247-1250

Hrejsa, J., *see* Schott, C., *T-IM Apr 97* 613-616

Hristoforou, E., H. Chiriac, and M. Neagu. A new magnetic field sensor based on magnetostrictive delay lines; *T-IM Apr 97* 632-635

Hu, J., T. Ahola, E. Ikonen, and K. Riski. Frequency shifts of iodine stabilized He-Ne lasers at higher harmonic order stabilization; *T-IM Apr 97* 186-190

Huang, J., N. Ohnishi, and N. Sugie. Sound localization in reverberant environment based on the model of the precedence effect; *T-IM Aug 97* 842-846

Huang Chung-Ming, *see* Chih-Hsien Kung, *T-IM Aug 97* 811-816

Huang De Xiang, *see* De Xiang Huang, *T-IM Apr 97* 337-341

Huang De-Xiang, *see* Kinard, J.R., *T-IM Apr 97* 347-351

Huang De-Xiang, *see* Kinard, J.R., *T-IM Apr 97* 391-394

Huber, A., *see* Udem, T., *T-IM Apr 97* 166-168

Huey-Ru Chuang, *see* Cheng-Yung Chiang, *T-IM Oct 97* 1150-1155

Huijsing, J.H., *see* Lyahou, K.F., *T-IM Aug 97* 752-757

Huijsing, J.H., *see* Fasoli, L.G., *T-IM Aug 97* 954-960

Hunt, R.T., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259

Hu Xiao, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

Huyart, B., *see* Wiedmann, F., *T-IM Apr 97* 527-530

Huyart, B., *see* Hesselbarth, J., *T-IM Aug 97* 966-969

Huyart, B., *see* Berghoff, G., *T-IM Oct 97* 1111-1114

Hu Yiqun, *see* Yiqun Hu, *T-IM Oct 97* 1160-1164

I

II Park Se, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780

Ikonen, E., *see* Hu, J., *T-IM Apr 97* 186-190

Imajo, H., *see* Tanaka, U., *T-IM Apr 97* 137-140

Inglis, A.D., *see* Wood, H.M., *T-IM Apr 97* 269-272

Inglis, A.D., and I. Minowa. Fabrication of precision quantized Hall devices; *T-IM Apr 97* 281-284

Inglis, B.D., *see* Sasaki, H., *T-IM Apr 97* 377-381

Iwasa, A., *see* Murayama, Y., *T-IM Apr 97* 233-236

Iwasa, A., *see* Fukushima, A., *T-IM Apr 97* 289-293

J

Jaatinen, E., *see* Zarka, A., *T-IM Apr 97* 145-148

Jallet, L., *see* Wiedmann, F., *T-IM Apr 97* 527-530

Jallet, L., *see* Berghoff, G., *T-IM Oct 97* 1111-1114

Janssen, W.J.G.D., *see* Van Mullem, C., *T-IM Apr 97* 361-364

Jarrett, D.G. Automated guarded bridge for calibration of multimegohm standard resistors from 10 MΩ to 1 TΩ; *T-IM Apr 97* 325-328

Jeanneret, B., *see* Jeckelmann, B., *T-IM Apr 97* 276-280

Jeanneret, B., B. Jeckelmann, H.-J. Buhlmann, and M. Begems. Influence of infrared illumination on the accuracy of the quantized Hall resistance; *T-IM Apr 97* 285-288

Jeckelmann, B., and B. Jeanneret. Influence of the voltage contacts on the four-terminal quantized Hall resistance in the nonlinear regime; *T-IM Apr 97* 276-280

Jeckelmann, B., *see* Jeanneret, B., *T-IM Apr 97* 285-288

Jefferts, S.R., *see* Ascarrunz, F.G., *T-IM Apr 97* 205-208

Jefferts, S.R., M.A. Weiss, J. Levine, S. Dilla, E.W. Bell, and T.E. Parker. Two-way time and frequency transfer using optical fibers; *T-IM Apr 97* 209-211

Jeffery, A.-M., R.E. Elmquist, L.H. Lee, J.Q. Shields, and R.F. Dziuba. NIST comparison of the quantized Hall resistance and the realization of the SI OHM through the calculable capacitor; *T-IM Apr 97* 264-268

Jenq Yih-Chyun, *see* Yih-Chyun Jenq, *T-IM Jun 97* 649-652

Jenq Yih-Chyun, *see* Yih-Chyun Jenq, *T-IM Jun 97* 653-655

Jian Qian, *see* Chih-Wei Chang, *T-IM Oct 97* 1084-1092

Jian Qiu Zhang, *see* Yi Shen, *T-IM Aug 97* 937-940

Jian Qiu Zhang, Zhao Xinmin, Hu Xiao, and Sun Jinwei. Sinewave fit algorithm based on total least-squares method with application to ADC effective bits measurement; *T-IM Aug 97* 1026-1030

Jichang Qin, *see* Trofimenkoff, F.N., *T-IM Oct 97* 1208-1211

Jie Bingxin, *see* Ken Xu, *T-IM Oct 97* 1081-1083

Jinwei Sun, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

Jones, K., *see* Early, M.D., *T-IM Apr 97* 459-462

Jones, K., *see* White, D.R., *T-IM Oct 97* 1068-1074

Jones, M., *see* Arya, V., *T-IM Oct 97* 1173-1177

Josephs-Franks, P.W., *see* Flowers, J.L., *T-IM Apr 97* 104-107

Jovanovic, L.D. A method of compensation of the frequency dependent systematic error of the time-division watt-converter; *T-IM Apr 97* 416-419

Juncar, P.P., H. Elandaloussi, M.E. Himbert, J. Pinard, and A. Razet. A new optical wavelength ratio measurement apparatus: the fringe counting sigmameter; *T-IM Jun 97* 690-695

Jun Kim Hau, *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336

Jun Ye, Long-Sheng Ma, and J.L. Hall. Ultrastable optical frequency reference at 1.064 μm using a C_2HD molecular overtone transition; *T-IM Apr 97* 178-182

K

Kahrizi, M., *see* Ahmad, H., *T-IM Feb 97* 18-26

Kalisz, J., R. Szplet, J. Pasierbinski, and A. Poniecki. Field-programmable-gate-array-based time-to-digital converter with 200-ps resolution; *T-IM Feb 97* 51-55

Kalisz, J., *see* Pelka, R., *T-IM Apr 97* 449-453

Kalisz, J., R. Szplet, R. Pelka, and A. Poniecki. Single-chip interpolating time counter with 200-ps resolution and 43-s range; *T-IM Aug 97* 851-856

Kamel, M.S., *see* Bacakoglu, H., *T-IM Oct 97* 1165-1172

Kampik, M., M. Klonz, and T. Skubis. Thermal converter with quartz crystal temperature sensor for ac-dc transfer; *T-IM Apr 97* 387-390

Kancleris, Z., *see* Dagys, M., *T-IM Apr 97* 499-502

Kang, T.W., S. Chung, R. Honigbaum, J. Ruhaak, and U. Stumper. K- and Ka-band waveguide microcalorimeters for microwave power standards; *T-IM Dec 97* 1247-1250

Katzmann, F.L., M. Klonz, T. Spiegel, and E. Kessler. Thin-film ac-dc converter with thermoresistive sensing; *T-IM Apr 97* 382-386

Kawamata, K., S. Minegishi, A. Haga, and R. Sato. Measurement of very-fast-voltage rise curve due to gap discharge using coupled transmission lines in distributed constant system; *T-IM Aug 97* 918-921

Keller, M.W., J.M. Martinis, A.H. Steinbach, and N.M. Zimmerman. A seven-junction electron pump: design, fabrication, and operation; *T-IM Apr 97* 307-310

Kenny, M.J., *see* Collins, J.G., *T-IM Apr 97* 572-575

Ken Xu, and Bingxin Jie. A false-balance-avoidance transductor for measuring large DC currents; *T-IM Oct 97* 1081-1083

Kessel, W., F.-I. Buchholz, M.I. Khabipov, R. Dolata, and J. Niemeyer. Development of a rapid-single-flux-quantum shift register for applications in RF noise power metrology; *T-IM Apr 97* 477-481

Kessler, E., *see* Katzmann, F.L., *T-IM Apr 97* 382-386

Kessler, E.G., Jr., J.E. Schweppe, and R.D. Deslattes. Intercomparison of silicon samples from the Avogadro projects; *T-IM Apr 97* 551-555

Keyser, U., *see* Rottger, S., *T-IM Apr 97* 560-562

Khabipov, M.I., *see* Kessel, W., *T-IM Apr 97* 477-481

Khorev, V.N., *see* Shifrin, V.Y., *T-IM Apr 97* 97-100

Kibble, B.P., *see* Robinson, I.A., *T-IM Apr 97* 596-600

Kim Cheol Gi, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100

Kim Hau Jun, *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336

Kim Kyu-Tae, *see* Kyu-Tae Kim, *T-IM Apr 97* 314-317

Kim Kyu-Tae, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780

Kinard, J.R., *see* Hamilton, C.A., *T-IM Apr 97* 224-228

Kinard, J.R., D.B. Novomy, T.E. Lipe, and De-Xiang Huang. Development of thin-film multijunction thermal converters at NIST; *T-IM Apr 97* 347-351

Kinard, J.R., T.E. Lipe, C.B. Childers, D.B. Novotny, and De-Xiang Huang. High-current thin-film multijunction thermal converters and multiconverter modules; *T-IM Apr 97* 391-394

Kinoshita, T. Fine-structure constant obtained from an improved calculation of the electron g-2; *T-IM Apr 97* 108-111

Kiong Wong Eng, *see* Taylor, C.T., *T-IM Apr 97* 183-185

Klebanov, I., *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336

Klein, H.A., *see* Barwood, G.P., *T-IM Apr 97* 133-136

Klonz, M. CCE comparison of AC-DC voltage transfer standards at the lowest attainable level of uncertainty; *T-IM Apr 97* 342-346

Klonz, M., *see* Sasaki, H., *T-IM Apr 97* 377-381

Klonz, M., *see* Katzmann, F.L., *T-IM Apr 97* 382-386

Klonz, M., *see* Kampik, M., *T-IM Apr 97* 387-390

Knolle, D., *see* Ratschko, D., *T-IM Apr 97* 588-591

Kohlmann, J., *see* Muller, F., *T-IM Apr 97* 229-232

Kohlmann, J., *see* Hebrank, F.X., *T-IM Apr 97* 242-245

Koide, F.T. Common-mode rejection ratio redefined; *T-IM Jun 97* 737-739

Kollar, I., *see* Plett, G.L., *T-IM Dec 97* 1217-1223

Komatsuzaki, T., *see* Fukushima, A., *T-IM Apr 97* 289-293

Konig, W., *see* Udem, T., *T-IM Apr 97* 166-168

Kostamovaara, J., *see* Palojarvi, P., *T-IM Aug 97* 996-999

Kostamovaara, J.T., *see* Makynen, A., *T-IM Oct 97* 1133-1136

Kozakai, T., *see* Murayama, Y., *T-IM Apr 97* 233-236

Kozakai, T., *see* Yoshida, H., *T-IM Apr 97* 260-263

Koziol, J., *see* Zhixin Li, *T-IM Jun 97* 722-730

Kramer, G., *see* Tyurikov, D., *T-IM Apr 97* 174-177
Krasnosvobodtsev, S.I., *see* Gudoshnikov, S.A., *T-IM Apr 97* 624-628
Krekels, H.-G., and B. Schiek. A closed form theory for calibrating a dual six-port network analyzer; *T-IM Oct 97* 1115-1119
Kruger, E., W. Nistler, and W. Weirauch. Constant by measuring the quotient of the Planck constant and the neutron mass; *T-IM Apr 97* 101-103
Krupenin, V.A., *see* Wolf, H., *T-IM Apr 97* 303-306
Kung Chih-Hsien, *see* Chih-Hsien Kung, *T-IM Aug 97* 811-816
Kun-Mu Chen, *see* Chih-Wei Chang, *T-IM Oct 97* 1084-1092
Kupferman, S.L., *see* Hamilton, C.A., *T-IM Apr 97* 237-241
Kwon Soo Han, *see* Kyu-Tae Kim, *T-IM Apr 97* 314-317
Kwon Sung-Won, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780
Kyu-Tae Kim, Kwon Soo Han, Y. Sukamoto, and T. Sakuraba. Comparison of Zener voltage standard calibrations at 10 V between the KRISS and the ETL; *T-IM Apr 97* 314-317
Kyu-Tae Kim, Se Il Park, Yong Myung Cho, and Sung-Won Kwon. Common error sources in using a series-resistors-type voltage divider below the level of 0.01 ppm; *T-IM Aug 97* 776-780

L

Laakso, T.I., *see* Ovaska, S.J., *T-IM Oct 97* 1196-1201
Labonte, S., *see* Roy, L., *T-IM Aug 97* 1000-1004
Lacquet, B.M., P.L. Swart, and S.J. Spammer. Polymer dispersed liquid crystal fiber optic electric field probe; *T-IM Feb 97* 31-35
Laiz, H., and R. Garcia. A power comparator with high accuracy: simple and inexpensive; *T-IM Apr 97* 420-422
Landeck, J., *see* Simoes, J.B., *T-IM Dec 97* 1274-1279
Landi, C., *see* Bucci, G., *T-IM Dec 97* 1241-1246
Landsberger, L.M., *see* Ahmad, H., *T-IM Feb 97* 18-26
Langham, C.D., *see* Gallop, J.C., *T-IM Apr 97* 122-125
Langham, C.D., and J.C. Gallop. Cryogenic sapphire dielectric resonators: performance and potential; *T-IM Apr 97* 130-132
Lapuh, R., and Z. Svetik. Evaluation of a voltage source with three calculable RMS outputs; *T-IM Aug 97* 784-788
Latrasse, C., *see* Poulin, M., *T-IM Apr 97* 157-161
Laug, O.B., *see* Souders, T.M., *T-IM Aug 97* 947-953
Lawrence, K.C., *see* Nelson, S.O., *T-IM Aug 97* 941-946
Layer, E. Theoretical principles for establishing a hierarchy of dynamic accuracy with the integral-square-error as an example; *T-IM Oct 97* 1178-1182
Leclercq, D., *see* Machut, C., *T-IM Oct 97* 1128-1132
Lee, L.H., *see* Jeffery, A.-M., *T-IM Apr 97* 264-268
Lee Chan Bok, *see* Morikawa, T., *T-IM Apr 97* 216-219
Lee Rae Duk, *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336
Leibfried, D., *see* Udem, T., *T-IM Apr 97* 166-168
Leistner, A.J., *see* Collins, J.G., *T-IM Apr 97* 572-575
Leistner, A.J., *see* De Bievre, P., *T-IM Apr 97* 592-595
Lescure, M., *see* Servagent, N., *T-IM Aug 97* 847-850
Lescure, M., *see* Bosch, T., *T-IM Dec 97* 1224-1228
Levi, F., C. Novero, A. Godone, and G. Brida. Analysis of the light shift effect in the ^{87}Rb frequency standard; *T-IM Apr 97* 126-129
Levine, J., *see* Jefferts, S.R., *T-IM Apr 97* 209-211
Li, H.H., *see* Xue, S.Q., *T-IM Apr 97* 250-252
Li, M., *see* Roy, L., *T-IM Aug 97* 1000-1004
Li, X., G.C.M. Meijer, and G.W. de Jong. A microcontroller-based self-calibration technique for a smart capacitive angular-position sensor; *T-IM Aug 97* 888-892
Liao Ho-En, *see* Ho-En Liao, *T-IM Aug 97* 868-872
Ling Hao, *see* Gallop, J.C., *T-IM Apr 97* 122-125
Lipe, T.E., *see* Kinard, J.R., *T-IM Apr 97* 347-351
Lipe, T.E., *see* Kinard, J.R., *T-IM Apr 97* 391-394
Lipphardt, B., *see* Tyurikov, D., *T-IM Apr 97* 174-177
Li Xianjun, *see* Xianjun Li, *T-IM Apr 97* 636-639
Li Xiujun, *see* Xiujun Li, *T-IM Feb 97* 8-14
Li Zhixin, *see* Zhixin Li, *T-IM Jun 97* 722-730
Lobos, T., and J. Rezmer. Real-time determination of power system frequency; *T-IM Aug 97* 877-881
Long-Sheng Ma, *see* Jun Ye, *T-IM Apr 97* 178-182
Lorrondo, H.A., R.R. Rivera, R.M. Hidalgo, and L. Epele. Direct memory access methods applied to chaotic behavior experiments; *T-IM Oct 97* 1183-1188
Lotkhov, S.V., *see* Wolf, H., *T-IM Apr 97* 303-306
Louage, F., *see* Dobrowiecki, T.P., *T-IM Aug 97* 991-995
Lu, Y., *see* Zhang, K., *T-IM Aug 97* 899-902
Lualdi, P.L., Jr., *see* Gubisch, A., *T-IM Apr 97* 403-407
Lyahou, K.F., G. van der Horn, and J.H. Huijsing. A noniterative polynomial 2-D calibration method implemented in a microcontroller; *T-IM Aug 97* 752-757

M

Maatta, K., *see* Palojarvi, P., *T-IM Aug 97* 996-999
Machut, C., E. Gaviot, P. Godts, S. Sakly, and D. Leclercq. A new Peltier sensor for measuring the thermal conductivity of fluids; *T-IM Oct 97* 1128-1132
Madej, A.A., *see* Marmet, L., *T-IM Apr 97* 169-173
Makdissi, A., and E. De Clercq. A signal approach analysis of the Ramsey pattern in cesium beam frequency standards; *T-IM Apr 97* 112-116
Makishita, G., *see* Fujii, Y., *T-IM Apr 97* 609-612
Makynen, A., J.T. Kostamovaara, and R.A. Myllyla. Displacement sensing resolution of position-sensitive detectors in atmospheric turbulence using retroreflected beam; *T-IM Oct 97* 1133-1136
Ma Long-Sheng, *see* Jun Ye, *T-IM Apr 97* 178-182
Mana, G., *see* Bergamin, A., *T-IM Apr 97* 196-200
Mana, G., *see* Bergamin, A., *T-IM Apr 97* 576-579
Mann, A.G., *see* Taylor, C.T., *T-IM Apr 97* 183-185
Marioli, D., E. Sardini, and A. Taroni. A system for the generation of static and very low-frequency reference accelerations; *T-IM Feb 97* 27-30
Markovic, O., *see* Osmokrovic, P., *T-IM Feb 97* 36-44
Marmet, L., A.A. Madej, K.J. Siemsen, J.E. Bernard, and B.G. Whitford. Precision frequency measurement of the $^{2}S_{1}$2/-$^{2}D_{5}$2/ transition of Sr^{+} with a 674-nm diode laser locked to an ultrastable cavity; *T-IM Apr 97* 169-173
Martinis, J.M., *see* Keller, M.W., *T-IM Apr 97* 307-310
Maslen, E.H., *see* Noh, M.D., *T-IM Feb 97* 45-50
Massicotte, D., R.Z. Morawski, and A. Barwicz. Kalman-filter-based algorithms of spectrometric data correction-Part I: an iterative algorithm of deconvolution; *T-IM Jun 97* 678-684
Mathur, B.S., *see* Gupta, A.S., *T-IM Apr 97* 212-215
Matsumoto, M., *see* Mino, H., *T-IM Oct 97* 1189-1195
Matveets, L.V., *see* Gudoshnikov, S.A., *T-IM Apr 97* 624-628
Mauritzen, D.W., and M.S. Alam. Comments on “Accurate measurement of power, energy, and true RMS voltage using synchronous counting”; *T-IM Dec 97* 1300-1301
McNeill, J.A., *see* Onat, B.M., *T-IM Jun 97* 672-677
Meier, W., *see* Muller, F., *T-IM Apr 97* 229-232
Meijer, G.C.M., *see* Xiujun Li, *T-IM Feb 97* 8-14
Meijer, G.C.M., *see* Toth, F.N., *T-IM Apr 97* 644-646
Meijer, G.C.M., *see* van der Goes, F.M.L., *T-IM Jun 97* 704-710
Meijer, G.C.M., *see* de Jong, P.C., *T-IM Aug 97* 758-763
Meijer, G.C.M., *see* Li, X., *T-IM Aug 97* 888-892
Meijier, C.M., *see* Xianjun Li, *T-IM Apr 97* 636-639
Meszaros, T.C., *see* Dobrowiecki, T.P., *T-IM Aug 97* 991-995
Miekina, A., R.Z. Morawski, and A. Barwicz. The use of deconvolution and iterative optimization for spectrogram interpretation; *T-IM Aug 97* 1049-1053
Miki, Y., *see* Fujii, Y., *T-IM Apr 97* 609-612
Miljanic, P.N., *see* Gubisch, A., *T-IM Apr 97* 403-407
Miljanic, P.N. Mutual inductance highly independent of primary winding position and ambient fields; *T-IM Apr 97* 471-473
Milovancev, S.S., *see* Vujicic, V.V., *T-IM Apr 97* 439-441
Minegishi, S., *see* Kawamata, K., *T-IM Aug 97* 918-921
Ming Yang, S.L. Hill, and J.O. Gray. Localization of plane reflectors using a wide-beamwidth ultrasound transducer arrangement; *T-IM Jun 97* 711-716
Mino, H., M. Matsumoto, and K. Yana. A method for estimating intensity and impulse response functions of filtered Poisson processes; *T-IM Oct 97* 1189-1195
Minowa, I., *see* Inglis, A.D., *T-IM Apr 97* 281-284
Montefusco, A., *see* Bobbio, A., *T-IM Aug 97* 747-751
Morandi, C., *see* Chiorboli, G., *T-IM Feb 97* 56-60
Morawski, R.Z., *see* Massicotte, D., *T-IM Jun 97* 678-684
Morawski, R.Z., *see* Slima, M.B., *T-IM Jun 97* 685-689
Morawski, R.Z., *see* Szczecinski, L., *T-IM Aug 97* 922-928
Morawski, R.Z., *see* Miekina, A., *T-IM Aug 97* 1049-1053
Morikawa, T., M. Aida, A. Otsuka, and Chan Bok Lee. An experiment on frequency transfer using a geostationary broadcasting satellite; *T-IM Apr 97* 216-219
Moron, Z., Z. Rucki, and Z. Szczepanik. The possibility of employing a calculable four-electrode conductance cell to substitute for the secondary standards of electrolytic conductivity; *T-IM Dec 97* 1268-1273
Mosca, M., *see* De Bievre, P., *T-IM Apr 97* 592-595
Muciek, A. Digital impedance bridge based on a two-phase generator; *T-IM Apr 97* 467-470
Muginov, G.D., and A.N. Venetsanopoulos. A new approach for estimating high-speed analog-to-digital converter error; *T-IM Aug 97* 980-985
Muller, F., R. Popel, J. Kohlmann, J. Niemeyer, W. Meier, T. Weimann, L. Grimm, F.-W. Dunschede, and P. Gutmann. Optimized 1 V and 10 V Josephson series arrays; *T-IM Apr 97* 229-232
Mullner, W., *see* Garn, H., *T-IM Apr 97* 544-548

Munter, K., R. Pape, and J. Glimm. Portable E-field strength meter and its traceable calibration up to 1 GHz using a "µTEM" cell; *T-IM Apr 97* 549-550
Muravyov, S.V., and V. Savolainen. Scales and covers in general measurement problem; *T-IM Aug 97* 961-965
Murayama, Y., *see* Yoshida, H., *T-IM Feb 97* 72-78
Murayama, Y., T. Sakuraba, Y. Sakamoto, A. Iwasa, H. Yoshida, T. Kozakai, and T. Endo. Ten-volt Josephson voltage standard at the ETL; *T-IM Apr 97* 233-236
Murayama, Y., *see* Ogita, E., *T-IM Apr 97* 253-255
Murayama, Y., *see* Yoshida, H., *T-IM Apr 97* 260-263
Myllyla, R.A., *see* Makynen, A., *T-IM Oct 97* 1133-1136
Myung Cho Yong, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780

N

Nakamura, Y., *see* Fukushima, A., *T-IM Apr 97* 289-293
Nakane, H., *see* Yamazaki, S., *T-IM Aug 97* 873-876
Nakayama, K., and H. Fujimoto. Progress in the measurement of lattice spacing d(220) of silicon; *T-IM Apr 97* 580-583
Narayanan, C., A.B. Buckman, and I. Busch-Vishniac. Noise analysis for position-sensitive detectors; *T-IM Oct 97* 1137-1144
Narduzzi, C., *see* Bertocco, M., *T-IM Apr 97* 445-448
Narduzzi, C., *see* Bertocco, M., *T-IM Aug 97* 970-974
Narduzzi, C., *see* Bertocco, M., *T-IM Aug 97* 1011-1015
Naujoks, G.A., *see* Hamilton, C.A., *T-IM Apr 97* 237-241
Neagu, M., *see* Hristoforou, E., *T-IM Apr 97* 632-635
Negishi, T., *see* Yamazaki, S., *T-IM Aug 97* 873-876
Nelson, S.O., P.G. Bartley, Jr., and K.C. Lawrence. Measuring RF and microwave permittivities of adult rice weevils; *T-IM Aug 97* 941-946
Neri, B., *see* Ciofi, C., *T-IM Aug 97* 789-793
Neri, B., *see* Baracchino, L., *T-IM Dec 97* 1256 -1261
Nerino, R., A. Sosso, and G.B. Picotto. A novel AC current source for capacitance-based displacement measurements; *T-IM Apr 97* 640-643
Newell, D.B., *see* Fujii, K., *T-IM Apr 97* 191-195
Newell, D.B., *see* Steiner, R.L., *T-IM Apr 97* 601-604
Newell, D.B., *see* Gillespie, *T-IM Apr 97* 605-608
Nezu, Y., *see* Bettin, H., *T-IM Apr 97* 556-559
Nezu, Y., *see* De Bievre, P., *T-IM Apr 97* 592-595
Nezu, Y., *see* Fujii, Y., *T-IM Apr 97* 609-612
Nicolaus, R.A., and G. Bonsch. A novel interferometer for dimensional measurement of a silicon sphere; *T-IM Apr 97* 563-565
Niemeyer, J., *see* Muller, F., *T-IM Apr 97* 229-232
Niemeyer, J., *see* Hebrank, F.X., *T-IM Apr 97* 242-245
Niemeyer, J., *see* Wolf, H., *T-IM Apr 97* 303-306
Niemeyer, J., *see* Kessel, W., *T-IM Apr 97* 477-481
Nilsson, H., *see* Reymann, D., *T-IM Apr 97* 220-223
Nistler, W., *see* Kruger, E., *T-IM Apr 97* 101-103
Noh, M.D., and E.H. Maslen. Self-sensing magnetic bearings using parameter estimation; *T-IM Feb 97* 45-50
Notcutt, M., *see* Taylor, C.T., *T-IM Apr 97* 183-185
Novero, C., *see* Levi, F., *T-IM Apr 97* 126-129
Novomy, D.B., *see* Kinard, J.R., *T-IM Apr 97* 347-351
Novotny, D.B., *see* Kinard, J.R., *T-IM Apr 97* 391-394
Nubile, P. Deep-level characterization of p-n junction devices using trigonometric weight functions; *T-IM Oct 97* 1156-1159
N'zi, E.C., *see* Chavand, F., *T-IM Dec 97* 1229-1235

O

Ogita, E., H. Sakuma, Y. Murayama, and Y. Sakamoto. Step number determination with two sets of frequency and step number in Josephson-junction array voltage standard; *T-IM Apr 97* 253-255
Ohmukai, R., *see* Tanaka, U., *T-IM Apr 97* 137-140
Ohnishi, N., *see* Huang, J., *T-IM Aug 97* 842-846
Oldham, N.M., S. Avramov-Zamurovic, and M.E. Parker. Exploring the low-frequency performance of thermal converters using circuit models and a digitally synthesized source; *T-IM Apr 97* 352-355
Oldham, N.M., S. Avramov-Zamurovic, M.E. Parker, and B.C. Waltrip. Low-voltage standards in the 10 Hz to 1 MHz range; *T-IM Apr 97* 395-398
Oldham, N.M., *see* Waltrip, B.C., *T-IM Aug 97* 781-783
Olsen, P.T., *see* Steiner, R.L., *T-IM Apr 97* 601-604
Olsen, P.T., *see* Gillespie, *T-IM Apr 97* 605-608
Onat, B.M., J.A. McNeill, and U. Cilingiroglu. Implementation of a charge-based neural Euclidean classifier for a 3-bit flash analog-to-digital converter; *T-IM Jun 97* 672-677
Orsevski, V., *see* Dagys, M., *T-IM Apr 97* 499-502
Ortega, J.A., *see* Chavez, J.A., *T-IM Aug 97* 817-821
Osmokrovic, P., D. Petkovic, and O. Markovic. Measuring probe for fast transients monitoring in gas insulated substation; *T-IM Feb 97* 36-44
Otsuka, A., *see* Morikawa, T., *T-IM Apr 97* 216-219
Ovaska, S.J., O. Vainio, and T.I. Laakso. Design of predictive IIR filters via feedback extension of FIR forward predictors; *T-IM Oct 97* 1196-1201

P

Pacaud, A., *see* Bareau, P., *T-IM Aug 97* 1044-1048
Pacut, A., *see* Hejn, K., *T-IM Aug 97* 913-917
Paglierani, P., *see* Bertocco, M., *T-IM Aug 97* 1011-1015
Pajander, H., *see* Reymann, D., *T-IM Apr 97* 220-223
Palojarvi, P., K. Maatta, and J. Kostamovaara. Integrated time-of-flight laser radar; *T-IM Aug 97* 996-999
Panciera, R., *see* Sacconi, A., *T-IM Apr 97* 584-587
Papay, Z. Correction to "Comments on 'The modulo time plot: A useful data acquisition diagnostic tool'" [Dec 96 959]; *T-IM Jun 97* 739
Pape, R., *see* Munter, K., *T-IM Apr 97* 549-550
Park, Y.T., *see* Shapiro, E.Z., *T-IM Apr 97* 412-415
Parker, M.E., *see* Oldham, N.M., *T-IM Apr 97* 352-355
Parker, M.E., *see* Oldham, N.M., *T-IM Apr 97* 395-398
Parker, T.E., *see* Ascarrunz, F.G., *T-IM Apr 97* 205-208
Parker, T.E., *see* Jefferts, S.R., *T-IM Apr 97* 209-211
Park Po Gyu, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100
Park Se II, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780
Parvis, M., *see* Carullo, A., *T-IM Dec 97* 1262-1267
Pasierbinski, J., *see* Kalisz, J., *T-IM Feb 97* 51-55
Pasin, W., *see* Sacconi, A., *T-IM Apr 97* 584-587
Pataki, B., *see* Dobrowiecki, T.P., *T-IM Aug 97* 991-995
Patt, R., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259
Paul, A., *see* Rottger, S., *T-IM Apr 97* 560-562
Paulusse, D.C., *see* Clark, R.F., *T-IM Apr 97* 365-368
Peeters, E.J.E.A., M.S.J. Steyaert, and W. Sansen. High-frequency measurement procedure for fully differential building blocks; *T-IM Aug 97* 1039-1043
Pelka, R., J. Kalisz, and R. Szplet. Nonlinearity correction of the integrated time-to-digital converter with direct coding; *T-IM Apr 97* 449-453
Pelka, R., *see* Kalisz, J., *T-IM Aug 97* 851-856
Peregrino, L., *see* Cosart, L.D., *T-IM Aug 97* 1016-1019
Perez, M.A., *see* Chavez, J.A., *T-IM Aug 97* 817-821
Petersons, O., G.J. FitzPatrick, and E.D. Simmon. An active high-voltage divider with 20 µV/V uncertainty; *T-IM Apr 97* 430-434
Petit, G., and P. Wolf. Computation of the relativistic rate shift of a frequency standard; *T-IM Apr 97* 201-204
Petkovic, D., *see* Osmokrovic, P., *T-IM Feb 97* 36-44
Petley, B.W., *see* Flowers, J.L., *T-IM Apr 97* 104-107
Petri, D., *see* Bertocco, M., *T-IM Aug 97* 970-974
Petri, D., *see* Bertocco, M., *T-IM Aug 97* 1011-1015
Petrizzelli, M., *see* Andreone, D., *T-IM Apr 97* 535-538
Pettorruso, S., *see* De Bievre, P., *T-IM Apr 97* 592-595
Peuto, A., *see* Bettin, H., *T-IM Apr 97* 556-559
Peuto, A., *see* De Bievre, P., *T-IM Apr 97* 592-595
Picard, A., *see* Steiner, R.L., *T-IM Apr 97* 601-604
Picard, O.A., *see* Gillespie, *T-IM Apr 97* 605-608
Picotto, G.B., *see* Nerino, R., *T-IM Apr 97* 640-643
Pietrosanto, A., *see* Baccigalupi, A., *T-IM Jun 97* 731-736
Pinard, J., *see* Juncar, P.P., *T-IM Jun 97* 690-695
Pintelon, R., and J. Schoukens. Frequency-domain identification of linear time-invariant systems under nonstandard conditions; *T-IM Feb 97* 65-71
Pintelon, R., *see* Schoukens, J., *T-IM Aug 97* 1005-1010
Piotrowski, J.K., *see* Galwas, B.A., *T-IM Apr 97* 511-514
Plana, R., *see* Roux, J.-P., *T-IM Oct 97* 1100-1104
Platte, W. Microwave measurements of effective dielectric constant of semiconductor waveguides via periodic-structure photoexcitation; *T-IM Jun 97* 717-721
Plett, G.L., and I. Kollar. Specification for common IEEE styles; *T-IM Dec 97* 1217-1223
Pogliano, U. Precision measurement of AC voltage below 20 Hz at IEN; *T-IM Apr 97* 369-372
Pogliano, U., and G.C. Bosco. Determination of the frequency dependence of the AC-DC voltage standard at IEN; *T-IM Apr 97* 373-376
Po Gyu Park, *see* Shifrin, V.Y., *T-IM Apr 97* 97-100
Pohl, A., and F. Seifert. Wirelessly interrogable surface acoustic wave sensors for vehicular applications; *T-IM Aug 97* 1031-1038
Pollard, R.D., *see* Blackham, D.V., *T-IM Oct 97* 1093-1099
Poniecki, A., *see* Kalisz, J., *T-IM Feb 97* 51-55
Poniecki, A., *see* Kalisz, J., *T-IM Aug 97* 851-856
Popel, R., *see* Muller, F., *T-IM Apr 97* 229-232
Popovic, R.S., *see* Schott, C., *T-IM Apr 97* 613-616
Potenziani, E., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259

Poulin, M., N. Cyr, C. Latrasse, and M. Tetu. Progress in the realization of a frequency standard at 192.1 THz (1560.5 nm) using ^{87}Rb D$_2$-line and second harmonic generation; *T-IM Apr 97* 157-161
Presnov, D.E., *see* Wolf, H., *T-IM Apr 97* 303-306
Prevedelli, M., *see* Udem, T., *T-IM Apr 97* 166-168
Protzmann, M., *see* Boche, H., *T-IM Apr 97* 442-444

Q

Qian Jian, *see* Chih-Wei Chang, *T-IM Oct 97* 1084-1092
Qin Jichang, *see* Trofimenkoff, F.N., *T-IM Oct 97* 1208-1211
Qiu Zhang Jian, *see* Yi Shen, *T-IM Aug 97* 937-940
Qiu Zhang Jian, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

R

Racz, R., *see* Schott, C., *T-IM Apr 97* 613-616
Rae Duk Lee, *see* Semyonov, Yu.P., *T-IM Apr 97* 333-336
Ramsey, I.E., *see* White, D.R., *T-IM Oct 97* 1068-1074
Randa, J., *see* Wait, D.F., *T-IM Apr 97* 482-485
Rasinger, J., *see* Garn, H., *T-IM Apr 97* 544-548
Ratschko, D., B.G. Zhou, D. Knolle, and M. Glaser. Investigations on ion beams from a high-current ion source; *T-IM Apr 97* 588-591
Razet, A., *see* Juncar, P.P., *T-IM Jun 97* 690-695
Rebuldela, G., *see* De Xiang Huang, *T-IM Apr 97* 337-341
Reedtz, G.M., *see* Boella, G., *T-IM Apr 97* 311-313
Renfors, M., *see* Vainio, O., *T-IM Oct 97* 1202-1207
Reymann, D., T.J. Witt, G. Eklund, H. Pajander, and H. Nilsson. Comparison of the Josephson voltage standards of the SP and the BIPM; *T-IM Apr 97* 220-223
Rezmer, J., *see* Lobos, T., *T-IM Aug 97* 877-881
Ricci, G., *see* Conte, E., *T-IM Aug 97* 836-841
Riedijk, F.R., *see* Fasoli, L.G., *T-IM Aug 97* 954-960
Riski, K., *see* Hu, J., *T-IM Apr 97* 186-190
Rivera, R.R., *see* Lorrondo, H.A., *T-IM Oct 97* 1183-1188
Robertazzi, R., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259
Robinson, I.A., and B.P. Kibble. The NPL moving-coil apparatus for measuring Planck's constant and monitoring the kilogram; *T-IM Apr 97* 596-600
Rolain, Y., *see* Steenput, E., *T-IM Aug 97* 742-746
Roman, G., *see* Dobrowiecki, T.P., *T-IM Aug 97* 991-995
Rottger, S., A. Paul, and U. Keyser. Prompt (n, γ)-spectrometry for the isotopic analysis of silicon crystals for the Avogadro project; *T-IM Apr 97* 560-562
Roux, J.-P., L. Escotte, R. Plana, and J. Graffeuil. Wideband on-wafer noise measurement setup for noise characterization of active devices in the low VHF band; *T-IM Oct 97* 1100-1104
Rowley, W.R.C., *see* Barwood, G.P., *T-IM Apr 97* 133-136
Roy, L., M. Li, S. Labonte, and N.R.S. Simons. Measurement techniques for integrated-circuit slot antennas; *T-IM Aug 97* 1000-1004
Rucki, Z., *see* Moron, Z., *T-IM Dec 97* 1268-1273
Ruhaak, J., *see* Kang, T.W., *T-IM Dec 97* 1247-1250
Rydler, K.-E., *see* Simonson, P., *T-IM Apr 97* 423-425

S

Sabouri, F., *see* Trofimenkoff, F.N., *T-IM Oct 97* 1208-1211
Sacconi, A., *see* Bettin, H., *T-IM Apr 97* 556-559
Sacconi, A., R. Panciera, and W. Pasin. Precision volume measurements on silicon spheres [Avogadro constant]; *T-IM Apr 97* 584-587
Sakamoto, Y., *see* Murayama, Y., *T-IM Apr 97* 233-236
Sakamoto, Y., *see* Ogita, E., *T-IM Apr 97* 253-255
Sakamoto, Y., *see* Fukushima, A., *T-IM Apr 97* 289-293
Sakly, S., *see* Machut, C., *T-IM Oct 97* 1128-1132
Sakuma, H., *see* Ogita, E., *T-IM Apr 97* 253-255
Sakuraba, T., *see* Murayama, Y., *T-IM Apr 97* 233-236
Sakuraba, T., *see* Kyu-Tae Kim, *T-IM Apr 97* 314-317
Salter, M.J., *see* Alexander, M.J., *T-IM Apr 97* 539-543
Sannino, M., *see* Caddemi, A., *T-IM Apr 97* 490-494
Sansen, W., *see* Peeters, E.J.E.A., *T-IM Aug 97* 1039-1043
Saramaki, T., *see* Vainio, O., *T-IM Oct 97* 1202-1207
Sardini, E., *see* Marioli, D., *T-IM Feb 97* 27-30
Sasaki, H., B.D. Inglis, K. Takahashi, and M. Klonz. Determination of the time constants of thermoelectric effects in thermal converters using a fast-reversed DC; *T-IM Apr 97* 377-381
Sato, A., *see* Fukushima, A., *T-IM Apr 97* 289-293
Sato, R., *see* Kawamata, K., *T-IM Aug 97* 918-921
Satrapinski, A., *see* Seppa, H., *T-IM Apr 97* 463-466
Savolainen, V., *see* Muravyov, S.V., *T-IM Aug 97* 961-965
Scherer, H., *see* Wolf, H., *T-IM Apr 97* 303-306
Schiek, B., *see* Stolle, R., *T-IM Apr 97* 426-429
Schiek, B., *see* Heuermann, H., *T-IM Oct 97* 1105-1110
Schiek, B., *see* Krekels, H.-G., *T-IM Oct 97* 1115-1119
Schiek, B., *see* Heuermann, H., *T-IM Oct 97* 1120-1127
Schmidt-Szalowski, M., *see* Wiatr, W., *T-IM Apr 97* 486-489
Schott, C., H. Blanchard, R.S. Popovic, R. Racz, and J. Hrejsa. High-accuracy analog Hall probe; *T-IM Apr 97* 613-616
Schoukens, J., *see* Pintelon, R., *T-IM Feb 97* 65-71
Schoukens, J., R. Pintelon, and G. Vandersteen. A sinewave fitting procedure for characterizing data acquisition channels in the presence of time base distortion and time jitter; *T-IM Aug 97* 1005-1010
Schweppe, J.E., *see* Kessler, E.G., Jr., *T-IM Apr 97* 551-555
Seifert, F., *see* Pohl, A., *T-IM Aug 97* 1031-1038
Se Il Park, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780
Semyonov, Yu.P., I. Klebanov, Rae Duk Lee, and Hau Jun Kim. Bifilar AC-DC resistor using a microwire; *T-IM Apr 97* 333-336
Senko, A.P., *see* Akhiezer, A.N., *T-IM Apr 97* 495-498
Seppa, H., and A. Satrapinski. AC resistance bridge based on the cryogenic current comparator; *T-IM Apr 97* 463-466
Seredniy, V.P., *see* Akhiezer, A.N., *T-IM Apr 97* 495-498
Servagent, N., T. Bosch, and M. Lescure. A laser displacement sensor using the self-mixing effect for modal analysis and defect detection; *T-IM Aug 97* 847-850
Shapiro, E.Z., Y.T. Park, N. Budovsky, and A.M. Cibbes. A new power transfer standard, its investigation and intercomparison; *T-IM Apr 97* 412-415
Shen, X.C., *see* Xue, S.Q., *T-IM Apr 97* 250-252
Shen Yi, *see* Yi Shen, *T-IM Aug 97* 937-940
Sherrer, D.W., *see* Arya, V., *T-IM Oct 97* 1173-1177
Shields, J.Q., *see* Jeffery, A.-M., *T-IM Apr 97* 264-268
Shifrin, V.Y., Po Gyu Park, Cheol Gi Kim, V.N. Khorev, and Chang Ho Choi. Experimental determination of the gyromagnetic ratio of the helium-4 atom in terms of that of the helium-3 nucleus; *T-IM Apr 97* 97-100
Shiota, F., *see* Fujii, Y., *T-IM Apr 97* 609-612
Shiping Chen, *see* Yiqun Hu, *T-IM Oct 97* 1160-1164
Shirley, J.H. Velocity distributions calculated from the Fourier transforms of Ramsey lineshapes; *T-IM Apr 97* 117-121
Shun-Chung Wang, *see* Chern-Lin Chen, *T-IM Oct 97* 1145-1149
Siemsen, K.J., *see* Marmet, L., *T-IM Apr 97* 169-173
Simmon, E.D., *see* Petersons, O., *T-IM Apr 97* 430-434
Simniskis, R., *see* Dagys, M., *T-IM Apr 97* 499-502
Simoes, J.B., J. Landeck, and C.M.B.A. Correia. Nonlinearity of a data-acquisition system with interleaving/multiplexing; *T-IM Dec 97* 1274-1279
Simons, N.R.S., *see* Roy, L., *T-IM Aug 97* 1000-1004
Simonsen, H.R. Iodine-stabilized extended cavity diode laser at λ=633 nm; *T-IM Apr 97* 141-144
Simonson, P., S. Svensson, and K.-E. Rydler. A comparison of power measuring systems; *T-IM Apr 97* 423-425
Siskos, S., and A.A. Hatzopoulos. A simple built-in current sensor for current monitoring in mixed-signal circuits; *T-IM Dec 97* 1301-1304
Skubis, T., *see* Kampik, M., *T-IM Apr 97* 387-390
Skulski, J., *see* Galwas, B.A., *T-IM Apr 97* 511-514
Slima, M.B., R.Z. Morawski, and A. Barwicz. Kalman-filter-based algorithms of spectrophotometric data correction III. Use of splines for approximation of spectra; *T-IM Jun 97* 685-689
Snigirev, O., *see* Gudoshnikov, S.A., *T-IM Apr 97* 624-628
So, E., and D.A. Bennett. A low-current multistage clamp-on current transformer with ratio errors below 50×10^{-6}; *T-IM Apr 97* 454-458
Sonck, M., and A. Hermanne. The beam pick-up: a transducer with a versatile set of applications in applied nuclear science; *T-IM Aug 97* 857-861
Soo Han Kwon, *see* Kyu-Tae Kim, *T-IM Apr 97* 314-317
Sosso, A., *see* Nerino, R., *T-IM Apr 97* 640-643
Souders, T.M., B.C. Waltrip, O.B. Laug, and J.P. Deyst. A wideband sampling voltmeter; *T-IM Aug 97* 947-953
Spammer, S.J., *see* Lacquet, B.M., *T-IM Feb 97* 31-35
Spiegel, T., *see* Katzmann, F.L., *T-IM Apr 97* 382-386
Spieweck, F., *see* Bettin, H., *T-IM Apr 97* 556-559
Spieweck, F., *see* De Bievre, P., *T-IM Apr 97* 592-595
Spoelder, H.J.W., *see* Vos, F.M., *T-IM Aug 97* 794-797
Steenput, E., and Y. Rolain. Auto-consistent environment for measurement software development; *T-IM Aug 97* 742-746
Steinbach, A.H., *see* Keller, M.W., *T-IM Apr 97* 307-310
Steiner, R.L., *see* Fujii, K., *T-IM Apr 97* 191-195
Steiner, R.L., A.D. Gillespie, K. Fujii, E.R. Williams, D.B. Newell, A. Picard, C.N. Stenbakken, and P.T. Olsen. The NIST watt balance: progress toward monitoring the kilogram; *T-IM Apr 97* 601-604
Steiner, R.L., *see* Gillespie, *T-IM Apr 97* 605-608
Stenbakken, C.N., *see* Steiner, R.L., *T-IM Apr 97* 601-604
Stenbakken, G.N., *see* Gillespie, *T-IM Apr 97* 605-608
Steyaert, M.S.J., *see* Peeters, E.J.E.A., *T-IM Aug 97* 1039-1043

Stolle, R., and B. Schiek. Multiple-target frequency-modulated continuous-wave ranging by evaluation of the impulse response phase; *T-IM Apr 97* 426-429
Stumper, U. Determination of mismatch factor with RF power calibration using air-line impedance standards; *T-IM Apr 97* 531-534
Stumper, U., *see* Kang, T.W., *T-IM Dec 97* 1247-1250
Sugie, N., *see* Huang, J., *T-IM Aug 97* 842-846
Sukamoto, Y., *see* Kyu-Tae Kim, *T-IM Apr 97* 314-317
Sung-Won Kwon, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780
Sun Jinwei, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030
Svensson, S., *see* Simonson, P., *T-IM Apr 97* 423-425
Svetik, Z., *see* Lapuh, R., *T-IM Aug 97* 784-788
Svoboda, P., *see* Bohacek, J., *T-IM Apr 97* 273-275
Swart, P.L., *see* Lacquet, B.M., *T-IM Feb 97* 31-35
Szczecinski, L., R.Z. Morawski, and A. Barwicz. A cubic FIR-type filter for numerical correction of spectrometric data; *T-IM Aug 97* 922-928
Szczepanik, Z., *see* Moron, Z., *T-IM Dec 97* 1268-1273
Szplet, R., *see* Kalisz, J., *T-IM Feb 97* 51-55
Szplet, R., *see* Pelka, R., *T-IM Apr 97* 449-453
Szplet, R., *see* Kalisz, J., *T-IM Aug 97* 851-856
Szyper, M., *see* Gajda, J., *T-IM Aug 97* 769-775

T

Takahashi, K., *see* Sasaki, H., *T-IM Apr 97* 377-381
Tambe, A., *see* Cosart, L.D., *T-IM Aug 97* 1016-1019
Tanaka, M., *see* Bettin, H., *T-IM Apr 97* 556-559
Tanaka, M., *see* De Bievre, P., *T-IM Apr 97* 592-595
Tanaka, U., H. Imajo, K. Hayasaka, R. Ohmukai, M. Watanabe, and S. Urabe. Laser microwave double-resonance experiment on trapped ^{113}Cd^{+} ions; *T-IM Apr 97* 137-140
Tang Yi-Hua, *see* Yi-Hua Tang, *T-IM Apr 97* 256-259
Tantot, O., M. Chatard-Moulin, and P. Guillon. Measurement of complex permittivity and permeability and thickness of multilayered medium by an open-ended waveguide method; *T-IM Apr 97* 519-522
Tarach, D., and G. Trenkler. A noise-adaptive digital null detector; *T-IM Apr 97* 435-438
Taroni, A., *see* Marioli, D., *T-IM Feb 97* 27-30
Tavella, P., *see* Bobbio, A., *T-IM Aug 97* 747-751
Taylor, C.T., M. Notcutt, Eng Kiong Wong, A.G. Mann, and D.G. Blair. Measurement of the thermal expansion coefficient of an all-sapphire optical cavity; *T-IM Apr 97* 183-185
Taylor, P.D.P., *see* Gonfiantini, R., *T-IM Apr 97* 566-571
Taylor, P.D.P., *see* De Bievre, P., *T-IM Apr 97* 592-595
Tetu, M., *see* Poulin, M., *T-IM Apr 97* 157-161
Toth, F.N., G.C.M. Meijer, and M. van der Lee. A planar capacitive precision gauge for liquid-level and leakage detection; *T-IM Apr 97* 644-646
Toth, H., *see* Bettin, H., *T-IM Apr 97* 556-559
Track, E.K., *see* Yi-Hua Tang, *T-IM Apr 97* 256-259
Trenkler, G., *see* Tarach, D., *T-IM Apr 97* 435-438
Trofimenkoff, F.N., F. Sabouri, Jichang Qin, and J.W. Haslett. A square-rooting voltage-to-frequency converter; *T-IM Oct 97* 1208-1211
Trotta, A., *see* Giaquinto, N., *T-IM Aug 97* 1020-1025
Turnell, D.J., G.S. Deep, and R.C.S. Freire. A low-cost water detection method for furrow irrigation control; *T-IM Aug 97* 986-990
Tyurikov, D., G. Kramer, and B. Lipphardt. Saturated dispersion spectroscopy of OsO$_4$; *T-IM Apr 97* 174-177

U

Udem, T., A. Huber, M. Weitz, D. Leibfried, W. Konig, M. Prevedelli, A. Dimitriev, H. Geiger, and T.W. Hansch. Phase-coherent measurement of the hydrogen 1S-2S frequency with an optical frequency interval divider chain; *T-IM Apr 97* 166-168
Ukhansky, N., *see* Gudoshnikov, S.A., *T-IM Apr 97* 624-628
Urabe, S., *see* Tanaka, U., *T-IM Apr 97* 137-140
Urbanczyk, W., *see* Bock, W.J., *T-IM Aug 97* 903-907

V

Vainio, O., *see* Ovaska, S.J., *T-IM Oct 97* 1196-1201
Vainio, O., M. Renfors, and T. Saramaki. Recursive implementation of FIR differentiators with optimum noise attenuation; *T-IM Oct 97* 1202-1207
Valkiers, S., *see* Gonfiantini, R., *T-IM Apr 97* 566-571
Valkiers, S., *see* De Bievre, P., *T-IM Apr 97* 592-595
Valocchi, P., *see* Bucci, G., *T-IM Aug 97* 831-835
vand den Bos, A. Complex electron wave reconstruction using parameter estimation; *T-IM Aug 97* 826-830
van der Goes, F.M.L., and G.C.M. Meijer. A simple accurate bridge-transducer interface with continuous autocalibration; *T-IM Jun 97* 704-710
van der Heijde, G.L., *see* Vos, F.M., *T-IM Aug 97* 794-797
van der Horn, G., *see* Lyahou, K.F., *T-IM Aug 97* 752-757
van der Lee, M., *see* Toth, F.N., *T-IM Apr 97* 644-646
Vandersteen, G., *see* Schoukens, J., *T-IM Aug 97* 1005-1010
Van Mullem, C., W.J.G.D. Janssen, and J.P.M. De Vreede. Evaluation of the calculable high frequency AC-DC standard; *T-IM Apr 97* 361-364
van Stokkum, I.H.M. Parameter precision in global analysis of time-resolved spectra; *T-IM Aug 97* 764-768
van Stokkum, I.H.M., *see* Vos, F.M., *T-IM Aug 97* 794-797
Varkonyi-Koczy, A.R. Synchronized multisine measurements via DSP methods; *T-IM Aug 97* 929-932
Varlan, M., *see* Gueuning, F., *T-IM Dec 97* 1236-1240
Vasek, P., *see* Bohacek, J., *T-IM Apr 97* 273-275
Venetsanopoulos, A.N., *see* Muginov, G.D., *T-IM Aug 97* 980-985
Vengrus, I.I., *see* Gudoshnikov, S.A., *T-IM Apr 97* 624-628
Verspecht, J. Quantifying the maximum phase-distortion error introduced by signal samplers; *T-IM Jun 97* 660-666
Vickery, A., *see* Hamilton, C.A., *T-IM Apr 97* 237-241
Villeforceix, B., *see* Deshours, F., *T-IM Dec 97* 1251-1255
Villotte, J.-P., *see* Deshours, F., *T-IM Dec 97* 1251-1255
Vollmer, E., *see* Hebrank, F.X., *T-IM Apr 97* 242-245
Vos, F.M., G.L. van der Heijde, H.J.W. Spoelder, I.H.M. van Stokkum, and F.C.A. Groen. A new instrument to measure the shape of the cornea based on pseudorandom color coding; *T-IM Aug 97* 794-797
Vujicic, V.V., *see* Zupunski, I.Z., *T-IM Apr 97* 408-411
Vujicic, V.V., I.Z. Zupunski, and S.S. Milovancev. Predetermination of the quantization error in digital measurement systems; *T-IM Apr 97* 439-441

W

Wait, D.F., and J. Randa. Amplifier noise measurements at NIST; *T-IM Apr 97* 482-485
Waltrip, B.C., *see* Oldham, N.M., *T-IM Apr 97* 395-398
Waltrip, B.C., and N.M. Oldham. Wideband wattmeter based on RMS voltage measurements; *T-IM Aug 97* 781-783
Waltrip, B.C., *see* Souders, T.M., *T-IM Aug 97* 947-953
Wang, A., *see* Arya, V., *T-IM Oct 97* 1173-1177
Wang, H.B., *see* Xue, S.Q., *T-IM Apr 97* 250-252
Wang Shun-Chung, *see* Chern-Lin Chen, *T-IM Oct 97* 1145-1149
Wang Yan, *see* Yi Shen, *T-IM Aug 97* 937-940
Watanabe, K., *see* Yamada, M., *T-IM Feb 97* 3-7
Watanabe, M., *see* Tanaka, U., *T-IM Apr 97* 137-140
Wei Guo, *see* Guo Wei, *T-IM Feb 97* 79-82
Weimann, T., *see* Muller, F., *T-IM Apr 97* 229-232
Weimann, T., *see* Wolf, H., *T-IM Apr 97* 303-306
Weirauch, W., *see* Kruger, E., *T-IM Apr 97* 101-103
Weiss, M.A., *see* Jefferts, S.R., *T-IM Apr 97* 209-211
Weitz, M., *see* Udem, T., *T-IM Apr 97* 166-168
Wen-Shiung Chen, *see* Ho-En Liao, *T-IM Aug 97* 868-872
West, J.L., *see* Gubisch, A., *T-IM Apr 97* 403-407
Weyand, K., and V. Bosse. Fluxgate magnetometer for low-frequency magnetic electromagnetic compatibility measurements; *T-IM Apr 97* 617-620
Weyand, K., *see* Willenberg, G.-D., *T-IM Apr 97* 621-623
Wey Chin-Long, *see* Chin-Long Wey, *T-IM Jun 97* 667-671
White, D.R., and J.M. Williams. Resistance network for verifying the accuracy of resistance bridges; *T-IM Apr 97* 329-332
White, D.R., K. Jones, J.M. Williams, and I.E. Ramsey. A simple resistance network for calibrating resistance bridges; *T-IM Oct 97* 1068-1074
Whitford, B.G., *see* Marmet, L., *T-IM Apr 97* 169-173
Wiatr, W., and M. Schmidt-Szalowski. The multistate radiometer: a novel means for impedance and noise temperature measurement; *T-IM Apr 97* 486-489
Wiatr, W. Multistate radiometry: noise de-embedding and “un-terminating”; *T-IM Apr 97* 503-506
Wiedmann, F., B. Huyart, E. Bergeault, and L. Jallet. New structure for a six-port reflectometer in monolithic microwave integrated-circuit technology; *T-IM Apr 97* 527-530
Wiedmann, F., *see* Hesselbarth, J., *T-IM Aug 97* 966-969
Willenberg, G.-D., and K. Weyand. Three-dimensional positioning setup for magnetometer sensors; *T-IM Apr 97* 621-623
Williams, E.R., *see* Fujii, K., *T-IM Apr 97* 191-195
Williams, E.R., *see* Steiner, R.L., *T-IM Apr 97* 601-604
]Williams, E.R., *see* Gillespie, *T-IM Apr 97* 605-608
Williams, J.M., *see* White, D.R., *T-IM Apr 97* 329-332
Williams, J.M., *see* White, D.R., *T-IM Oct 97* 1068-1074
Witt, T.J., *see* Reymann, D., *T-IM Apr 97* 220-223

Witt, T.J. Low-frequency spectral analysis of DC nanovoltmeters and voltage reference standards; *T-IM Apr 97* 318-321

Wolf, H., F.J. Ahlers, J. Niemeyer, H. Scherer, T. Weimann, A.B. Zorin, V.A. Krupenin, S.V. Lotkhov, and D.E. Presnov. Investigation of the offset charge noise in single electron tunneling devices; *T-IM Apr 97* 303-306

Wolf, P., *see* Petit, G., *T-IM Apr 97* 201-204

Wolffenbuttel, R.F., *see* de Graaf, G., *T-IM Aug 97* 933-936

Wong, K.W., *see* Eren, H., *T-IM Aug 97* 908-912

Wong, K.W., *see* Fung, C.C., *T-IM Dec 97* 1295-1299

Wong Eng Kiong, *see* Taylor, C.T., *T-IM Apr 97* 183-185

Wood, H.M., A.D. Inglis, and M. Cote. Evaluation of the AC quantized Hall resistance; *T-IM Apr 97* 269-272

Wu, P.H., *see* Xue, S.Q., *T-IM Apr 97* 250-252

X

Xiang Huang De, *see* De Xiang Huang, *T-IM Apr 97* 337-341

Xianjun Li, and C.M. Meijier. A new method for the measurement of low speed using a multiple-electrode capacitive sensor; *T-IM Apr 97* 636-639

Xiao Hu, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

Xinmin Zhao, *see* Yi Shen, *T-IM Aug 97* 937-940

Xinmin Zhao, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

Xiujun Li, G. de Jong, and G.C.M. Meijer. The application of the capacitor's physics to optimize capacitive angular-position sensors; *T-IM Feb 97* 8-14

Xu, W.W., *see* Xue, S.Q., *T-IM Apr 97* 250-252

Xue, S.Q., H.H. Li, X.C. Shen, H.B. Wang, W.W. Xu, Q.H. Cheng, and P.H. Wu. High-Tc harmonic mixer applied to Josephson junction array voltage standard at NIM; *T-IM Apr 97* 250-252

Xu Ken, *see* Ken Xu, *T-IM Oct 97* 1081-1083

Y

Yamada, M., and K. Watanabe. A capacitive pressure sensor interface using oversampling Δ-Σ demodulation techniques; *T-IM Feb 97* 3-7

Yamazaki, S., T. Negishi, H. Nakane, N. Hayashi, and S. Yoshizawa. A method to evaluate cracks in a superconductive cylinder used to shield weak magnetic fields; *T-IM Aug 97* 873-876

Yana, K., *see* Mino, H., *T-IM Oct 97* 1189-1195

Yang, Q., *see* Zhang, K., *T-IM Aug 97* 899-902

Yang Ming, *see* Ming Yang, *T-IM Jun 97* 711-716

Yan Wang, *see* Yi Shen, *T-IM Aug 97* 937-940

Ye Jun, *see* Jun Ye, *T-IM Apr 97* 178-182

Yih-Chyun Jenq Perfect reconstruction of digital spectrum from nonuniformly sampled signals; *T-IM Jun 97* 649-652

Yih-Chyun Jenq Direct digital synthesizer with jittered clock; *T-IM Jun 97* 653-655

Yi-Hua Tang, R.T. Hunt, R. Robertazzi, M.A. Fisher, J. Coughlin, R. Patt, E.K. Track, and E. Potenziani. Cryocooled primary voltage standard system; *T-IM Apr 97* 256-259

Yiqun Hu, and Shiping Chen. Two-dimensional encoding scheme for digital spatial domain multiplexed large-scale optical fiber sensor arrays; *T-IM Oct 97* 1160-1164

Yi Shen, Jian Qiu Zhang, Yan Wang, and Zhao Xinmin. A new sensor for paper basis-weight and ash-content measurements; *T-IM Aug 97* 937-940

Yokoi, K., *see* Aoki, T., *T-IM Apr 97* 474-476

Yong Myung Cho, *see* Kyu-Tae Kim, *T-IM Aug 97* 776-780

Yoshida, H., Y. Murayama, and T. Endo. A new 10-V array of Josephson junctions based on low-frequency designs scaled up to 94 GHz; *T-IM Feb 97* 72-78

Yoshida, H., *see* Murayama, Y., *T-IM Apr 97* 233-236

Yoshida, H., T. Kozakai, and Y. Murayama. A precise null-balancing technique (PNB) for the 10 V Josephson junction array voltage standard system; *T-IM Apr 97* 260-263

Yoshizawa, S., *see* Yamazaki, S., *T-IM Aug 97* 873-876

Yushchenko, A.G., and V.V. Chizhov. Precision microwave testing of dielectric substrates; *T-IM Apr 97* 507-510

Z

Zakrzewski, J. Combined magnetoelastic transducer for torque and force measurement; *T-IM Aug 97* 807-810

Zarka, A., J.-M. Chartier, J. Aman, and E. Jaatinen. Intracavity iodine cell spectroscopy with an extended-cavity laser diode around 633 nm; *T-IM Apr 97* 145-148

Zeitler, R. Digital correlator for measuring the velocity of solid surfaces; *T-IM Aug 97* 803-806

Zelle, J.J., *see* Arseneau, R., *T-IM Apr 97* 399-402

Zhang, K., C. Butler, Q. Yang, and Y. Lu. A fiber optic sensor for the measurement of surface roughness and displacement using artificial neural networks; *T-IM Aug 97* 899-902

Zhang Jian Qiu, *see* Yi Shen, *T-IM Aug 97* 937-940

Zhang Jian Qiu, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

Zhao Xinmin, *see* Yi Shen, *T-IM Aug 97* 937-940

Zhao Xinmin, *see* Jian Qiu Zhang, *T-IM Aug 97* 1026-1030

Zhixin Li, and J. Koziol. A theoretical analysis of the laser melt-level monitoring system for the Czochralski crystal growing furnaces; *T-IM Jun 97* 722-730

Zhou, B.G., *see* Ratschko, D., *T-IM Apr 97* 588-591

Zimmerman, N.M., J.L. Cobb, and A.F. Clark. Recent results and future challenges for the NIST charged-capacitor experiment; *T-IM Apr 97* 294-298

Zimmerman, N.M., *see* Keller, M.W., *T-IM Apr 97* 307-310

Zinkernagel, J. Inductive voltage divider of simple design for 120 V and 50 Hz to 30 kHz; *T-IM Oct 97* 1075-1080

Zorin, A.B. Ultimate sensitivity of the single Cooper pair tunneling electrometer; *T-IM Apr 97* 299-302

Zorin, A.B., *see* Wolf, H., *T-IM Apr 97* 303-306

Zosi, G., *see* Bergamin, A., *T-IM Apr 97* 576-579

Zupunski, I.Z., L.M. Holicek, and V.V. Vujicic. Power-factor calibrator; *T-IM Apr 97* 408-411

Zupunski, I.Z., *see* Vujicic, V.V., *T-IM Apr 97* 439-441

SUBJECT INDEX

A

Absolute stability
  two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211

Acceleration measurement
  2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
  ref. accel. generation for accelerometer calib. *Marioli, D., + , T-IM Feb 97* 27-30

AC-DC power conversion
  thin-film ac-dc converter with thermoresistive sens., temp. sens. *Katzmann, F.L., + , T-IM Apr 97* 382-386

Acoustic arrays
  plane reflectors localization, wide-beamwidth US transducer. *Ming Yang, + , T-IM Jun 97* 711-716

Acoustic correlators
  accurate dist. meas. by autonomous US syst. combining TOF and phase-shift methods. *Gueuning, F., + , T-IM Dec 97* 1236-1240

Acoustic detectors; cf. Surface acoustic wave detectors

Acoustic devices; cf. Acoustic correlators; Acoustic resonators; Acoustic transducers; Bulk acoustic wave devices

Acoustic distance measurement
  accurate dist. meas. by autonomous US syst. combining TOF and phase-shift methods. *Gueuning, F., + , T-IM Dec 97* 1236-1240

Acoustic measurements
  speech codecs, objective test. *Bucci, G., + , T-IM Aug 97* 831-835

Acoustic resonators
  AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390

Acoustic signal detection
  sound localization in reverberant environ., precedence effect model. *Huang, J., + , T-IM Aug 97* 842-846

Acoustic signal processing
  accurate dist. meas. by autonomous US syst. combining TOF and phase-shift methods. *Gueuning, F., + , T-IM Dec 97* 1236-1240
  num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246

Acoustic signal processing; cf. Acoustic correlators

Acoustic transducers
  num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246

Active circuits; cf. Active filters; Switched capacitor circuits; Switched resistor circuits

Active filters
  transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867

Agriculture
  irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990
  rice weevils permittivities meas., RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946

- **Air pollution**
  - PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
- **Alloys; cf.** Boron alloys; Germanium alloys; Silicon alloys
- **Aluminum**
  - Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
  - Nb/Al$_2$O$_3$-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481
- **Aluminum compounds**
  - AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
  - GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
  - GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
  - Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
  - Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
  - Nb/Al$_2$O$_3$-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481
  - p-n jn. devices deep-level charactn. *Nubile, P., T-IM Oct 97* 1156-1159
- **Aluminum compounds; cf.** Sapphire
- **Amorphous magnetic wires**
  - FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635
- **Amorphous semiconductors**
  - FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
- **Amplifier noise**
  - absol. voltage amplif., dyn. feedback control. *de Jong, P.C., + , T-IM Aug 97* 758-763
- **Amplifiers; cf.** Differential amplifiers; Feedback amplifiers; Microwave amplifiers; Power FET amplifiers; UHF amplifiers
- **Analog circuits**
  - current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
- **Analog circuits; cf.** Analog integrated circuits
- **Analog-digital conversion**
  - AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
  - AC voltage precision meas., sampling voltmeter. *Pogliano, U., T-IM Apr 97* 369-372
  - autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
  - calib. sigs. dyn. accuracy, integral-sq.-error. *Layer, E., T-IM Oct 97* 1178-1182
  - chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188
  - current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671
  - FPGA integrated time-to-digital converter, direct coding, nonlin. correction. *Pelka, R., + , T-IM Apr 97* 449-453
  - high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
  - interpolating time counter, single-chip, 200-ps resoln. *Kalisz, J., + , T-IM Aug 97* 851-856
  - meas. systs., quantization error predetermination. *Vujicic, V.V., + , T-IM Apr 97* 439-441
  - multisine synchronized meas. via DSP methods. *Varkonyi-Koczy, A.R., T-IM Aug 97* 929-932
  - neural Euclidean classifier, charge based synaptic matrix. *Onat, B.M., + , T-IM Jun 97* 672-677
  - nonlinearity of data-acquisition syst. with interleaving/multiplexing. *Simoes, J.B., + , T-IM Dec 97* 1274-1279
  - sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
  - sq.-rooting voltage-to-freq. converter. *Trofimenkoff, F.N., + , T-IM Oct 97* 1208-1211
  - subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979
  - testing, enhanced sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
  - waveform digitizers, SNR testing, sine-fit vs. DFT algms. *Bertocco, M., + , T-IM Apr 97* 445-448
  - wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953
- **Analog-digital conversion; cf.** Sigma-delta modulation
- **Analog integrated circuits**
  - simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304
- **Analog integrated circuits; cf.** Mixed analog-digital integrated circuits; MOS analog integrated circuits
- **Analog systems**
  - calib. sigs. dyn. accuracy, integral-sq.-error. *Layer, E., T-IM Oct 97* 1178-1182
- **Analog system testing**
  - simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304
- **Anechoic chambers (acoustic)**
  - sound localization in reverberant environ., precedence effect model. *Huang, J., + , T-IM Aug 97* 842-846
- **Anechoic chambers (electromagnetic)**
  - dipole antenna factor calib., primary stds., site atten. meas. *Garn, H., + , T-IM Apr 97* 544-548
- **Anemometers**
  - Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
- **Angle modulation; cf.** Frequency modulation; Phase modulation
- **Angular velocity**
  - low-speed meas., multiple-electrode capacitive sens. *Xianjun Li, + , T-IM Apr 97* 636-639
- **Antenna measurements**
  - dipole antenna factor calib., primary stds., site atten. meas. *Garn, H., + , T-IM Apr 97* 544-548
  - low-uncertainty dipole/monopole std. antennas, insertion loss, antenna factors. *Alexander, M.J., + , T-IM Apr 97* 539-543
  - selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
  - slot antennas meas., input impedance and radiation pattern. *Roy, L., + , T-IM Aug 97* 1000-1004
- **Antenna radiation patterns**
  - dielec. props. meas. at mm-wavelength, free-space. *Friedsam, G.L., + , T-IM Apr 97* 515-518
  - slot antennas meas., input impedance and radiation pattern. *Roy, L., + , T-IM Aug 97* 1000-1004
- **Antennas; cf.** Dipole antennas; Microwave antennas; Monopole antennas
- **Aperture antennas; cf.** Horn antennas; Slot antennas
- **Application specific integrated circuits**
  - FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
  - opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
  - TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999
- **Approximation methods; cf.** Curve fitting; Interpolation; Least squares methods; Linear approximation; Polynomial approximation
- **Argon**
  - Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
  - ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591
- **Arithmetic; cf.** Subtraction
- **Arrays; cf.** Acoustic arrays; Josephson arrays; Logic arrays
- **Artificial intelligence; cf.** Intelligent systems; Learning systems
- **Atomic beams**
  - ^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
- **Atomic clocks**
  - precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
  - Sr$^+$ ion based freq. std. develop. *Barwood, G.P., + , T-IM Apr 97* 133-136
- **Atomic measurements**
  - absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168
  - fine-struct. const., electron g-2 calc. improvement. *Kinoshita, T., T-IM Apr 97* 108-111
  - fund. consts. determ., ^{3}He NMR and hydrogen ESR. *Flowers, J.L., + , T-IM Apr 97* 104-107
  - Ramsey lineshapes anal., vel. distrib. calc. by FT. *Shirley, J.H., T-IM Apr 97* 117-121
  - ^{113}Cd$^+$ trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140
  - ^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
- **Atomic physics**
  - ^{113}Cd$^+$ trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140
  - ^{3}He, opt. pumped NMR, fund. consts. determ. *Flowers, J.L., + , T-IM Apr 97* 104-107
- **Attenuation**
  - microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
- **Attenuation measurement**
  - dipole antenna factor calib., primary stds., site atten. meas. *Garn, H., + , T-IM Apr 97* 544-548

microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293

Attitude control
scanning X-ray interf. over mm baseline, Si (220) lattice spacing meas. *Bergamin, A., + , T-IM Apr 97* 576-579

Automatic test equipment
fault online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44

Automatic testing
current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671
expt. comparison of load-pull meas. systs. for nonlin. power transistor charactn. *Deshours, F., + , T-IM Dec 97* 1251-1255
high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44

Automation; cf. Automatic testing; Design automation

Autoregressive integrated moving average processes
Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195

Autoregressive moving average processes
nonlin. delay elements determ., NARMA models, using dispersion fns. *Ho-En Liao, + , T-IM Aug 97* 868-872

Avalanche diodes; cf. Zener diodes

B

Backpropagation
fiber optic sens. for surface roughness/displacement meas. *Zhang, K., + , T-IM Aug 97* 899-902
modular ANN for prediction of petrophysical props. from well log data. *Fung, C.C., + , T-IM Dec 97* 1295-1299

Bandlimited signals
bandlimited fn. reconstruction, Hilbert transform, EM fields. *Boche, H., + , T-IM Apr 97* 442-444

Barium compounds
YBCO resonators, freq. stds. *Gallop, J.C., + , T-IM Apr 97* 122-125

Beams; cf. Gaussian beams

Beta-ray detectors
paper basis-wt./ash-content meas., nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940

BiCMOS integrated circuits
bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710

Bifurcation
model based opt. resoln. *den Dekker, A.J., T-IM Aug 97* 798-802

Biological systems; cf. Visual system

Biomedical computing
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797

Biomedical image processing
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797

Biomedical measurements
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797

Biomedical signal processing; cf. Biomedical image processing

Bipolar integrated circuits
resistive bridge sens., bitstream output. *Fasoli, L.G., + , T-IM Aug 97* 954-960

Bipolar integrated circuits; cf. BiCMOS integrated circuits

Bipolar transistors; cf. Heterojunction bipolar transistors

Birefringence
interferometric meas. of birefr. opt. fibers. *Bock, W.J., + , T-IM Aug 97* 903-907

Bolometers
supercond. thin-films, microwave surface resist., calorimetric meas. *Andreone, D., + , T-IM Apr 97* 535-538

Boron alloys
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635

Bridge circuits
AC QHE-based calib. of resist. stds. *Bohacek, J., + , T-IM Apr 97* 273-275
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825
current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
multimegohm std. resistors calib., automated guarded bridge. *Jarrett, D.G., T-IM Apr 97* 325-328
NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
resist. bridges accuracy verification. *White, D.R., + , T-IM Apr 97* 329-332
resistive bridge sens., bitstream output. *Fasoli, L.G., + , T-IM Aug 97* 954-960
resist. thermometry bridges, calib., resist. network. *White, D.R., + , T-IM Oct 97* 1068-1074
transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710

Broadcasting; cf. Satellite broadcasting

Buffer circuits
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783

Built-in testing; cf. Self-testing

Bulk acoustic wave devices
AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390

C

Cadmium
^{113}Cd^{+} trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140

Calibration
AC QHE-based calib. of resist. stds. *Bohacek, J., + , T-IM Apr 97* 273-275
AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
alternating voltage meas., ac-dc transfer stds., micropotentiometer-based calib. *Budovsky, I., T-IM Apr 97* 356-360
autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
beam pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861
bifilar AC-DC resistor, microwire. *Semyonov, Yu.P., + , T-IM Apr 97* 333-336
bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
capacitance-based displacement meas., AC current source, input shielding. *Nerino, R., + , T-IM Apr 97* 640-643
capacitance scaling syst., four-terminal-pair LCR meter, inductive voltage divider. *Aoki, T., + , T-IM Apr 97* 474-476
dipole antenna factor calib., primary stds., site atten. meas. *Garn, H., + , T-IM Apr 97* 544-548
double six-port reflectometer, on-wafer calib., absol. power meas. *Berghoff, G., + , T-IM Oct 97* 1111-1114
dual six-port automatic NWA, calib. *Ginley, R.A., T-IM Apr 97* 523-526
dual six-port NWA calib. *Krekels, H.-G., + , T-IM Oct 97* 1115-1119
dyn. accuracy of calib. sigs., integral-sq.-error. *Layer, E., T-IM Oct 97* 1178-1182
high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
inductive voltage divider, ac-power meas., in-phase errors. *Zinkernagel, J., T-IM Oct 97* 1075-1080
Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252
Josephson jn. array, 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263
LF mag. EMC meas., fluxgate magnetometer. *Weyand, K., + , T-IM Apr 97* 617-620
LV stds., 10 Hz, 1 MHz range. *Oldham, N.M., + , T-IM Apr 97* 395-398
microwave pulse meas., resistive sens. *Dagys, M., + , T-IM Apr 97* 499-502
mismatch factor determ., RF power calib. *Stumper, U., T-IM Apr 97* 531-534
mobile cryocooled primary voltage std. without liq. He. *Yi-Hua Tang, + , T-IM Apr 97* 256-259
monitoring calib. status of measuring instrum., stochastic model. *Bobbio, A., + , T-IM Aug 97* 747-751
multimegohm std. resistors calib., automated guarded bridge. *Jarrett, D.G., T-IM Apr 97* 325-328

multistate microwave radiometer, impedance and noise temp. meas. *Wiatr, W., + , T-IM Apr 97* 486-489
multistate radiometry, noise de-embedding/un-terminating. *Wiatr, W., T-IM Apr 97* 503-506
Nb/Al$_2$O$_3$-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481
noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048
NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
on-wafer microwave meas., NWA self-calib. methods. *Heuermann, H., + , T-IM Oct 97* 1105-1110
open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099
PF calibrator using precise wattmeter, autocalibration procedure. *Zupunski, I.Z., + , T-IM Apr 97* 408-411
portable E-field strength meter, traceable calib., µTEM cell. *Munter, K., + , T-IM Apr 97* 549-550
power calibrator, sampled feedback for current and voltage. *Gubisch, A., + , T-IM Apr 97* 403-407
power transducers, PC-based adaptive software. *Chern-Lin Chen, + , T-IM Oct 97* 1145-1149
ref. accel. generation for accelerometer calib. *Marioli, D., + , T-IM Feb 97* 27-30
resist. bridges accuracy verification. *White, D.R., + , T-IM Apr 97* 329-332
resist. thermometry bridges, calib., resist. network. *White, D.R., + , T-IM Oct 97* 1068-1074
RF-DC differences of micropotentiometers. *De Xiang Huang, + , T-IM Apr 97* 337-341
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841
series-resistors-type voltage divider, common error sources. *Kyu-Tae Kim, + , T-IM Aug 97* 776-780
Si analog Hall probe, magnetometry, vert. Hall devices. *Schott, C., + , T-IM Apr 97* 613-616
sig. samplers phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666
six-port reflectometers, large bandwidths. *Hesselbarth, J., + , T-IM Aug 97* 966-969
smart capacitive ang.-posn. sens., self-calib. *Li, X., + , T-IM Aug 97* 888-892
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928
std. time/freq. sig. broadcast via INSAT, differential mode. *Gupta, A.S., + , T-IM Apr 97* 212-215
three-phase digital recorder syst. for calib. power instrumentation. *Arseneau, R., + , T-IM Apr 97* 399-402
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
transportable compact Josephson voltage std. *Hamilton, C.A., + , T-IM Apr 97* 237-241
voltage source eval., calculable RMS outputs. *Lapuh, R., + , T-IM Aug 97* 784-788
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
Zener voltage std. calib. at 10 V, KRISS vs ETL. *Kyu-Tae Kim, + , T-IM Apr 97* 314-317

Calorimetry
mm-wave power stds., isothermal calorimeter power meters. *Akhiezer, A.N., + , T-IM Apr 97* 495-498
NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
supercond. thin-films, microwave surface resist., calorimetric meas. *Andreone, D., + , T-IM Apr 97* 535-538

Cameras
three-step camera calib. for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172

Capacitance measurement
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825
irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990
NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
scaling syst., four-terminal-pair LCR meter, inductive voltage divider. *Aoki, T., + , T-IM Apr 97* 474-476
seven-jn. electron pump, design, fab., and operation. *Keller, M.W., + , T-IM Apr 97* 307-310

Capacitance transducers
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
displacement meas., AC current source, input shielding. *Nerino, R., + , T-IM Apr 97* 640-643
liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646

Capacitors
NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298

Capacitors; cf. Power capacitors

Carbon compounds; cf. Organic compounds

Carbon dioxide lasers
CO$_2$/OsO$_4$ lasers as freq. stds., 29 THz range. *Acef, O., T-IM Apr 97* 162-165
precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173

Cavity resonators; cf. Coaxial resonators; Superconducting cavity resonators

Cepstral analysis
num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246

Cesium
at. beam freq. stds., Ramsey pattern anal. *Makdissi, A., + , T-IM Apr 97* 112-116

Chaos
chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188

Charge coupled image sensors
birefr. opt. fibers meas., interferometry. *Bock, W.J., + , T-IM Aug 97* 903-907

Charge measurement
offset charge noise in SET devices. *Wolf, H., + , T-IM Apr 97* 303-306
scan conversion-based transient digitizers, improved sig. extraction. *Arpaia, P., + , T-IM Aug 97* 893-898
tunneling electrometer, single Cooper pair type, sensitivity. *Zorin, A.B., T-IM Apr 97* 299-302

Charge transfer image sensors; cf. Charge coupled image sensors

Chemical analysis; cf. Spectrochemical analysis

Chemical transducers; cf. Gas detectors

Choppers
absol. voltage amplif., dyn. feedback control. *de Jong, P.C., + , T-IM Aug 97* 758-763
Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263
resistive bridge sens., bitstream output. *Fasoli, L.G., + , T-IM Aug 97* 954-960

Circuit analysis
differential amplifer, common-mode rejection ratio redefined. *Koide, F.T., T-IM Jun 97* 737-739

Circuit modeling
subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979
thermal voltage converters, LF perform., cct. models. *Oldham, N.M., + , T-IM Apr 97* 352-355

Circuit noise
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256 -1261

Circuit noise; cf. Amplifier noise; Filter noise; Oscillator noise

Circuit optimization
FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867

Circuits; cf. Analog circuits; Bridge circuits; Buffer circuits; Counting circuits; Equivalent circuits; Feedback circuits; Integrated circuits; Linear circuits; Millimeter wave circuits; Multiport circuits; One-port circuits; Phase shifters; Programmable circuits; Resistive circuits; Stochastic circuits; Switched capcacitor circuits; Switched resistor circuits

Circuit simulation
chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188
NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979

Circuit stability
- absol. voltage amplif., dyn. feedback control. *de Jong, P.C., + , T-IM Aug 97* 758-763

Circuit synthesis
- predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201

Circuit testing
- high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
- subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979

Circuit testing; cf. Integrated circuit testing

Circuit topology
- current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
- transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867

Circular waveguides
- dielec. meas. using coaxial resonator, L-band automated syst. *Galwas, B.A., + , T-IM Apr 97* 511-514
- multilayers permitt./permeab./thickness meas., waveguide. *Tantot, O., + , T-IM Apr 97* 519-522
- precision microwave testing of dielec. substrs. *Yushchenko, A.G., + , T-IM Apr 97* 507-510

Clocks
- Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
- clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
- direct digital synthesizer, jittered clock. *Yih-Chyun Jenq, T-IM Jun 97* 653-655
- freq. std., relativistic rate shift. *Petit, G., + , T-IM Apr 97* 201-204

Closed loop systems
- opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806

Clutter; cf. Radar clutter

CMOSFET logic devices
- interpolating time counter, single-chip, 200-ps resoln. *Kalisz, J., + , T-IM Aug 97* 851-856

CMOS integrated circuits
- 2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
- FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
- sq.-rooting voltage-to-freq. converter. *Trofimenkoff, F.N., + , T-IM Oct 97* 1208-1211

CMOS integrated circuits; cf. BiCMOS integrated circuits

Coaxial components
- open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099
- permitt. meas. of rice weevils, RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946

Coaxial resonators
- dielec. meas. using coaxial resonator, L-band automated syst. *Galwas, B.A., + , T-IM Apr 97* 511-514

Coaxial transmission lines
- microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
- permitt. meas. of rice weevils, RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946

Codecs; cf. Speech codecs

Coils
- externally shielded cryogenic current comparator, sensitivity meas., QHR bridges. *Early, M.D., + , T-IM Apr 97* 459-462
- ferrofluid fluxgate sens. magnetometer, dc mag. field intens. meas. *Baltag, O., + , T-IM Apr 97* 629-631
- K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816
- SQUID magnetometer sens., 3D positioning setup. *Willenberg, G.-D., + , T-IM Apr 97* 621-623

Color
- light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936

Communication equipment; cf. Receivers

Communication equipment testing
- speech codecs, objective test. *Bucci, G., + , T-IM Aug 97* 831-835

Communication system nonlinearities
- two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208

Communication systems
- clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294

Communication systems; cf. Digital communication; Optical communication; Spread spectrum communication

Communication terminals; cf. Satellite communication earth terminals

Comparators
- NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
- thermal power transfer std., resistive voltage divider, comparator. *Shapiro, E.Z., + , T-IM Apr 97* 412-415
- thermal wattmeter, power comparator, ac power meas. *Laiz, H., + , T-IM Apr 97* 420-422
- wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953

Comparators; cf. Current comparators; Phase comparators

Compensation
- act. HV divider with 20 μV/V uncertainty, compressed-gas capacitor. *Petersons, O., + , T-IM Apr 97* 430-434
- fiber optic grating-based devices, temp. compensation. *Arya, V., + , T-IM Oct 97* 1173-1177
- Peltier sens. for meas. thermal cond. of fluids. *Machut, C., + , T-IM Oct 97* 1128-1132
- piezoresistive tactile sens. *Fiorillo, A.S., T-IM Feb 97* 15-17

Compensation; cf. Error compensation

Complementary circuits; cf. CMOS integrated circuits

Complexity theory
- meas. software develop., auto-consistent environ. *Steenput, E., + , T-IM Aug 97* 742-746
- multisine synchronized meas. via DSP methods. *Varkonyi-Koczy, A.R., T-IM Aug 97* 929-932
- spectrophotometric data correction, Kalman-filter, use of splines. *Slima, M.B., + , T-IM Jun 97* 685-689

Computer aided analysis
- DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321

Computer applications; cf. Biomedical computing; Computer aided analysis; Design automation; Microcomputer applications; Neural network applications

Computer interfaces
- bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710

Computers; cf. Modular computer systems

Conducting films; cf. Superconducting films

Conducting liquids
- employing calculable four-electrode conductance cell to substitute for secondary standards of electrolytic conductivity. *Moron, Z., + , T-IM Dec 97* 1268-1273
- liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646

Conductivity measurement
- employing calculable four-electrode conductance cell to substitute for secondary standards of electrolytic conductivity. *Moron, Z., + , T-IM Dec 97* 1268-1273

Contact resistance
- AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288

Contacts
- voltage transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921

Continuous time systems
- LTI systs., nonstandard conditions, freq.-domain ident. *Pintelon, R., + , T-IM Feb 97* 65-71

Control equipment; cf. Microcontrollers

Control systems; cf. Closed loop systems; Digital control; Servosystems

Converters; cf. Frequency conversion; Thermal converters

Convolution
- spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684

Cooling
- mobile cryocooled primary voltage std. without liq. He. *Yi-Hua Tang, + , T-IM Apr 97* 256-259
- ^{113}Cd^{+} trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140

Copper
- microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
- resist. scaling, loading effects. *Elmquist, R.E., + , T-IM Apr 97* 322-324

Correlators; cf. Acoustic correlators; Optical correlators

Counting circuits
- interpolating time counter, single-chip, 200-ps resoln. *Kalisz, J., + , T-IM Aug 97* 851-856

Coupled transmission lines
- voltage transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921

Crack detection
superconductive cylinder cracks eval. by impedance meas. *Yamazaki, S., + , T-IM Aug 97* 873-876
Crosstalk
NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
Crosstalk; cf. Optical crosstalk
Cryogenic electronics
loading effects in resist. scaling. *Elmquist, R.E., + , T-IM Apr 97* 322-324
NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
Cryogenics
AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
externally shielded cryogenic current comparator, sensitivity meas., QHR bridges. *Early, M.D., + , T-IM Apr 97* 459-462
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
Crystal growth
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
Crystals; cf. Sapphire
Current; cf. Leakage currents
Current comparators
AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825
externally shielded cryogenic current comparator, sensitivity meas., QHR bridges. *Early, M.D., + , T-IM Apr 97* 459-462
loading effects in resist. scaling. *Elmquist, R.E., + , T-IM Apr 97* 322-324
mutual inductance independent of primary winding posn. and ambient fields. *Miljanic, P.N., T-IM Apr 97* 471-473
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
Current density
Ar^+ ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591
Current measurement
false-bal.-avoidance transductor for measuring large DC currents. *Ken Xu, + , T-IM Oct 97* 1081-1083
multiconverter modules, thin-film multijunction thermal converters. *Kinard, J.R., + , T-IM Apr 97* 391-394
multistage clamp-on CT, ratio errors, low current meas. *So, E., + , T-IM Apr 97* 454-458
mutual inductance independent of primary winding posn. and ambient fields. *Miljanic, P.N., T-IM Apr 97* 471-473
simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304
Current measurement; cf. Current comparators; Current transformers
Current mode logic
BIST design of current-mode algorithmic A/D converters. *Chin-Long Wey, T-IM Jun 97* 667-671
Current transformers
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816
multistage clamp-on CT, ratio errors, low current meas. *So, E., + , T-IM Apr 97* 454-458
Curve fitting
ADC, effective bit estim. methods accuracy. *Bertocco, M., + , T-IM Aug 97* 1011-1015
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
sinewave fitting procedure for data acquisition channels characterization. *Schoukens, J., + , T-IM Aug 97* 1005-1010
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
time-resolved spectra global anal., param. precision. *van Stokkum, I.H.M., T-IM Aug 97* 764-768
CW lasers
crosstalk anal. of 1 m to 10 m laser phase-shift range finder. *Bosch, T., + , T-IM Dec 97* 1224-1228
CW radar; cf. FM radar
Cyclotron radiation
beam pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861

D

Data acquisition
AC voltage precision meas., sampling voltmeter. *Pogliano, U., T-IM Apr 97* 369-372
chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188
correction to "comments on 'The modulo time plot: A useful data acquisition diagnostic tool'" (Dec 96 959). *Papay, Z., T-IM Jun 97* 739
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
nonlinearity of data-acquisition syst. with interleaving/multiplexing. *Simoes, J.B., + , T-IM Dec 97* 1274-1279
power amp. design, RF transistor large-sig. meas. *Cheng-Yung Chiang, + , T-IM Oct 97* 1150-1155
power meter for highly distorted three-phase systs. *Carullo, A., + , T-IM Dec 97* 1262-1267
sinewave fitting procedure for data acquisition channels characterization. *Schoukens, J., + , T-IM Aug 97* 1005-1010
Database systems
3D meas. using video camera and range finder. *Chavand, F., + , T-IM Dec 97* 1229-1235
Data conversion; cf. Analog-digital conversion; Digital-analog conversion
Data handling; cf. Measurement system data handling
Data models
meas. software develop., auto-consistent environ. *Steenput, E., + , T-IM Aug 97* 742-746
Data processing; cf. Text processing
Decision-making; cf. Pattern classification
Deconvolution
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
Delay effects
predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211
Delay estimation
accurate dist. meas. by autonomous US syst. combining TOF and phase-shift methods. *Gueuning, F., + , T-IM Dec 97* 1236-1240
nonlin. delay elements determ., NARMA models, using dispersion fns. *Ho-En Liao, + , T-IM Aug 97* 868-872
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
Delay lines
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635
FPGA integrated time-to-digital converter, direct coding, nonlin. correction. *Pelka, R., + , T-IM Apr 97* 449-453
FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
Delta modulation; cf. Sigma-delta modulation
Demodulation
metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
Density measurement
Si dens. stds., internat. intercomparison. *Bettin, H., + , T-IM Apr 97* 556-559
Si, molar vol. rel., Avogadro const. determ. *De Bievre, P., + , T-IM Apr 97* 592-595
Si sphere dimens. meas., Avogadro's no. determ. *Nicolaus, R.A., + , T-IM Apr 97* 563-565
Design automation
2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
power amp. design, RF transistor large-sig. meas. *Cheng-Yung Chiang, + , T-IM Oct 97* 1150-1155
Design automation software; cf. SPICE
Design for testability
current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671
Design methodology; cf. Design automation
Detectors
capacitance-based displacement meas., AC current source, input shielding. *Nerino, R., + , T-IM Apr 97* 640-643
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7

dielec. meas. using coaxial resonator, L-band automated syst. *Galwas, B.A., + , T-IM Apr 97* 511-514
liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646
low-speed meas., multiple-electrode capacitive sens. *Xianjun Li, + , T-IM Apr 97* 636-639
microwave pulse meas., resistive sens. *Dagys, M., + , T-IM Apr 97* 499-502
Peltier sens. for meas. thermal cond. of fluids. *Machut, C., + , T-IM Oct 97* 1128-1132
piezoresistive tactile sens. *Fiorillo, A.S., T-IM Feb 97* 15-17
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50
smart capacitive ang.-posn. sens., self-calib. *Li, X., + , T-IM Aug 97* 888-892
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867
Dielectric breakdown; cf. Gas discharges
Dielectric devices; cf. Capacitors; Dielectric resonator oscillators
Dielectric films
precision microwave testing of dielec. substrs. *Yushchenko, A.G., + , T-IM Apr 97* 507-510
Dielectric losses
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
Dielectric materials; cf. Dielectric films
Dielectric measurements
permitt. meas. of rice weevils, RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
Dielectric measurements; cf. Permittivity measurement
Dielectric resonator oscillators
high-T_c resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
Difference equations
freq. estim., drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
Differential amplifiers
common-mode rejection ratio redefined. *Koide, F.T., T-IM Jun 97* 737-739
HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043
neural Euclidean classifier, charge based synaptic matrix. *Onat, B.M., + , T-IM Jun 97* 672-677
Differential equations; cf. Stochastic differential equations
Differentiating circuits
FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
Diffraction; cf. Electromagnetic diffraction
Diffusion processes; cf. Electromigration
Digital-analog conversion
direct digital synthesizer, jittered clock. *Yih-Chyun Jenq, T-IM Jun 97* 653-655
multiple digital sig. generators, noise-adaptive digital null detector. *Tarach, D., + , T-IM Apr 97* 435-438
transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867
voltage source eval., calculable RMS outputs. *Lapuh, R., + , T-IM Aug 97* 784-788
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953
Digital circuits; cf. Digital filters
Digital communication
metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
Digital communication; cf. Synchronous Digital Hierarchy
Digital control
irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990
Digital filters
predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
Digital filters; cf. FIR digital filters; IIR digital filters; Recursive digital filters
Digital integrated circuits; cf. Mixed analog-digital integrated circuits
Digital measurements
clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
digital meas. systs., quantization error predetermination. *Vujicic, V.V., + , T-IM Apr 97* 439-441
multiple digital sig. generators, noise-adaptive digital null detector. *Tarach, D., + , T-IM Apr 97* 435-438
num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783
Digital radio; cf. Spread spectrum communication
Digital signal processors
power meter for highly distorted three-phase systs. *Carullo, A., + , T-IM Dec 97* 1262-1267
Dipole antennas
factor calib., primary stds., site atten. meas. *Garn, H., + , T-IM Apr 97* 544-548
low-uncertainty dipole/monopole std. antennas, insertion loss, antenna factors. *Alexander, M.J., + , T-IM Apr 97* 539-543
Directive antennas; cf. Horn antennas
Discrete Fourier transforms
ADC, effective bit estim. methods accuracy. *Bertocco, M., + , T-IM Aug 97* 1011-1015
multiple-target FM CW ranging by eval. of impulse response phase. *Stolle, R., + , T-IM Apr 97* 426-429
multisine synchronized meas. via DSP methods. *Varkonyi-Koczy, A.R., T-IM Aug 97* 929-932
Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
power syst. freq. real-time determ. *Lobos, T., + , T-IM Aug 97* 877-881
sinewave optimized test of waveform digitizers, DFT approach. *Bertocco, M., + , T-IM Aug 97* 970-974
waveform digitizers, SNR testing, sine-fit vs. DFT algms. *Bertocco, M., + , T-IM Apr 97* 445-448
Discrete time systems; cf. Sampled data systems
Discrete transforms; cf. Discrete Fourier transforms
Displacement measurement
capacitance-based displacement meas., AC current source, input shielding. *Nerino, R., + , T-IM Apr 97* 640-643
fiber optic sens. for surface roughness/displacement meas. *Zhang, K., + , T-IM Aug 97* 899-902
laser displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200
Distance measurement; cf. Acoustic distance measurement; Optical distance measurement; Radar distance measurement
Distortion
power meter for highly distorted three-phase systs. *Carullo, A., + , T-IM Dec 97* 1262-1267
scan conversion-based transient digitizers, improved sig. extraction. *Arpaia, P., + , T-IM Aug 97* 893-898
three-phase digital recorder syst. for calib. power instrumentation. *Arseneau, R., + , T-IM Apr 97* 399-402
Distortion; cf. Harmonic distortion; Jitter; Phase distortion
Distributed feedback lasers
freq. std., ^{87}Rb D$_2$-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161
Dither techniques
autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
dither-based quantizing systs. design. *Carbone, P., T-IM Jun 97* 656-659
Doppler effect
Cs beam freq. stds., Ramsey pattern anal. *Makdissi, A., + , T-IM Apr 97* 112-116
freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
DRAM chips
neural Euclidean classifier, charge based synaptic matrix. *Onat, B.M., + , T-IM Jun 97* 672-677
Dynamic response
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
Dynamic response; cf. Transient response

E

Echo interference
plane reflectors localization, wide-beamwidth US transducer. *Ming Yang, + , T-IM Jun 97* 711-716

Electric field measurement
fiber optic elec. field probe, liq. crysts. *Lacquet, B.M., + , T-IM Feb 97* 31-35
Electric fields
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
Electric variables; cf. Attenuation; Inductance
Electric variables measurement
sig. samplers phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666
Electric variables measurement; cf. Attenuation measurement; Capacitance measurement; Conductivity measurement; Current measurement; Dielectric measurements; Electric field measurement; Energy measurement; Gain measurement; Impedance measurement; Power measurement; Resistance measurement; Voltage measurement
Electrochemical processes
employing calculable four-electrode conductance cell to substitute for secondary standards of electrolytic conductivity. *Moron, Z., + , T-IM Dec 97* 1268-1273
Electromagnetic compatibility
LF mag. EMC meas., fluxgate magnetometer. *Weyand, K., + , T-IM Apr 97* 617-620
low-uncertainty dipole/monopole std. antennas, insertion loss, antenna factors. *Alexander, M.J., + , T-IM Apr 97* 539-543
portable E-field strength meter, traceable calib., µTEM cell. *Munter, K., + , T-IM Apr 97* 549-550
voltage transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921
Electromagnetic diffraction
dielec. props. meas. at mm-wavelength, free-space. *Friedsam, G.L., + , T-IM Apr 97* 515-518
Electromagnetic diffraction; cf. Optical diffraction
Electromagnetic fields
bandlimited fn. reconstruction, Hilbert transform, EM fields. *Boche, H., + , T-IM Apr 97* 442-444
Electromagnetic interference
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
Electromagnetic interference; cf. Power distribution electromagnetic interference
Electromagnetic measurements
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
Electromagnetic measurements; cf. Microwave measurements; Millimeter wave measurements; UHF measurements; VHF measurements
Electromagnetic radiation; cf. Antenna radiation patterns; Cyclotron radiation
Electromagnetic reflection; cf. Microwave reflectometry; Optical reflection
Electromagnetic refraction; cf. Optical refraction
Electromagnetic scattering; cf. Radar scattering
Electromagnetic transient analysis; cf. Switching transients
Electromigration
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
Electronic equipment testing
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
sinewave optimized test of waveform digitizers, DFT approach. *Bertocco, M., + , T-IM Aug 97* 970-974
Electronic equipment testing; cf. Communication equipment testing
Electronics; cf. Road vehicle electronics
Electron microscopy
complex electron wave reconstruction, param. estim. *vand den Bos, A., T-IM Aug 97* 826-830
Electrostatic measurements; cf. Charge measurement
Encoding
FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
position estim. of mobile robots based on coded IR sig. transm. *Eren, H., + , T-IM Dec 97* 1280-1283
Encoding; cf. Image coding; Multidimensional coding; Speech codecs
Energy measurement
comments on "Accurate measurement of power, energy, and true RMS voltage using synchronous counting" by J.K. Kolanko (Jun 93 752-754). *Mauritzen, D.W., + , T-IM Dec 97* 1300-1301
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
Environmental factors
irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990
Epitaxial growth
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
Equations; cf. Difference equations; Integral equations; Stochastic differential equations
Equivalent circuits
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
Error analysis
ADC, effective bit estim. methods accuracy. *Bertocco, M., + , T-IM Aug 97* 1011-1015
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
A/D converters quantization-noise estim. uncertainties. *Chiorboli, G., + , T-IM Feb 97* 56-60
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
sq.-rooting voltage-to-freq. converter. *Trofimenkoff, F.N., + , T-IM Oct 97* 1208-1211
two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953
Error compensation
time-division watt-converter,frequency depend. systematic error, compensation. *Jovanovic, L.D., T-IM Apr 97* 416-419
Error correction
freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
Si analog Hall probe, magnetometry, vert. Hall devices. *Schott, C., + , T-IM Apr 97* 613-616
std. time/freq. sig. broadcast via INSAT, differential mode. *Gupta, A.S., + , T-IM Apr 97* 212-215
subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979
Estimation
Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
Estimation; cf. Delay estimation; Least squares methods; Maximum likelihood estimation; Nonlinear estimation; Parameter estimation
Etching
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
Expert systems
measuring instrums. as agents, future prospects. *Dobrowiecki, T.P., + , T-IM Aug 97* 991-995

F

Fabrication; cf. Optical device fabrication; Semiconductor device fabrication
Fabry-Perot interferometers
extended-cavity LD stabilized on I_2, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
Fabry-Perot resonators
freq. std., ^{87}Rb D_2-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161
precision freq. meas., diode laser locked Sr^+ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
Farming; cf. Agriculture
Fault currents; cf. Leakage currents
Fault diagnosis
online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979
Fault tolerance
false-bal.-avoidance transductor for measuring large DC currents. *Ken Xu, + , T-IM Oct 97* 1081-1083
Feedback
false-bal.-avoidance transductor for measuring large DC currents. *Ken Xu, + , T-IM Oct 97* 1081-1083
FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
Nb/Al_2O_3-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481

power calibrator, sampled feedback for current and voltage. *Gubisch, A., + , T-IM Apr 97* 403-407
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953

Feedback amplifiers
absol. voltage amplif., dyn. feedback control. *de Jong, P.C., + , T-IM Aug 97* 758-763
act. HV divider with 20 μV/V uncertainty, compressed-gas capacitor. *Petersons, O., + , T-IM Apr 97* 430-434
differential amplifer, common-mode rejection ratio redefined. *Koide, F.T., T-IM Jun 97* 737-739

Feedback amplifiers; cf. Operational amplifiers

Feedback circuits
differential amplifer, common-mode rejection ratio redefined. *Koide, F.T., T-IM Jun 97* 737-739
predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201

Feedback lasers
displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
freq. std., ^{87}Rb D$_2$-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161

Feedback lasers; cf. Distributed feedback lasers

Feedback systems; cf. Servosystems

Feedforward neural networks; cf. Multilayer perceptrons

Ferromagnetic materials
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635

FET amplifiers; cf. Power FET amplifiers

FET analog integrated circuits; cf. MOS analog integrated circuits

FET oscillators; cf. MESFET oscillators

FETs; cf. Microwave FETs; MODFETs

Field programmable gate arrays
interpolating time counter, single-chip, 200-ps resoln. *Kalisz, J., + , T-IM Aug 97* 851-856
time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
time-to-digital converter, integrated, direct coding, nonlin. correction. *Pelka, R., + , T-IM Apr 97* 449-453

File systems
chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188

Films; cf. Dielectric films

Filtering
Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
sound localization in reverberant environ., precedence effect model. *Huang, J., + , T-IM Aug 97* 842-846
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928
spectrophotometric data correction, Kalman-filter, use of splines. *Slima, M.B., + , T-IM Jun 97* 685-689

Filtering; cf. Kalman filtering

Filter noise
transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867

Filters; cf. Active filters; Digital filters; Microwave filters; Nonlinear filters

Finite element methods
multilayers permitt./permeab./thickness meas., waveguide. *Tantot, O., + , T-IM Apr 97* 519-522
scanning X-ray interf. over mm baseline, Si (220) lattice spacing meas. *Bergamin, A., + , T-IM Apr 97* 576-579

Finline components
Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78

FIR digital filters
differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
power syst. freq. real-time determ. *Lobos, T., + , T-IM Aug 97* 877-881
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928

Fluid flow measurement
neural networks for hydrocyclone param. d50$_c$ estim. *Eren, H., + , T-IM Aug 97* 908-912
Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
sq.-rooting voltage-to-freq. converter. *Trofimenkoff, F.N., + , T-IM Oct 97* 1208-1211

FM radar
multiple-target FM CW ranging by eval. of impulse response phase. *Stolle, R., + , T-IM Apr 97* 426-429

Force measurement
magnetoelastic transducer for torque and force meas. *Zakrzewski, J., T-IM Aug 97* 807-810

Fourier series
electron wave reconstruction, param. estim. *vand den Bos, A., T-IM Aug 97* 826-830

Fourier transforms
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
Ramsey lineshapes anal., vel. distrib. calc. by FT. *Shirley, J.H., T-IM Apr 97* 117-121

Fourier transforms; cf. Discrete Fourier transforms

Frequency conversion
absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168

Frequency conversion; cf. Optical frequency conversion

Frequency domain analysis
LTI systs., nonstandard conditions, freq.-domain ident. *Pintelon, R., + , T-IM Feb 97* 65-71
sig. samplers phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053

Frequency estimation
drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
power syst. freq. real-time determ. *Lobos, T., + , T-IM Aug 97* 877-881

Frequency measurement
absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168
Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
CO$_2$/OsO$_4$ lasers as freq. stds., 29 THz range. *Acef, O., T-IM Apr 97* 162-165
Cs beam freq. stds., Ramsey pattern anal. *Makdissi, A., + , T-IM Apr 97* 112-116
extended cavity diode laser, I$_2$-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
fringe counting sigmameter, opt. wavelength ratio meas. *Juncar, P.P., + , T-IM Jun 97* 690-695
geostationary broadcasting satellite, freq. transfer syst. *Morikawa, T., + , T-IM Apr 97* 216-219
He-Ne laser, ^{127}I$_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
high-T$_c$ resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
laser displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
OsO$_4$ saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177
power syst. freq. real-time determ. *Lobos, T., + , T-IM Aug 97* 877-881
precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
Ramsey lineshapes anal., vel. distrib. calc. by FT. *Shirley, J.H., T-IM Apr 97* 117-121
relativistic rate shift of freq. std. *Petit, G., + , T-IM Apr 97* 201-204
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
selected papers CPEM’96 (special issue). *T-IM Apr 97* 94-646
Sr$^+$ ion based freq. std. develop. *Barwood, G.P., + , T-IM Apr 97* 133-136
std., ^{87}Rb D$_2$-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161
^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
ultrastable opt. freq. ref., 1.064 μm. *Jun Ye, + , T-IM Apr 97* 178-182

Frequency modulation
Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
Cs beam freq. stds., Ramsey pattern anal. *Makdissi, A., + , T-IM Apr 97* 112-116
ultrastable opt. freq. ref., 1.064 μm. *Jun Ye, + , T-IM Apr 97* 178-182

Frequency response
LF mag. EMC meas., fluxgate magnetometer. *Weyand, K., + , T-IM Apr 97* 617-620
portable E-field strength meter, traceable calib., μTEM cell. *Munter, K., + , T-IM Apr 97* 549-550
transimpedance filter topol. for instrumentation. *Carlosena, A., + , T-IM Aug 97* 862-867

Frequency stability
Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129

Functions; cf. Spline functions; Transfer functions
Furnaces
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730

G

Gain measurement
low-uncertainty dipole/monopole std. antennas, insertion loss, antenna factors. *Alexander, M.J., + , T-IM Apr 97* 539-543
Galerkin method
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
Gallium compounds
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
FET large-sig. meas., power amp. design. *Cheng-Yung Chiang, + , T-IM Oct 97* 1150-1155
GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
p-n jn. devices deep-level charactn. *Nubile, P., T-IM Oct 97* 1156-1159
six-port reflectometer in MMIC technol. *Wiedmann, F., + , T-IM Apr 97* 527-530
slot antennas meas., input impedance and radiation pattern. *Roy, L., + , T-IM Aug 97* 1000-1004
Gamma-ray detectors
paper basis-wt./ash-content meas., nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940
Gamma-ray spectroscopy
Avogadro project, Si crysts. isotopic anal. *Rottger, S., + , T-IM Apr 97* 560-562
Gas detectors
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
Gas discharges
voltage transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921
Gases; cf. Hydrogen
Gas insulated substations
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
Gas lasers
Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
He-Ne and He-Ne/I$_2$ lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
He-Ne laser, ^{127}I$_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
He-Ne, wavelength ratio meas., fringe counting sigmameter. *Juncar, P.P., + , T-IM Jun 97* 690-695
Gas lasers; cf. Carbon dioxide lasers
Gaussian beams
dielec. props. meas. at mm-wavelength, free-space. *Friedsam, G.L., + , T-IM Apr 97* 515-518
Gaussian distributions
dither-based quantizing systs. design. *Carbone, P., T-IM Jun 97* 656-659
Gaussian processes
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841
Geometric modeling
3D meas. using video camera and range finder. *Chavand, F., + , T-IM Dec 97* 1229-1235
Geophysical signal processing
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841
Germanium alloys
AuGeNi contacts, precision quantized Hall devices fab. *Inglis, A.D., + , T-IM Apr 97* 281-284
Gold alloys
AuGeNi contacts, precision quantized Hall devices fab. *Inglis, A.D., + , T-IM Apr 97* 281-284
Gradient methods; cf. Backpropagation; Least mean square methods
Graphical user interfaces
multimegohm std. resistors calib., automated guarded bridge. *Jarrett, D.G., T-IM Apr 97* 325-328
Gratings
fiber optic grating-based devices, temp. compensation. *Arya, V., + , T-IM Oct 97* 1173-1177
Gunn device oscillators
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
Gyromagnetism
He-4 atom gyromagnetic ratio, expt. determ. *Shifrin, V.Y., + , T-IM Apr 97* 97-100

H

Hall effect
AC QHE-based calib. of resist. stds. *Bohacek, J., + , T-IM Apr 97* 273-275
AC quantized Hall resist. eval. *Wood, H.M., + , T-IM Apr 97* 269-272
AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
bifilar AC-DC resistor, microwire. *Semyonov, Yu.P., + , T-IM Apr 97* 333-336
externally shielded cryogenic current comparator, sensitivity meas., QHR bridges. *Early, M.D., + , T-IM Apr 97* 459-462
four-terminal quantized Hall resist. in nonlin. regime. *Jeckelmann, B., + , T-IM Apr 97* 276-280
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
IEN primary group of std. resistors, working temp. *Boella, G., + , T-IM Apr 97* 311-313
NPL moving-coil apparatus, Planck’s const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
ohm realization, quantized Hall resist. vs calculable capacitor. *Jeffery, A.-M., + , T-IM Apr 97* 264-268
Hall effect devices
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
Si analog Hall probe, magnetometry, vert. Hall devices. *Schott, C., + , T-IM Apr 97* 613-616
Halogens; cf. Iodine
Harmonic analysis
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816
three-phase digital recorder syst. for calib. power instrumentation. *Arseneau, R., + , T-IM Apr 97* 399-402
Harmonic distortion
multiple digital sig. generators, noise-adaptive digital null detector. *Tarach, D., + , T-IM Apr 97* 435-438
sinewave fitting procedure for data acquisition channels characterization. *Schoukens, J., + , T-IM Aug 97* 1005-1010
Helium
He-Ne and He-Ne/I$_2$ lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
He-Ne laser, H two-photon reson. meas. *Udem, T., + , T-IM Apr 97* 166-168
He-Ne laser, precision freq. meas., Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
He-Ne laser, ^{127}I$_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
wavelength ratio meas., fringe counting sigmameter. *Juncar, P.P., + , T-IM Jun 97* 690-695
Heterojunction bipolar transistors
GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
Heterojunctions; cf. Semiconductor heterojunctions
High-temperature superconductors
DC SQUID-based magnetometer, direct-coupled electronics. *Gudoshnikov, S.A., + , T-IM Apr 97* 624-628
Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252
superconductive cylinder cracks eval. by impedance meas. *Yamazaki, S., + , T-IM Aug 97* 873-876
thin films, microwave surface resist., calorimetric meas. *Andreone, D., + , T-IM Apr 97* 535-538
YBCO resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
High-temperature techniques
current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038

High-voltage techniques
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
Hilbert transforms
bandlimited fn. reconstruction, Hilbert transform, EM fields. *Boche, H., + , T-IM Apr 97* 442-444
multiple-target FM CW ranging by eval. of impulse response phase. *Stolle, R., + , T-IM Apr 97* 426-429
Horn antennas
dielec. props. meas. at mm-wavelength, free-space. *Friedsam, G.L., + , T-IM Apr 97* 515-518
Hybrid integrated circuits
Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
Hydrogen
absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168

I

Identification
LTI systs., nonstandard conditions, freq.-domain ident. *Pintelon, R., + , T-IM Feb 97* 65-71
nonlin. delay elements determ., NARMA models, using dispersion fns. *Ho-En Liao, + , T-IM Aug 97* 868-872
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
Identification; cf. Parameter estimation
IEEE publications
spec. for common IEEE styles. *Plett, G.L., + , T-IM Dec 97* 1217-1223
IEEE standards
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
IIR digital filters
predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
Image analysis; cf. Image color analysis
Image classification
fiber optic sens. for surface roughness/displacement meas. *Zhang, K., + , T-IM Aug 97* 899-902
Image coding
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797
Image color analysis
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797
Image processing; cf. Biomedical image processing; Image classification; Image coding; Image reconstruction; Image resolution; Image restoration; Video signal processing
Image reconstruction
electron wave reconstruction, param. estim. *vand den Bos, A., T-IM Aug 97* 826-830
Image resolution
model based opt. resoln. *den Dekker, A.J., T-IM Aug 97* 798-802
Image restoration
model based opt. resoln. *den Dekker, A.J., T-IM Aug 97* 798-802
Image sensors
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
Imaging; cf. Radar imaging
Impedance matching
mismatch factor determ., RF power calib. *Stumper, U., T-IM Apr 97* 531-534
Impedance measurement
digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043
LV stds., 10 Hz, 1 MHz range. *Oldham, N.M., + , T-IM Apr 97* 395-398
mismatch factor determ., RF power calib. *Stumper, U., T-IM Apr 97* 531-534
multistate microwave radiometer, impedance and noise temp. meas. *Wiatr, W., + , T-IM Apr 97* 486-489
noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
slot antennas meas., input impedance and radiation pattern. *Roy, L., + , T-IM Aug 97* 1000-1004
superconductive cylinder cracks eval. by impedance meas. *Yamazaki, S., + , T-IM Aug 97* 873-876
Inductance
voltage divider, ac-power meas., in-phase errors. *Zinkernagel, J., T-IM Oct 97* 1075-1080
Inductors
mutual inductance independent of primary winding posn. and ambient fields. *Miljanic, P.N., T-IM Apr 97* 471-473
Industries; cf. Petroleum industry; Pulp and paper industry; Textile industry
Information theory
meas. IS, general meas. problem representation. *Muravyov, S.V., + , T-IM Aug 97* 961-965
Information theory; cf. Encoding
Infrared detectors
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
Infrared measurements; cf. Infrared spectroscopy
Infrared radiation effects
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
Infrared spectroscopy
CO_2/OsO_4 lasers as freq. stds., 29 THz range. *Acef, O., T-IM Apr 97* 162-165
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
Infrared transmission; cf. Optical communication
Instrument transformers; cf. Current transformers; Voltage transformers
Integral equations
calib. sigs. dyn. accuracy, integral-sq.-error. *Layer, E., T-IM Oct 97* 1178-1182
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
Integrated circuit metallization
PC based ultralow-noise meas. *Ciofi, C., + , T-IM Aug 97* 789-793
Integrated circuits; cf. Analog integrated circuits; Application specific integrated circuits; Bipolar integrated circuits; CMOS integrated circuits; Hybrid integrated circuits; Monolithic integrated circuits; Very-large-scale integration
Integrated circuit testing
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
interpolating time counter, single-chip, 200-ps resoln. *Kalisz, J., + , T-IM Aug 97* 851-856
simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304
Intelligent sensors
2D noniterative polynomial calib., microcontroller based syst. *Lyahou, K.F., + , T-IM Aug 97* 752-757
capacitive ang.-posn. sens., self-calib. *Li, X., + , T-IM Aug 97* 888-892
light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936
resistive bridge sens., bitstream output. *Fasoli, L.G., + , T-IM Aug 97* 954-960
Intelligent systems
measuring instrums. as agents, future prospects. *Dobrowiecki, T.P., + , T-IM Aug 97* 991-995
Interference; cf. Echo interference; Electromagnetic interference
Interference suppression
FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
Interferometry
scanning X-ray interf. over mm baseline, Si (220) lattice spacing meas. *Bergamin, A., + , T-IM Apr 97* 576-579
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
Si, lattice spacing d(220), X-ray/opt. interferometry meas. *Nakayama, K., + , T-IM Apr 97* 580-583
X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200
Interferometry; cf. Optical interferometry
Interpolation
time counter, single-chip, 200-ps resoln. *Kalisz, J., + , T-IM Aug 97* 851-856

Interpolation; cf. Spline functions

Inverse problems; cf. Deconvolution; Image reconstruction

Iodine
- Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
- Doppler-free freq. stabilized extended cavity diode laser. *Simonsen, H.R., T-IM Apr 97* 141-144
- He-Ne/I$_2$ lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
- intracavity saturation spectrosc., extended-cavity LD. *Zarka, A., + , T-IM Apr 97* 145-148
- precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
- ^{127}I$_2$ stabilized He-Ne laser, freq. shifts, higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190

Ion beams
- Ar$^+$ ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591

Ions
- ^{113}Cd$^+$ trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140

Ion sources
- Ar$^+$ ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591

Iron alloys
- FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635

Iron alloys; cf. Steel

ISDN; cf. SONET

Iterative methods
- bandlimited fn. reconstruction, Hilbert transform, EM fields. *Boche, H., + , T-IM Apr 97* 442-444
- reconstruction of digital spectrum from nonuniformly sampled sigs. *Yih-Chyun Jenq, T-IM Jun 97* 649-652
- spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
- spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684

J

Jitter
- direct digital synthesizer, jittered clock. *Yih-Chyun Jenq, T-IM Jun 97* 653-655

Jitter; cf. Phase jitter; Timing jitter

Josephson arrays
- 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
- AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
- Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252
- Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
- Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263
- Josephson-jn. array voltage std., step no. determ. *Ogita, E., + , T-IM Apr 97* 253-255
- Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
- mobile cryocooled primary voltage std. without liq. He. *Yi-Hua Tang, + , T-IM Apr 97* 256-259
- Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
- voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
- voltage stds. of SP and BIPM, comparison. *Reymann, D., + , T-IM Apr 97* 220-223
- Zener voltage std. calib. at 10 V, KRISS vs ETL. *Kyu-Tae Kim, + , T-IM Apr 97* 314-317

Josephson device fabrication
- voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232

Josephson device measurement applications
- AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
- array, 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
- array voltage stds. of SP and BIPM, comparison. *Reymann, D., + , T-IM Apr 97* 220-223
- Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
- NPL moving-coil apparatus, Planck's const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
- voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232

Josephson device noise
- tunneling electrometer, single Cooper pair type, sensitivity. *Zorin, A.B., T-IM Apr 97* 299-302

Josephson devices
- tunneling electrometer, single Cooper pair type, sensitivity. *Zorin, A.B., T-IM Apr 97* 299-302

Josephson devices; cf. Josephson logic; Josephson mixers; SQUIDs

Josephson effect
- NPL moving-coil apparatus, Planck's const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
- transportable compact Josephson voltage std. *Hamilton, C.A., + , T-IM Apr 97* 237-241

Josephson junctions
- Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78

Josephson logic
- Nb/Al$_2$O$_3$-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481

Josephson mixers
- Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252

K

Kalman filtering
- freq. estim., drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
- Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
- spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684
- spectrophotometric data correction, Kalman-filter, use of splines. *Slima, M.B., + , T-IM Jun 97* 685-689

Knowledge based systems; cf. Expert systems

L

Large-scale integration; cf. Very-large-scale integration

Laser absorbers
- He-Ne laser, ^{127}I$_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
- OsO$_4$ saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177

Laser accessories; cf. Laser absorbers; Laser resonators

Laser applications
- Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
- He-Ne and He-Ne/I$_2$ lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
- Sr$^+$ ion based freq. std. develop. *Barwood, G.P., + , T-IM Apr 97* 133-136
- ^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129

Laser applications; cf. Laser measurement applications

Laser beams
- X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200

Laser excitation; cf. Optical pumping

Laser measurement applications
- absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168
- crosstalk anal. of 1 m to 10 m laser phase-shift range finder. *Bosch, T., + , T-IM Dec 97* 1224-1228
- CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
- displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
- precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
- TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999

Laser measurement applications; cf. Laser radar

Laser measurements
- extended cavity diode laser, I$_2$-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
- extended-cavity LD stabilized on I$_2$, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
- He-Ne laser, ^{127}I$_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190

wavelength ratio meas., fringe counting sigmameter. *Juncar, P.P., + , T-IM Jun 97* 690-695
Laser modes
He-Ne and He-Ne/I_2 lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
Laser noise
^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
Laser radar
TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999
Laser resonators
extended cavity diode laser, I_2-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
extended-cavity LD stabilized on I_2, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
Lasers; cf. CW lasers; Feedback lasers; Gas lasers; Pulsed lasers; Semiconductor lasers
Laser stability
Ar^+ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
CO_2/OsO_4 lasers as freq. stds., 29 THz range. *Acef, O., T-IM Apr 97* 162-165
extended cavity diode laser, I_2-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
extended-cavity LD stabilized on I_2, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
He-Ne and He-Ne/I_2 lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
He-Ne laser, $^{127}I_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
OsO_4 saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177
precision freq. meas., diode laser locked Sr^+ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
std., ^{87}Rb D_2-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161
ultrastable opt. freq. ref., 1.064 μm. *Jun Ye, + , T-IM Apr 97* 178-182
Laser tuning
extended cavity diode laser, I_2-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
extended-cavity LD stabilized on I_2, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
Lead compounds
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
Leakage currents
series-resistors-type voltage divider, common error sources. *Kyu-Tae Kim, + , T-IM Aug 97* 776-780
Leak detection; cf. Liquid leak detection
Learning systems
FPGA integrated time-to-digital converter, direct coding, nonlin. correction. *Pelka, R., + , T-IM Apr 97* 449-453
Learning systems; cf. Backpropagation; Neural networks
Least mean square methods
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
Least mean square methods; cf. Backpropagation
Least squares methods
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
freq. estim., drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
Level measurement
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646
num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246
Levitation; cf. Magnetic levitation
Linear algebra; cf. Matrices
Linear approximation
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
Schottky detector diodes for six-port reflectometers. *Hesselbarth, J., + , T-IM Aug 97* 966-969
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757
Linear circuits
HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043
Linear systems
time-invariant systs., nonstandard conditions, freq.-domain ident. *Pintelon, R., + , T-IM Feb 97* 65-71
Liquid crystal devices
fiber optic elec. field probe, liq. crysts. *Lacquet, B.M., + , T-IM Feb 97* 31-35
Liquid crystals
fiber optic elec. field probe, liq. crysts. *Lacquet, B.M., + , T-IM Feb 97* 31-35
Liquid leak detection
liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646
Liquids; cf. Conducting liquids; Liquid crystals; Magnetic liquids; Water
Lithography; cf. Photolithography
Logic arrays
metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
Logic circuits; cf. CMOSFET logic devices; Current mode logic; Logic arrays
Logic circuit testing
current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671
Logic design
current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671
Logic devices; cf. Josephson logic
Losses
low-uncertainty dipole/monopole std. antennas, insertion loss, antenna factors. *Alexander, M.J., + , T-IM Apr 97* 539-543
Losses; cf. Attenuation; Dielectric losses; Power transformer losses
Loss measurement
permitt. meas. of rice weevils, RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946
Luminescent devices; cf. Scintillation detectors

M

Machine vision
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
Machine vision; cf. Robot vision systems
Machining; cf. Micromachining
Magnetic cores; cf. Saturable cores
Magnetic devices
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50
Magnetic devices; cf. Magnetic transducers; Magnetostrictive devices
Magnetic field effects; cf. Cyclotron radiation; Magnetic levitation
Magnetic field measurement
ferrofluid fluxgate sens. magnetometer, dc mag. field intens. meas. *Baltag, O., + , T-IM Apr 97* 629-631
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635
HTSC DC SQUID-based magnetometer, direct-coupled electronics. *Gudoshnikov, S.A., + , T-IM Apr 97* 624-628
LF mag. EMC meas., fluxgate magnetometer. *Weyand, K., + , T-IM Apr 97* 617-620
SQUID magnetometer sens., 3D positioning setup. *Willenberg, G.-D., + , T-IM Apr 97* 621-623
Magnetic levitation
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50
supercond. mag. levitation syst., buoyancy-free mass comparator. *Fujii, Y., + , T-IM Apr 97* 609-612
Magnetic liquids
ferrofluid fluxgate sens. magnetometer, dc mag. field intens. meas. *Baltag, O., + , T-IM Apr 97* 629-631
Magnetic materials; cf. Ferromagnetic materials; Magnetic liquids
Magnetic resonance; cf. Nuclear magnetic resonance; Paramagnetic resonance
Magnetic shielding
mutual inductance independent of primary winding posn. and ambient fields. *Miljanic, P.N., T-IM Apr 97* 471-473
superconductive cylinder cracks eval. by impedance meas. *Yamazaki, S., + , T-IM Aug 97* 873-876

Magnetic transducers
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635
Magnetic transducers; cf. Magnetometers
Magnetic variables measurement; cf. Magnetic field measurement; Permeability measurement
Magnetoelasticity
transducer for torque and force meas. *Zakrzewski, J., T-IM Aug 97* 807-810
Magnetoelectric effects; cf. Hall effect
Magnetomechanical effects; cf. Magnetoelasticity
Magnetometers
ferrofluid fluxgate sens. magnetometer, dc mag. field intens. meas. *Baltag, O., + , T-IM Apr 97* 629-631
He-4 atom gyromagnetic ratio, expt. determ. *Shifrin, V.Y., + , T-IM Apr 97* 97-100
LF mag. EMC meas., fluxgate magnetometer. *Weyand, K., + , T-IM Apr 97* 617-620
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
Si analog Hall probe, magnetometry, vert. Hall devices. *Schott, C., + , T-IM Apr 97* 613-616
Magnetometers; cf. SQUID magnetometers
Magnetostrictive devices
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635
Mass spectroscopy
Ar^+ ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591
Si molar mass meas. for better Avogadro const. *Gonfiantini, R., + , T-IM Apr 97* 566-571
Materials processing; cf. Etching
Materials testing; cf. Nondestructive testing
Mathematics; cf. Numerical analysis; Optimization methods
Matrices
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
Maximum likelihood estimation
electron wave reconstruction, param. estim. *vand den Bos, A., T-IM Aug 97* 826-830
Measurement
expert agents appls. of measuring instrums., future prospects. *Dobrowiecki, T.P., + , T-IM Aug 97* 991-995
parametric optim., joint error criterion. *Gajda, J., + , T-IM Aug 97* 769-775
representational theory, meas. IS approach. *Muravyov, S.V., + , T-IM Aug 97* 961-965
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
selected papers CPEM'96 (special issue intro.). *Cook, R.J., T-IM Apr 97* 95-96
Measurement; cf. Acoustic measurements; Antenna measurements; Atomic measurements; Biomedical measurements; Digital measurements; Electric variables measurement; Electromagnetic measurements; Frequency measurement; Josephson device measurement applications; Laser measurement applications; Laser measurements; Loss measurement; Mechanical variables measurement; Moisture measurement; Noise measurement; Nuclear measurements; Optical fiber measurements; Optical variables measurement; Particle beam measurements; Phase measurement; Pollution measurement; Power system measurements; Radar measurements; Reflectometry; Remote sensing; Scattering parameters measurement; Sea measurements; Semiconductor device measurements; Semiconductor materials measurements; Soil measurements; Spectroscopy; Superconducting device measurements; Thermal variables measurement; Time domain measurements; Time measurement; Wavelength measurement; X-ray measurements
Measurement errors
AC-DC voltage transfer stds., lowest uncertainty level, CCE comparison. *Klonz, M., T-IM Apr 97* 342-346
AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
alternating voltage meas., ac-dc transfer stds., micropotentiometer-based calib. *Budovsky, I., T-IM Apr 97* 356-360
calculable HF AC-DC transfer std. *Van Mullem, C., + , T-IM Apr 97* 361-364
calib. sigs. dyn. accuracy, integral-sq.-error. *Layer, E., T-IM Oct 97* 1178-1182
capacitance scaling syst., four-terminal-pair LCR meter, inductive voltage divider. *Aoki, T., + , T-IM Apr 97* 474-476
digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
digital meas. systs., quantization error predetermination. *Vujicic, V.V., + , T-IM Apr 97* 439-441
false-bal.-avoidance transductor for measuring large DC currents. *Ken Xu, + , T-IM Oct 97* 1081-1083
FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
freq. std., relativistic rate shift. *Petit, G., + , T-IM Apr 97* 201-204
inductive voltage divider, ac-power meas., in-phase errors. *Zinkernagel, J., T-IM Oct 97* 1075-1080
Josephson-array voltage stds. of SP and BIPM, comparison. *Reymann, D., + , T-IM Apr 97* 220-223
Josephson jn. array, 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
Josephson-jn. array voltage std., step no. determ. *Ogita, E., + , T-IM Apr 97* 253-255
liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646
mm-wave power stds., isothermal calorimeter power meters. *Akhiezer, A.N., + , T-IM Apr 97* 495-498
multiple digital sig. generators, noise-adaptive digital null detector. *Tarach, D., + , T-IM Apr 97* 435-438
multistage clamp-on CT, ratio errors, low current meas. *So, E., + , T-IM Apr 97* 454-458
NIST amp. noise meas., noise-fig. meas. service. *Wait, D.F., + , T-IM Apr 97* 482-485
NIST watt bal., kilogram monitoring, meas. uncertainties. *Steiner, R.L., + , T-IM Apr 97* 601-604
NIST watt expt., alignment uncertainties. *Gillespie, + , T-IM Apr 97* 605-608
NPL moving-coil apparatus, Planck's const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
ohm realization, quantized Hall resist. vs calculable capacitor. *Jeffery, A.-M., + , T-IM Apr 97* 264-268
on-wafer microwave meas., NWA self-calib. methods. *Heuermann, H., + , T-IM Oct 97* 1105-1110
open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099
parametric optim., joint error criterion. *Gajda, J., + , T-IM Aug 97* 769-775
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
power measuring stds., automatic zero-PF/sampling wattmeter std. *Simonson, P., + , T-IM Apr 97* 423-425
refractometer, vac. cell/double-pass Michelson interferometer, air refr. index meas. *Fujii, K., + , T-IM Apr 97* 191-195
series-resistors-type voltage divider, common error sources. *Kyu-Tae Kim, + , T-IM Aug 97* 776-780
Si analog Hall probe, magnetometry, vert. Hall devices. *Schott, C., + , T-IM Apr 97* 613-616
Si fine struct. const. determ. *Kruger, E., + , T-IM Apr 97* 101-103
Si, lattice spacing d(220), X-ray/opt. interferometry meas. *Nakayama, K., + , T-IM Apr 97* 580-583
Si molar mass meas. for better Avogadro const. *Gonfiantini, R., + , T-IM Apr 97* 566-571
Si, molar vol. rel., Avogadro const. determ. *De Bievre, P., + , T-IM Apr 97* 592-595
smart capacitive ang.-posn. sens., self-calib. *Li, X., + , T-IM Aug 97* 888-892
spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928
sq.-rooting voltage-to-freq. converter. *Trofimenkoff, F.N., + , T-IM Oct 97* 1208-1211
supercond. mag. levitation syst., buoyancy-free mass comparator. *Fujii, Y., + , T-IM Apr 97* 609-612
thermal wattmeter, power comparator, ac power meas. *Laiz, H., + , T-IM Apr 97* 420-422
time-division watt-converter,frequency depend. systematic error, compensation. *Jovanovic, L.D., T-IM Apr 97* 416-419
voltage source eval., calculable RMS outputs. *Lapuh, R., + , T-IM Aug 97* 784-788
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200
Measurement standards
absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168
AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
AC QHE-based calib. of resist. stds. *Bohacek, J., + , T-IM Apr 97* 273-275
AC quantized Hall resist. eval. *Wood, H.M., + , T-IM Apr 97* 269-272

act. HV divider with 20 µV/V uncertainty, compressed-gas capacitor. *Petersons, O., + , T-IM Apr 97* 430-434
air refr. index meas., vac. cell/double-pass Michelson interferometer refractometer. *Fujii, K., + , T-IM Apr 97* 191-195
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
capacitance-based displacement meas., AC current source, input shielding. *Nerino, R., + , T-IM Apr 97* 640-643
capacitance scaling syst., four-terminal-pair LCR meter, inductive voltage divider. *Aoki, T., + , T-IM Apr 97* 474-476
clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
CO$_2$/OsO$_4$ lasers as freq. stds., 29 THz range. *Acef, O., T-IM Apr 97* 162-165
Cs beam freq. stds., Ramsey pattern anal. *Makdissi, A., + , T-IM Apr 97* 112-116
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
dipole antenna factor calib., primary stds., site atten. meas. *Garn, H., + , T-IM Apr 97* 544-548
employing calculable four-electrode conductance cell to substitute for secondary standards of electrolytic conductivity. *Moron, Z., + , T-IM Dec 97* 1268-1273
extended cavity diode laser, I$_2$-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
extended-cavity LD stabilized on I$_2$, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
fine-struct. const., electron g-2 calc. improvement. *Kinoshita, T., T-IM Apr 97* 108-111
freq. std., relativistic rate shift. *Petit, G., + , T-IM Apr 97* 201-204
freq. std., ^{87}Rb D$_2$-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
He-Ne laser, ^{127}I$_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
high-T$_c$ resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
IEN primary group of std. resistors, working temp. *Boella, G., + , T-IM Apr 97* 311-313
Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
Josephson-array voltage stds. of SP and BIPM, comparison. *Reymann, D., + , T-IM Apr 97* 220-223
Josephson jn. array, 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263
Josephson-jn. array voltage std., step no. determ. *Ogita, E., + , T-IM Apr 97* 253-255
Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
K- and Ka-band waveguide microcalorimeters for microwave power standards. *Kang, T.W., + , T-IM Dec 97* 1247-1250
loading effects in resist. scaling. *Elmquist, R.E., + , T-IM Apr 97* 322-324
LV stds., 10 Hz, 1 MHz range. *Oldham, N.M., + , T-IM Apr 97* 395-398
mismatch factor determ., RF power calib. *Stumper, U., T-IM Apr 97* 531-534
mm-wave power stds., isothermal calorimeter power meters. *Akhiezer, A.N., + , T-IM Apr 97* 495-498
mobile cryocooled primary voltage std. without liq. He. *Yi-Hua Tang, + , T-IM Apr 97* 256-259
multiconverter modules, thin-film multijunction thermal converters. *Kinard, J.R., + , T-IM Apr 97* 391-394
multimegohm std. resistors calib., automated guarded bridge. *Jarrett, D.G., T-IM Apr 97* 325-328
Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
Nb/Al$_2$O$_3$-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481
NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
NIST thin-film multijunction thermal converters, micropotentiometers. *Kinard, J.R., + , T-IM Apr 97* 347-351
NIST watt bal., kilogram monitoring, meas. uncertainties. *Steiner, R.L., + , T-IM Apr 97* 601-604
NIST watt expt., alignment uncertainties. *Gillespie, + , T-IM Apr 97* 605-608
NPL moving-coil apparatus, Planck's const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
ohm realization, quantized Hall resist. vs calculable capacitor. *Jeffery, A.-M., + , T-IM Apr 97* 264-268
OsO$_4$ saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177
power measuring stds., automatic zero-PF/sampling wattmeter std. *Simonson, P., + , T-IM Apr 97* 423-425
precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
Ramsey lineshapes anal., vel. distrib. calc. by FT. *Shirley, J.H., T-IM Apr 97* 117-121
ref. accel. generation for accelerometer calib. *Marioli, D., + , T-IM Feb 97* 27-30
resist. bridges accuracy verification. *White, D.R., + , T-IM Apr 97* 329-332
RF-DC differences of micropotentiometers. *De Xiang Huang, + , T-IM Apr 97* 337-341
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
selected papers CPEM'96 (special issue intro.). *Cook, R.J., T-IM Apr 97* 95-96
seven-jn. electron pump, design, fab., and operation. *Keller, M.W., + , T-IM Apr 97* 307-310
Si dens. stds., internat. intercomparison. *Bettin, H., + , T-IM Apr 97* 556-559
Si fine struct. const. determ. *Kruger, E., + , T-IM Apr 97* 101-103
Si samples intercomparison from Avogadro projects. *Kessler, E.G., Jr., + , T-IM Apr 97* 551-555
Si spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587
Sr$^+$ ion based freq. std. develop. *Barwood, G.P., + , T-IM Apr 97* 133-136
^{113}Cd$^+$ trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140
^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
supercond. mag. levitation syst., buoyancy-free mass comparator. *Fujii, Y., + , T-IM Apr 97* 609-612
thermal voltage converters, LF perform., cct. models. *Oldham, N.M., + , T-IM Apr 97* 352-355
ultrastable opt. freq. ref., 1.064 µm. *Jun Ye, + , T-IM Apr 97* 178-182
Zener voltage std. calib. at 10 V, KRISS vs ETL. *Kyu-Tae Kim, + , T-IM Apr 97* 314-317

Measurement standards; cf. Transfer standards

Measurement system data handling
Avogadro project, Si crysts. isotopic anal. *Rottger, S., + , T-IM Apr 97* 560-562
correction to "comments on 'The modulo time plot: A useful data acquisition diagnostic tool'" (Dec 96 959). *Papay, Z., T-IM Jun 97* 739
electron wave reconstruction, param. estim. *vand den Bos, A., T-IM Aug 97* 826-830
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
p-n jn. devices deep-level charactn. *Nubile, P., T-IM Oct 97* 1156-1159
Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
Ramsey lineshapes anal., vel. distrib. calc. by FT. *Shirley, J.H., T-IM Apr 97* 117-121
reconstruction of digital spectrum from nonuniformly sampled sigs. *Yih-Chyun Jenq, T-IM Jun 97* 649-652
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928
spectrophotometric data correction, Kalman-filter, use of splines. *Slima, M.B., + , T-IM Jun 97* 685-689
time-resolved spectra global anal., param. precision. *van Stokkum, I.H.M., T-IM Aug 97* 764-768

transportable compact Josephson voltage std. *Hamilton, C.A., + , T-IM Apr 97* 237-241
Measurement units
AC quantized Hall resist. eval. *Wood, H.M., + , T-IM Apr 97* 269-272
four-terminal quantized Hall resist. in nonlin. regime. *Jeckelmann, B., + , T-IM Apr 97* 276-280
NIST watt bal., kilogram monitoring, meas. uncertainties. *Steiner, R.L., + , T-IM Apr 97* 601-604
NIST watt expt., alignment uncertainties. *Gillespie, + , T-IM Apr 97* 605-608
NPL moving-coil apparatus, Planck's const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
ohm realization, quantized Hall resist. vs calculable capacitor. *Jeffery, A.-M., + , T-IM Apr 97* 264-268
Mechanical factors
Si sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575
Mechanical factors; cf. Semiconductor device mechanical factors; Superconducting magnet mechanical factors
Mechanical variables control; cf. Attitude control; Position control
Mechanical variables measurement; cf. Acceleration measurement; Density measurement; Displacement measurement; Fluid flow measurement; Force measurement; Level measurement; Position measurement; Pressure measurement; Shape measurement; Size measurement; Strain measurement; Thickness measurement; Torque measurement; Velocity measurement; Vibration measurement; Volume measurement; Weight measurement
MESFET oscillators
Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
MESFETs; cf. Power MESFETs
Metallization; cf. Integrated circuit metallization
Metals; cf. Aluminum; Cadmium; Cesium; Rubidium; Silicon
Microcomputer applications
calib. of power transducers, PC-based adaptive software. *Chern-Lin Chen, + , T-IM Oct 97* 1145-1149
chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
paper basis-wt./ash-content meas., nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940
voltage source eval., calculable RMS outputs. *Lapuh, R., + , T-IM Aug 97* 784-788
Microcontrollers
liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646
low-speed meas., multiple-electrode capacitive sens. *Xianjun Li, + , T-IM Apr 97* 636-639
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757
Microelectromechanical devices
2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
Microelectromechanical devices; cf. Microsensors
Micromachining
2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
Microprocessor applications
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816
smart capacitive ang.-posn. sens., self-calib. *Li, X., + , T-IM Aug 97* 888-892
spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684
Microprocessors; cf. Digital signal processors; Microcontrollers
Microscopy; cf. Electron microscopy
Microsensors
NIST thin-film multijunction thermal converters, micropotentiometers. *Kinard, J.R., + , T-IM Apr 97* 347-351
Microwave amplifiers
NIST amp. noise meas., noise-fig. meas. service. *Wait, D.F., + , T-IM Apr 97* 482-485
Microwave antennas
dielec. props. meas. at mm-wavelength, free-space. *Friedsam, G.L., + , T-IM Apr 97* 515-518
Microwave circuits; cf. Microwave amplifiers; Microwave filters; Microwave oscillators
Microwave devices; cf. Microwave antennas; Microwave resonators; Superconducting microwave devices
Microwave FETs
low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494
noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048
Microwave filters
atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
Microwave generation
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
Microwave generation; cf. Microwave oscillators
Microwave integrated circuits; cf. MMICs
Microwave measurements
dielec. meas. using coaxial resonator, L-band automated syst. *Galwas, B.A., + , T-IM Apr 97* 511-514
high-T_c resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
K- and Ka-band waveguide microcalorimeters for microwave power standards. *Kang, T.W., + , T-IM Dec 97* 1247-1250
microwave low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494
NIST amp. noise meas., noise-fig. meas. service. *Wait, D.F., + , T-IM Apr 97* 482-485
noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048
NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
on-wafer microwave meas., NWA self-calib. methods. *Heuermann, H., + , T-IM Oct 97* 1105-1110
open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099
permittivities meas. of rice weevils. *Nelson, S.O., + , T-IM Aug 97* 941-946
precision microwave testing of dielec. substrs. *Yushchenko, A.G., + , T-IM Apr 97* 507-510
pulse meas., resistive sens. *Dagys, M., + , T-IM Apr 97* 499-502
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
supercond. thin-films, microwave surface resist., calorimetric meas. *Andreone, D., + , T-IM Apr 97* 535-538
transportable compact Josephson voltage std. *Hamilton, C.A., + , T-IM Apr 97* 237-241
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
Microwave measurements; cf. Microwave radiometry; Microwave reflectometry
Microwave oscillators
Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
Microwave radiometry
mismatch factor determ., RF power calib. *Stumper, U., T-IM Apr 97* 531-534
multistate microwave radiometer, impedance and noise temp. meas. *Wiatr, W., + , T-IM Apr 97* 486-489
multistate radiometry, noise de-embedding/un-terminating. *Wiatr, W., T-IM Apr 97* 503-506
Microwave reflectometry
double six-port reflectometer, on-wafer calib., absol. power meas. *Berghoff, G., + , T-IM Oct 97* 1111-1114
dual six-port automatic NWA, calib. *Ginley, R.A., T-IM Apr 97* 523-526
dual six-port NWA calib. *Krekels, H.-G., + , T-IM Oct 97* 1115-1119
semicond. waveguides meas., dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721
six-port reflectometer in MMIC technol. *Wiedmann, F., + , T-IM Apr 97* 527-530
six-port reflectometers, large bandwidths. *Hesselbarth, J., + , T-IM Aug 97* 966-969
Microwave resonators
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
Microwave transistors; cf. Microwave FETs
Millimeter wave circuits
Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232

Millimeter wave circuits; cf. Millimeter wave mixers

Millimeter wave devices
- Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263

Millimeter wave frequency conversion; cf. Millimeter wave mixers

Millimeter wave measurements
- dielec. props. meas. at mm-wavelength, free-space. *Friedsam, G.L., + , T-IM Apr 97* 515-518
- Nb/Al-AlO_x/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
- power stds., isothermal calorimeter power meters. *Akhiezer, A.N., + , T-IM Apr 97* 495-498

Millimeter wave mixers
- Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252

Minimization methods
- predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
- sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030

Mixed analog-digital integrated circuits
- autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
- simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304

Mixers; cf. Josephson mixers; Millimeter wave mixers; Optical mixers

MMICs
- NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
- six-port reflectometer in MMIC technol. *Wiedmann, F., + , T-IM Apr 97* 527-530
- slot antennas meas., input impedance and radiation pattern. *Roy, L., + , T-IM Aug 97* 1000-1004

Mobile robots
- position estim. of mobile robots based on coded IR sig. transm. *Eren, H., + , T-IM Dec 97* 1280-1283

Modeling; cf. Circuit modeling; Data models; Geometric modeling; Semiconductor device modeling

Mode locked lasers
- Ar^+ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
- extended-cavity LD stabilized on I_2, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
- Sr^+ ion based freq. std. develop. *Barwood, G.P., + , T-IM Apr 97* 133-136

MODFETs
- microwave low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494

Modular computer systems
- modular ANN for prediction of petrophysical props. from well log data. *Fung, C.C., + , T-IM Dec 97* 1295-1299

Modulation
- two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208

Modulation; cf. Frequency modulation; Optical modulation; Phase modulation; Pulse width modulation

Moisture measurement
- open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099

Moment methods; cf. Galerkin method

Monitoring
- irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990

Monolithic integrated circuits
- light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936

Monolithic integrated circuits; cf. MMICs

Monopole antennas
- low-uncertainty dipole/monopole std. antennas, insertion loss, antenna factors. *Alexander, M.J., + , T-IM Apr 97* 539-543

Monte Carlo methods
- Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195

MOS analog integrated circuits
- current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671

MOSFET logic devices; cf. CMOSFET logic devices

MOS integrated circuits; cf. CMOS integrated circuits; MOS analog integrated circuits

Moving average processes; cf. Autoregressive moving average processes

Multidimensional coding
- multiplexed large-scale opt. fiber sens. arrays, 2D encoding. *Yiqun Hu, + , T-IM Oct 97* 1160-1164

Multilayer perceptrons
- FPGA integrated time-to-digital converter, direct coding, nonlin. correction. *Pelka, R., + , T-IM Apr 97* 449-453

Multiplexing
- nonlinearity of data-acquisition syst. with interleaving/multiplexing. *Simoes, J.B., + , T-IM Dec 97* 1274-1279
- opt. fiber sens. arrays, 2D encoding. *Yiqun Hu, + , T-IM Oct 97* 1160-1164

Multiport circuits
- HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043

Multiport circuits; cf. Two-port circuits

Multiprocessing; cf. Neural networks

Multisensor systems
- multiplexed large-scale opt. fiber sens. arrays, 2D encoding. *Yiqun Hu, + , T-IM Oct 97* 1160-1164

Mutual coupling; cf. Coupled transmission lines

N

Nanotechnology
- scanning X-ray interf. over mm baseline, Si (220) lattice spacing meas. *Bergamin, A., + , T-IM Apr 97* 576-579

Navigation; cf. Sonar navigation

Neodymium:YAG lasers
- ultrastable opt. freq. ref., 1.064 µm. *Jun Ye, + , T-IM Apr 97* 178-182

Neon
- He-Ne and He-Ne/I_2 lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
- He-Ne laser, H two-photon reson. meas. *Udem, T., + , T-IM Apr 97* 166-168
- He-Ne laser, precision freq. meas., Sr^+ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
- He-Ne laser, $^{127}I_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190
- wavelength ratio meas., fringe counting sigmameter. *Juncar, P.P., + , T-IM Jun 97* 690-695

Networks; cf. Neural networks

Neural network applications
- fiber optic sens. for surface roughness/displacement meas. *Zhang, K., + , T-IM Aug 97* 899-902
- modular ANN for prediction of petrophysical props. from well log data. *Fung, C.C., + , T-IM Dec 97* 1295-1299
- neural networks for hydrocyclone param. $d50_c$ estim. *Eren, H., + , T-IM Aug 97* 908-912

Neural networks
- Euclidean classifier, charge based synaptic matrix. *Onat, B.M., + , T-IM Jun 97* 672-677

Neural networks; cf. Multilayer perceptrons; Self-organizing feature maps

Neutron spectroscopy
- beam pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861

Nickel alloys
- AuGeNi contacts, precision quantized Hall devices fab. *Inglis, A.D., + , T-IM Apr 97* 281-284

Niobium
- Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
- Nb/Al-AlO_x/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
- Nb/Al_2O_3-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481

Noble gases; cf. Argon; Helium; Neon

Noise; cf. Circuit noise; Crosstalk; Electromagnetic interference; Laser noise; Phase noise; Random noise; Semiconductor device noise; White noise

Noise measurement
- A/D converters quantization-noise estim. uncertainties. *Chiorboli, G., + , T-IM Feb 97* 56-60
- DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
- GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
- microwave devices noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048
- microwave low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494
- multistate microwave radiometer, impedance and noise temp. meas. *Wiatr, W., + , T-IM Apr 97* 486-489
- multistate radiometry, noise de-embedding/un-terminating. *Wiatr, W., T-IM Apr 97* 503-506
- Nb/Al_2O_3-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481

NIST amp. noise meas., noise-fig. meas. service. *Wait, D.F., + , T-IM Apr 97* 482-485
offset charge noise in SET devices. *Wolf, H., + , T-IM Apr 97* 303-306
phase noise and jitter meas., time domain anal./appl. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
sinewave fitting procedure for data acquisition channels characterization. *Schoukens, J., + , T-IM Aug 97* 1005-1010
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256-1261

Nondestructive testing
laser displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092

Nonlinear circuits; cf. Nonlinear filters; Nonlinear oscillators

Nonlinear distortion; cf. Harmonic distortion

Nonlinear estimation
model based opt. resoln. *den Dekker, A.J., T-IM Aug 97* 798-802
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030

Nonlinear filters
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928

Nonlinearities
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
nonlinearity of data-acquisition syst. with interleaving/multiplexing. *Simoes, J.B., + , T-IM Dec 97* 1274-1279
subranging A/D converters with digital correction, testing. *Chiorboli, G., + , T-IM Aug 97* 975-979

Nonlinearities; cf. Communication system nonlinearities

Nonlinear magnetics; cf. Saturable cores

Nonlinear optics; cf. Optical mixers; Optical saturation

Nonlinear oscillators
chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188

Nonlinear systems
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
delay elements determ., NARMA models, dispersion fns. *Ho-En Liao, + , T-IM Aug 97* 868-872

Nuclear magnetic resonance
He-4 atom gyromagnetic ratio, expt. determ. *Shifrin, V.Y., + , T-IM Apr 97* 97-100
^{3}He, opt. pumped NMR, fund. consts. determ. *Flowers, J.L., + , T-IM Apr 97* 104-107

Nuclear measurements
paper basis-wt./ash-content meas., nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940

Numerical analysis
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928

Numerical analysis; cf. Finite element methods; Iterative methods; Monte Carlo methods

O

Object detection
plane reflectors localization, wide-beamwidth US transducer. *Ming Yang, + , T-IM Jun 97* 711-716

Object oriented programming
calib. of power transducers, PC-based adaptive software. *Chern-Lin Chen, + , T-IM Oct 97* 1145-1149

One-port circuits
multistate microwave radiometer, impedance and noise temp. meas. *Wiatr, W., + , T-IM Apr 97* 486-489

Operational amplifiers
HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043

Optical communication
position estim. of mobile robots based on coded IR sig. transm. *Eren, H., + , T-IM Dec 97* 1280-1283

Optical communication; cf. Optical fiber communication; SONET

Optical communication equipment; cf. Optical transmitters

Optical correlators
digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806

Optical crosstalk
crosstalk anal. of 1 m to 10 m laser phase-shift range finder. *Bosch, T., + , T-IM Dec 97* 1224-1228

Optical device fabrication
Si sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575

Optical diffraction
X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200

Optical distance measurement
3D meas. using video camera and range finder. *Chavand, F., + , T-IM Dec 97* 1229-1235
crosstalk anal. of 1 m to 10 m laser phase-shift range finder. *Bosch, T., + , T-IM Dec 97* 1224-1228
TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999

Optical fiber communication
two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211

Optical fiber devices
grating-based devices, temp. compensation. *Arya, V., + , T-IM Oct 97* 1173-1177

Optical fiber devices; cf. Optical fiber filters; Optical fiber transducers

Optical fiber filters
grating-based devices, temp. compensation. *Arya, V., + , T-IM Oct 97* 1173-1177

Optical fiber measurements
birefr. opt. fibers meas., interferometry. *Bock, W.J., + , T-IM Aug 97* 903-907

Optical fiber polarization
birefr. opt. fibers meas., interferometry. *Bock, W.J., + , T-IM Aug 97* 903-907

Optical fiber transducers
elec. field probe, polymer dispersed liq. crysts. *Lacquet, B.M., + , T-IM Feb 97* 31-35
multiplexed large-scale opt. fiber sens. arrays, 2D encoding. *Yiqun Hu, + , T-IM Oct 97* 1160-1164
surface roughness/displacement meas. *Zhang, K., + , T-IM Aug 97* 899-902

Optical filters; cf. Optical fiber filters

Optical frequency conversion
freq. meas., He-Ne laser. *Udem, T., + , T-IM Apr 97* 166-168
freq. std., ^{87}Rb D_2-line/SHG. *Poulin, M., + , T-IM Apr 97* 157-161
He-Ne laser, $^{127}I_2$ stabilized, freq. shifts at higher harmonic order stabilization. *Hu, J., + , T-IM Apr 97* 186-190

Optical frequency conversion; cf. Optical mixers

Optical imaging; cf. Robot vision systems

Optical interferometry
birefr. opt. fibers meas., interferometry. *Bock, W.J., + , T-IM Aug 97* 903-907
extended-cavity LD stabilized on I_2, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
He-Ne and He-Ne/I_2 lasers, Ne isotopes effect. *Cartaleva, S.S., + , T-IM Apr 97* 149-152
multiplexed large-scale opt. fiber sens. arrays, 2D encoding. *Yiqun Hu, + , T-IM Oct 97* 1160-1164
NIST watt bal., kilogram monitoring, meas. uncertainties. *Steiner, R.L., + , T-IM Apr 97* 601-604
NIST watt expt., alignment uncertainties. *Gillespie, + , T-IM Apr 97* 605-608
NPL moving-coil apparatus, Planck's const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
refractometer, vac. cell/double-pass Michelson interferometer, air refr. index meas. *Fujii, K., + , T-IM Apr 97* 191-195
Si, lattice spacing d(220), X-ray/opt. interferometry meas. *Nakayama, K., + , T-IM Apr 97* 580-583
Si sphere dimens. meas., Avogadro's no. determ. *Nicolaus, R.A., + , T-IM Apr 97* 563-565
wavelength ratio meas., fringe counting sigmameter. *Juncar, P.P., + , T-IM Jun 97* 690-695
X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200

Optical interferometry; cf. Fabry-Perot interferometers

Optical mixers
laser displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850

Optical modulation
Ar$^+$ laser, amplit. noise and linewidth reduction. *Bisi, M., + , T-IM Apr 97* 153-156
extended cavity diode laser, I_2-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
OsO_4 saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177

refractometer, vac. cell/double-pass Michelson interferometer, air refr. index meas. *Fujii, K., + , T-IM Apr 97* 191-195
ultrastable opt. freq. ref., 1.064 µm. *Jun Ye, + , T-IM Apr 97* 178-182
Optical noise; cf. Optical crosstalk
Optical phase shifters
crosstalk anal. of 1 m to 10 m laser phase-shift range finder. *Bosch, T., + , T-IM Dec 97* 1224-1228
Optical polarization; cf. Optical fiber polarization
Optical position measurement
noise anal. for posn.-sensitive detectors. *Narayanan, C., + , T-IM Oct 97* 1137-1144
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
Optical propagation in absorbing media; cf. Laser absorbers
Optical pumping
He-4 atom gyromagnetic ratio, expt. determ. *Shifrin, V.Y., + , T-IM Apr 97* 97-100
^{113}Cd$^+$ trapped ions, laser microwave double-reson. method. *Tanaka, U., + , T-IM Apr 97* 137-140
^{3}He, opt. pumped NMR, fund. consts. determ. *Flowers, J.L., + , T-IM Apr 97* 104-107
^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129
Optical reflection
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
Optical refraction
fiber optic grating-based devices, temp. compensation. *Arya, V., + , T-IM Oct 97* 1173-1177
Optical resonators; cf. Fabry-Perot resonators
Optical saturation
I$_2$-Doppler-free freq. stabilized extended cavity diode laser. *Simonsen, H.R., T-IM Apr 97* 141-144
I$_2$ intracavity saturation spectrosc., extended-cavity LD. *Zarka, A., + , T-IM Apr 97* 145-148
ultrastable opt. freq. ref., 1.064 µm. *Jun Ye, + , T-IM Apr 97* 178-182
Optical signal processing; cf. Optical correlators
Optical transducers
laser displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936
Optical transducers; cf. Optical fiber transducers
Optical transmitters
position estim. of mobile robots based on coded IR sig. transm. *Eren, H., + , T-IM Dec 97* 1280-1283
Optical variables measurement
OsO$_4$ saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177
wavelength ratio meas., fringe counting sigmameter. *Juncar, P.P., + , T-IM Jun 97* 690-695
Optical velocity measurement
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
Optical waveguide filters; cf. Optical fiber filters
Optimization methods
2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
beam pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861
calib. status of measuring instrum. monitoring, stochastic model. *Bobbio, A., + , T-IM Aug 97* 747-751
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990
meas. IS, general meas. problem representation. *Muravyov, S.V., + , T-IM Aug 97* 961-965
measuring systs. parametric optim., joint error criterion. *Gajda, J., + , T-IM Aug 97* 769-775
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
Optimization methods; cf. Circuit optimization; Least squares methods; Minimization methods
Optoelectronic devices; cf. Photoconducting devices; Photodetectors
Organic compounds
absol. freq. meas. of H two-photon reson. *Udem, T., + , T-IM Apr 97* 166-168
neural networks for hydrocyclone param. d50$_c$ estim. *Eren, H., + , T-IM Aug 97* 908-912
Oscillator noise
Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
Oscillators; cf. Dielectric resonator oscillators; Gunn device oscillators; Microwave oscillators; Nonlinear oscillators; Piezoelectric resonator oscillators; Voltage controlled oscillators
Oscilloscopes
metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666

P

Parallel processing
fault online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
Paramagnetic resonance
H, fund. consts. determ. *Flowers, J.L., + , T-IM Apr 97* 104-107
Parameter estimation
ADC, effective bit estim. methods accuracy. *Bertocco, M., + , T-IM Aug 97* 1011-1015
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
A/D converters quantization-noise estim. uncertainties. *Chiorboli, G., + , T-IM Feb 97* 56-60
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797
fault online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
measuring systs. parametric optim., joint error criterion. *Gajda, J., + , T-IM Aug 97* 769-775
model based opt. resoln. *den Dekker, A.J., T-IM Aug 97* 798-802
neural networks for hydrocyclone param. d50$_c$ estim. *Eren, H., + , T-IM Aug 97* 908-912
Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
spectrometric data num. correction, cubic FIR-type filter. *Szczecinski, L., + , T-IM Aug 97* 922-928
time-resolved spectra global anal., param. precision. *van Stokkum, I.H.M., T-IM Aug 97* 764-768
Parameter estimation; cf. Frequency estimation
Particle-beam choppers
beam pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861
Particle beam extraction
Ar$^+$ ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591
Particle beam measurements
Ar$^+$ ion beam from high-current ion source. *Ratschko, D., + , T-IM Apr 97* 588-591
pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861
Particle beams; cf. Atomic beams; Ion beams
Particle sources; cf. Ion sources
Pattern classification
neural Euclidean classifier, charge based synaptic matrix. *Onat, B.M., + , T-IM Jun 97* 672-677
Pattern classification; cf. Image classification
Pattern recognition
meas. IS, general meas. problem representation. *Muravyov, S.V., + , T-IM Aug 97* 961-965
Perceptrons; cf. Multilayer perceptrons
Periodic structures
microwave meas. of semicond. waveguides, dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721
Periodic structures; cf. Gratings
Permeability measurement
multilayers permitt./permeab./thickness meas., waveguide. *Tantot, O., + , T-IM Apr 97* 519-522
Permittivity measurement
broadband free-space meas. syst., MM wavelengths. *Friedsam, G.L., + , T-IM Apr 97* 515-518
L-band automated syst., coaxial resonator. *Galwas, B.A., + , T-IM Apr 97* 511-514

microwave meas. of semicond. waveguides, dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721
multilayers permitt./permeab./thickness meas., waveguide. *Tantot, O., + , T-IM Apr 97* 519-522
open-ended coaxial probe for permitt. meas., NWA. *Blackham, D.V., + , T-IM Oct 97* 1093-1099
precision microwave testing of dielec. substrs. *Yushchenko, A.G., + , T-IM Apr 97* 507-510
rice weevils, RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946
X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
Petroleum industry
modular ANN for prediction of petrophysical props. from well log data. *Fung, C.C., + , T-IM Dec 97* 1295-1299
Phase comparators
OsO_4 saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177
Phase distortion
sig. samplers phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666
Phase jitter
phase noise and jitter meas., time domain anal./appl. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
Phase locked loops
clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
Phase measurement
accurate dist. meas. by autonomous US syst. combining TOF and phase-shift methods. *Gueuning, F., + , T-IM Dec 97* 1236-1240
multiple-target FM CW ranging by eval. of impulse response phase. *Stolle, R., + , T-IM Apr 97* 426-429
Phase measurement; cf. Phase comparators
Phase modulation
phase noise and jitter meas., time domain anal./appl. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
refractometer, vac. cell/double-pass Michelson interferometer, air refr. index meas. *Fujii, K., + , T-IM Apr 97* 191-195
Phase noise
Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
time domain anal. and appl., meas. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
Phase shifters
six-port reflectometer in MMIC technol. *Wiedmann, F., + , T-IM Apr 97* 527-530
Phase shifters; cf. Optical phase shifters
Photoconducting devices
microwave meas. of semicond. waveguides, dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
Photoconducting devices; cf. Photodiodes
Photodetectors
light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
posn.-sensitive detectors, noise anal. *Narayanan, C., + , T-IM Oct 97* 1137-1144
Photodiodes
light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
Photodiodes; cf. p-i-n photodiodes
Photolithography
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
Photon beams; cf. Laser beams
Physics; cf. Atomic physics
Piezoelectric resonator oscillators
AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390
Piezoelectric transducers
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
Piezoresistive devices
tactile sens., robotic appl. *Fiorillo, A.S., T-IM Feb 97* 15-17
p-i-n photodiodes
posn.-sensitive detectors, noise anal. *Narayanan, C., + , T-IM Oct 97* 1137-1144
Planar waveguides
microwave meas. of semicond. waveguides, dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721
p-n heterojunctions
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
p-n junctions
deep-level charactn., trigonometric wt. fns. *Nubile, P., T-IM Oct 97* 1156-1159
Poisson processes
Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
Pollution; cf. Air pollution
Pollution measurement
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
Polynomial approximation
predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757
Position control
NIST watt expt., alignment uncertainties. *Gillespie, + , T-IM Apr 97* 605-608
scanning X-ray interf. over mm baseline, Si (220) lattice spacing meas. *Bergamin, A., + , T-IM Apr 97* 576-579
Position measurement
capacitive ang.-posn. sens. optimization. *Xiujun Li, + , T-IM Feb 97* 8-14
position estim. of mobile robots based on coded IR sig. transm. *Eren, H., + , T-IM Dec 97* 1280-1283
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50
smart capacitive ang.-posn. sens., self-calib. *Li, X., + , T-IM Aug 97* 888-892
Position measurement; cf. Optical position measurement
Potentiometers
alternating voltage meas., ac-dc transfer stds., micropotentiometer-based calib. *Budovsky, I., T-IM Apr 97* 356-360
NIST thin-film multijunction thermal converters, micropotentiometers. *Kinard, J.R., + , T-IM Apr 97* 347-351
RF-DC differences of micropotentiometers. *De Xiang Huang, + , T-IM Apr 97* 337-341
thin-film ac-dc converter with thermoresistive sens., temp. sens. *Katzmann, F.L., + , T-IM Apr 97* 382-386
Powders
microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
Power amplifiers; cf. Power FET amplifiers
Power capacitors
act. HV divider with 20 µV/V uncertainty, compressed-gas capacitor. *Petersons, O., + , T-IM Apr 97* 430-434
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825
Power conversion; cf. AC-DC power conversion
Power distribution electromagnetic interference
voltage transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921
Power engineering; cf. High-voltage techniques
Power FET amplifiers
RF transistor large-sig. meas., power amp. design. *Cheng-Yung Chiang, + , T-IM Oct 97* 1150-1155
Power FETs; cf. Power MESFETs
Power measurement
calibrator, sampled feedback for current and voltage. *Gubisch, A., + , T-IM Apr 97* 403-407
comments on “Accurate measurement of power, energy, and true RMS voltage using synchronous counting” by J.K. Kolanko (Jun 93 752-754). *Mauritzen, D.W., + , T-IM Dec 97* 1300-1301
double six-port reflectometer, on-wafer calib., absol. power meas. *Berghoff, G., + , T-IM Oct 97* 1111-1114
inductive voltage divider, ac-power meas., in-phase errors. *Zinkernagel, J., T-IM Oct 97* 1075-1080
K- and Ka-band waveguide microcalorimeters for microwave power standards. *Kang, T.W., + , T-IM Dec 97* 1247-1250

microwave pulse meas., resistive sens. *Dagys, M., + , T-IM Apr 97* 499-502
mismatch factor determ., RF power calib. *Stumper, U., T-IM Apr 97* 531-534
mm-wave power stds., isothermal calorimeter power meters. *Akhiezer, A.N., + , T-IM Apr 97* 495-498
NIST watt expt., alignment uncertainties. *Gillespie, + , T-IM Apr 97* 605-608
power meter for highly distorted three-phase systs. *Carullo, A., + , T-IM Dec 97* 1262-1267
selected papers CPEM’96 (special issue). *T-IM Apr 97* 94-646
stds., automatic zero-PF/sampling wattmeter std. *Simonson, P., + , T-IM Apr 97* 423-425
thermal power transfer std., resistive voltage divider, comparator. *Shapiro, E.Z., + , T-IM Apr 97* 412-415
thermal wattmeter, power comparator, ac power meas. *Laiz, H., + , T-IM Apr 97* 420-422
three-phase digital recorder syst. for calib. power instrumentation. *Arseneau, R., + , T-IM Apr 97* 399-402
time-division watt-converter,frequency depend. systematic error, compensation. *Jovanovic, L.D., T-IM Apr 97* 416-419
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783

Power MESFETs
expt. comparison of load-pull meas. systs. for nonlin. power transistor charactn. *Deshours, F., + , T-IM Dec 97* 1251-1255

Power supplies
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256-1261

Power system measurements
freq. real-time determ. *Lobos, T., + , T-IM Aug 97* 877-881

Power system measurements; cf. Substation measurements

Power system protection
power syst. freq. real-time determ. *Lobos, T., + , T-IM Aug 97* 877-881

Power transformer losses
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816

Power transformer testing
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816

Power transformer thermal factors
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816

Precision Electromagnetic Measurements, 1996 Conference on
selected papers (special issue). *T-IM Apr 97* 94-646

Prediction methods
IIR filters design, FIR forward predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
modular ANN for prediction of petrophysical props. from well log data. *Fung, C.C., + , T-IM Dec 97* 1295-1299

Pressure measurement
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757

Probability
calib. status of measuring instrum. monitoring, stochastic model. *Bobbio, A., + , T-IM Aug 97* 747-751

Probability; cf. Gaussian distributions

Programmable circuits
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256-1261

Programmable logic arrays; cf. Field programmable gate arrays

Programming
calib. of power transducers, PC-based adaptive software. *Chern-Lin Chen, + , T-IM Oct 97* 1145-1149
meas. software develop., auto-consistent environ. *Steenput, E., + , T-IM Aug 97* 742-746

Programming; cf. Object oriented programming

Programming environments
meas. software develop., auto-consistent environ. *Steenput, E., + , T-IM Aug 97* 742-746

Protection; cf. Power system protection

Pulp and paper industry
meas. of paper basis-wt./ash-content, nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940

Pulsed lasers
TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999

Pulsed lasers; cf. Mode locked lasers

Pulse width modulation
LF mag. EMC meas., fluxgate magnetometer. *Weyand, K., + , T-IM Apr 97* 617-620

Q

Quantization
accuracy of effective bit estim. methods. *Bertocco, M., + , T-IM Aug 97* 1011-1015
A/D converters quantization-noise estim. uncertainties. *Chiorboli, G., + , T-IM Feb 97* 56-60
digital meas. systs., quantization error predetermination. *Vujicic, V.V., + , T-IM Apr 97* 439-441
dither-based quantizing systs. design. *Carbone, P., T-IM Jun 97* 656-659
FPGA time-to-digital converter, 200-ps resoln. *Kalisz, J., + , T-IM Feb 97* 51-55
nonlinearity of data-acquisition syst. with interleaving/multiplexing. *Simoes, J.B., + , T-IM Dec 97* 1274-1279
phase noise and jitter meas., time domain anal./appl. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
scan conversion-based transient digitizers, improved sig. extraction. *Arpaia, P., + , T-IM Aug 97* 893-898
sinewave optimized test of waveform digitizers, DFT approach. *Bertocco, M., + , T-IM Aug 97* 970-974

Quantum effect semiconductor devices
single-electron tunneling expts., microwave filter atten. *Fukushima, A., + , T-IM Apr 97* 289-293

Quantum effect semiconductor devices; cf. MODFETs

R

Radar; cf. FM radar; Laser radar

Radar applications; cf. Radar imaging; Radar measurements; Radar tracking

Radar clutter
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841

Radar distance measurement
TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999

Radar imaging
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841

Radar interference; cf. Radar clutter

Radar measurements
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841

Radar measurements; cf. Radar distance measurement

Radar scattering
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841

Radar signal analysis
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841

Radar tracking
multiple-target FM CW ranging by eval. of impulse response phase. *Stolle, R., + , T-IM Apr 97* 426-429

Radiation detectors; cf. Beta-ray detectors; Bolometers; Gamma-ray detectors; Infrared detectors; Photodetectors; Scintillation detectors

Radiation effects; cf. Infrared radiation effects; Semiconductor device radiation effects

Radio communication equipment; cf. Transceivers

Radiometry; cf. Microwave radiometry

Radio receivers; cf. Transponders

Radio transmitters; cf. Transponders

Random access memories; cf. DRAM chips

Random noise
absol. voltage amplif., dyn. feedback control. *de Jong, P.C., + , T-IM Aug 97* 758-763
ADC, effective bit estim. methods accuracy. *Bertocco, M., + , T-IM Aug 97* 1011-1015
A/D converters quantization-noise estim. uncertainties. *Chiorboli, G., + , T-IM Feb 97* 56-60
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
dither-based quantizing systs. design. *Carbone, P., T-IM Jun 97* 656-659
freq. estim., drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
posn.-sensitive detectors, noise anal. *Narayanan, C., + , T-IM Oct 97* 1137-1144

  - series-resistors-type voltage divider, common error sources. *Kyu-Tae Kim, + , T-IM Aug 97* 776-780
- **Rayleigh-Ritz methods; cf.** Galerkin method
- **Reactive power**
  - calibrator using precise wattmeter, autocalibration procedure. *Zupunski, I.Z., + , T-IM Apr 97* 408-411
  - inductive voltage divider, ac-power meas., in-phase errors. *Zinkernagel, J., T-IM Oct 97* 1075-1080
  - measuring stds., automatic zero-PF/sampling wattmeter std. *Simonson, P., + , T-IM Apr 97* 423-425
  - thermal power transfer std., resistive voltage divider, comparator. *Shapiro, E.Z., + , T-IM Apr 97* 412-415
- **Real time systems**
  - chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188
  - fault online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
- **Receivers**
  - metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
- **Rectangular waveguides**
  - X-band EM params., dielec. materials, nondestructive determ. *Chih-Wei Chang, + , T-IM Oct 97* 1084-1092
- **Rectifiers; cf.** AC-DC power conversion
- **Recursive digital filters**
  - FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
  - multisine synchronized meas. via DSP methods. *Varkonyi-Koczy, A.R., T-IM Aug 97* 929-932
- **Recursive estimation; cf.** Kalman filtering
- **Redundancy**
  - meas. software develop., auto-consistent environ. *Steenput, E., + , T-IM Aug 97* 742-746
- **Reed relays**
  - Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263
- **Reflectometry**
  - six-port reflectometer in MMIC technol. *Wiedmann, F., + , T-IM Apr 97* 527-530
  - six-port reflectometers, large bandwidths. *Hesselbarth, J., + , T-IM Aug 97* 966-969
- **Reflectometry; cf.** Microwave reflectometry
- **Registers; cf.** Shift registers
- **Relativistic effects**
  - freq. std., relativistic rate shift. *Petit, G., + , T-IM Apr 97* 201-204
- **Relays; cf.** Reed relays
- **Remote sensing**
  - SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
  - sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841
- **Resistance; cf.** Contact resistance
- **Resistance measurement**
  - AC QHE-based calib. of resist. stds. *Bohacek, J., + , T-IM Apr 97* 273-275
  - AC quantized Hall resist. eval. *Wood, H.M., + , T-IM Apr 97* 269-272
  - AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
  - AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
  - bifilar AC-DC resistor, microwire. *Semyonov, Yu.P., + , T-IM Apr 97* 333-336
  - bridges accuracy verification. *White, D.R., + , T-IM Apr 97* 329-332
  - bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710
  - four-terminal quantized Hall resist. in nonlin. regime. *Jeckelmann, B., + , T-IM Apr 97* 276-280
  - GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
  - IEN primary group of std. resistors, working temp. *Boella, G., + , T-IM Apr 97* 311-313
  - loading effects in resist. scaling. *Elmquist, R.E., + , T-IM Apr 97* 322-324
  - multimegohm std. resistors calib., automated guarded bridge. *Jarrett, D.G., T-IM Apr 97* 325-328
  - ohm realization, quantized Hall resist. vs calculable capacitor. *Jeffery, A.-M., + , T-IM Apr 97* 264-268
  - selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
  - supercond. thin-films, microwave surface resist., calorimetric meas. *Andreone, D., + , T-IM Apr 97* 535-538
- **Resistive circuits**
  - resist. thermometry bridges, calib., resist. network. *White, D.R., + , T-IM Oct 97* 1068-1074
- **Resistors**
  - AC-DC voltage transfer std., freq. depend. *Pogliano, U., + , T-IM Apr 97* 373-376
  - AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
  - bifilar AC-DC resistor, microwire. *Semyonov, Yu.P., + , T-IM Apr 97* 333-336
  - GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
  - IEN primary group of std. resistors, working temp. *Boella, G., + , T-IM Apr 97* 311-313
  - loading effects in resist. scaling. *Elmquist, R.E., + , T-IM Apr 97* 322-324
  - multimegohm std. resistors calib., automated guarded bridge. *Jarrett, D.G., T-IM Apr 97* 325-328
- **Resonators; cf.** Acoustic resonators; Coaxial resonators; Laser resonators; Microwave resonators; Superconducting cavity resonators
- **Road vehicle electronics**
  - SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
- **Robots; cf.** Mobile robots; Telerobotics
- **Robot sensing systems**
  - plane reflectors localization, wide-beamwidth US transducer. *Ming Yang, + , T-IM Jun 97* 711-716
- **Robot tactile systems**
  - piezoresistive tactile sens. *Fiorillo, A.S., T-IM Feb 97* 15-17
- **Robot vision systems**
  - 3D meas. using video camera and range finder. *Chavand, F., + , T-IM Dec 97* 1229-1235
  - camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
- **Rough surfaces**
  - fiber optic sens. for surface roughness/displacement meas. *Zhang, K., + , T-IM Aug 97* 899-902
- **Rough surfaces; cf.** Sea surface
- **Rubidium**
  - ^{87}Rb D$_2$-line, opt. freq. std. appl. *Poulin, M., + , T-IM Apr 97* 157-161
  - ^{87}Rb freq. std., light shift effect anal. *Levi, F., + , T-IM Apr 97* 126-129

S

- **Sampled data systems**
  - Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
- **Sapphire**
  - cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
  - opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
- **Satellite broadcasting**
  - freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
  - std. time/freq. sig. broadcast via INSAT, differential mode. *Gupta, A.S., + , T-IM Apr 97* 212-215
- **Satellite communication earth terminals**
  - two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
- **Saturable cores**
  - false-bal.-avoidance transductor for measuring large DC currents. *Ken Xu, + , T-IM Oct 97* 1081-1083
- **Scattering parameters measurement**
  - double six-port reflectometer, on-wafer calib., absol. power meas. *Berghoff, G., + , T-IM Oct 97* 1111-1114
  - dual six-port NWA calib. *Krekels, H.-G., + , T-IM Oct 97* 1115-1119
  - HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043
  - microwave low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494
  - NWA meas. with leakage errors, direct calib. *Heuermann, H., + , T-IM Oct 97* 1120-1127
  - on-wafer microwave meas., NWA self-calib. methods. *Heuermann, H., + , T-IM Oct 97* 1105-1110
  - six-port reflectometer in MMIC technol. *Wiedmann, F., + , T-IM Apr 97* 527-530
- **Schottky diodes**
  - lin. for six-port reflectometers. *Hesselbarth, J., + , T-IM Aug 97* 966-969
- **Scintillation detectors**
  - paper basis-wt./ash-content meas., nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940
- **Sea measurements**
  - sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841

Sea surface
sea texture coherence length meas., cpd.-Gaussian proc. *Conte, E., + , T-IM Aug 97* 836-841
Self-organizing feature maps
modular ANN for prediction of petrophysical props. from well log data. *Fung, C.C., + , T-IM Dec 97* 1295-1299
Self-testing
current-mode algorithmic A/D converters, BIST design. *Chin-Long Wey, T-IM Jun 97* 667-671
simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304
Semiconductor defects
p-n jn. devices deep-level charactn. *Nubile, P., T-IM Oct 97* 1156-1159
Semiconductor device fabrication
GaAs/AlGaAs quantized Hall devices fab. for metrology. *Inglis, A.D., + , T-IM Apr 97* 281-284
Semiconductor device measurements
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
double six-port reflectometer, on-wafer calib., absol. power meas. *Berghoff, G., + , T-IM Oct 97* 1111-1114
expt. comparison of load-pull meas. systs. for nonlin. power transistor charactn. *Deshours, F., + , T-IM Dec 97* 1251-1255
extended cavity diode laser, I$_2$-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
extended-cavity LD stabilized on I$_2$, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
microwave low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494
on-wafer microwave meas., NWA self-calib. methods. *Heuermann, H., + , T-IM Oct 97* 1105-1110
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256-1261
Semiconductor device mechanical factors
Si sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575
Semiconductor device modeling
GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
Semiconductor device noise
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
microwave devices noise params. meas. *Bareau, P., + , T-IM Aug 97* 1044-1048
microwave low-noise packaged HEMT, scatt. and noise params., meas. and models. *Caddemi, A., + , T-IM Apr 97* 490-494
offset charge noise in SET devices. *Wolf, H., + , T-IM Apr 97* 303-306
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
posn.-sensitive detectors, noise anal. *Narayanan, C., + , T-IM Oct 97* 1137-1144
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256-1261
Semiconductor device radiation effects
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
Semiconductor devices; cf. Hall effect devices; Piezoresistive devices; Quantum effect semiconductor devices; Semiconductor lasers; Semiconductor waveguides
Semiconductor device testing
GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104
ultralow-noise prog. voltage source. *Baracchino, L., + , T-IM Dec 97* 1256-1261
Semiconductor diodes; cf. Photodiodes; Schottky diodes; Zener diodes
Semiconductor heterojunctions
AlGaAs/GaAs heterostruct., IR illum., quantized Hall resist. accuracy. *Jeanneret, B., + , T-IM Apr 97* 285-288
Semiconductor heterojunctions; cf. p-n heterojunctions
Semiconductor junctions; cf. p-n junctions;
Semiconductor lasers
crosstalk anal. of 1 m to 10 m laser phase-shift range finder. *Bosch, T., + , T-IM Dec 97* 1224-1228
displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850
extended cavity diode laser, I$_2$-Doppler-free freq. stabilized. *Simonsen, H.R., T-IM Apr 97* 141-144
extended-cavity LD stabilized on I$_2$, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148
precision freq. meas., diode laser locked Sr$^+$ S-D transit. *Marmet, L., + , T-IM Apr 97* 169-173
Sr$^+$ ion based freq. std. develop. *Barwood, G.P., + , T-IM Apr 97* 133-136
Semiconductor materials; cf. Amorphous semiconductors; Semiconductor waveguides
Semiconductor materials measurements
Si (220) lattice spacing, scanning X-ray interf., mm baseline. *Bergamin, A., + , T-IM Apr 97* 576-579
Si, lattice spacing d(220), X-ray/opt. interferometry meas. *Nakayama, K., + , T-IM Apr 97* 580-583
Si, molar vol. rel., Avogadro const. determ. *De Bievre, P., + , T-IM Apr 97* 592-595
Si spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587
Semiconductor waveguides
microwave meas. of semicond. waveguides, dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721
Sensitivity
tunneling electrometer, single Cooper pair type, sensitivity. *Zorin, A.B., T-IM Apr 97* 299-302
Series (mathematics); cf. Fourier series
Servosystems
scanning X-ray interf. over mm baseline, Si (220) lattice spacing meas. *Bergamin, A., + , T-IM Apr 97* 576-579
SF$_6$
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
Shape measurement
cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797
Si sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575
Si spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587
Shielding
capacitance-based displacement meas., AC current source, input shielding. *Nerino, R., + , T-IM Apr 97* 640-643
externally shielded cryogenic current comparator, sensitivity meas., QHR bridges. *Early, M.D., + , T-IM Apr 97* 459-462
Shielding; cf. Magnetic shielding
Shift registers
Nb/Al$_2$O$_3$-Al/Nb RSFQ shift register for appls. in RF noise power metrology. *Kessel, W., + , T-IM Apr 97* 477-481
Sigma-delta modulation
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
resistive bridge sens., bitstream output. *Fasoli, L.G., + , T-IM Aug 97* 954-960
Signal analysis
calib. sigs. dyn. accuracy, integral-sq.-error. *Layer, E., T-IM Oct 97* 1178-1182
Cs beam freq. stds., Ramsey pattern anal. *Makdissi, A., + , T-IM Apr 97* 112-116
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
high-speed ADC error estim. *Muginov, G.D., + , T-IM Aug 97* 980-985
multisine synchronized meas. via DSP methods. *Varkonyi-Koczy, A.R., T-IM Aug 97* 929-932
phase noise and jitter meas., time domain anal./appl. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
power meter for highly distorted three-phase systs. *Carullo, A., + , T-IM Dec 97* 1262-1267
scan conversion-based transient digitizers, improved sig. extraction. *Arpaia, P., + , T-IM Aug 97* 893-898
Signal analysis; cf. Harmonic analysis; Radar signal analysis; Spectral analysis
Signal detection; cf. Acoustic signal detection
Signal generators
AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
digitizers, SNR testing, sine-fit vs. DFT algms. *Bertocco, M., + , T-IM Apr 97* 445-448
direct digital synthesizer, jittered clock. *Yih-Chyun Jenq, T-IM Jun 97* 653-655

multiple digital sig. generators, noise-adaptive digital null detector. *Tarach, D., + , T-IM Apr 97* 435-438
PF calibrator using precise wattmeter, autocalibration procedure. *Zupunski, I.Z., + , T-IM Apr 97* 408-411
power calibrator, sampled feedback for current and voltage. *Gubisch, A., + , T-IM Apr 97* 403-407
sinewave fitting procedure for data acquisition channels characterization. *Schoukens, J., + , T-IM Aug 97* 1005-1010
voltage source eval., calculable RMS outputs. *Lapuh, R., + , T-IM Aug 97* 784-788
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953

Signal processing
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
fault online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
p-n jn. devices deep-level charactn. *Nubile, P., T-IM Oct 97* 1156-1159
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
self-sens. mag. bearings, param. estim. *Noh, M.D., + , T-IM Feb 97* 45-50

Signal processing; cf. Acoustic signal processing; Filtering; Geophysical signal processing; Image processing; Signal reconstruction; Signal sampling; Speech processing; Video signal processing

Signal reconstruction
nonuniformly sampled sigs., random equiv. time sampling syst. *Yih-Chyun Jenq, T-IM Jun 97* 649-652
samplers phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666

Signal reconstruction; cf. Image reconstruction
Signal resolution; cf. Image resolution
Signal restoration; cf. Image restoration
Signals; cf. Bandlimited signals

Signal sampling
capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
phase-distortion error quantification. *Verspecht, J., T-IM Jun 97* 660-666
reconstruction of digital spectrum from nonuniformly sampled sigs. *Yih-Chyun Jenq, T-IM Jun 97* 649-652
sinewave optimized test of waveform digitizers, DFT approach. *Bertocco, M., + , T-IM Aug 97* 970-974
voltage source eval., calculable RMS outputs. *Lapuh, R., + , T-IM Aug 97* 784-788
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953

Silicon
Avogadro project, Si crysts. isotopic anal. *Rottger, S., + , T-IM Apr 97* 560-562
Avogadro projects, Si samples intercomparison. *Kessler, E.G., Jr., + , T-IM Apr 97* 551-555
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
dens. stds., internat. intercomparison. *Bettin, H., + , T-IM Apr 97* 556-559
fine struct. const. determ. *Kruger, E., + , T-IM Apr 97* 101-103
lattice spacing d(220), X-ray/opt. interferometry meas. *Nakayama, K., + , T-IM Apr 97* 580-583
lattice spacing, scanning X-ray interf., mm baseline. *Bergamin, A., + , T-IM Apr 97* 576-579
lattice spacing, X-ray/laser interferometry, beam-astigmatism. *Bergamin, A., + , T-IM Apr 97* 196-200
light-to-freq. converter, integrat. mode photodiodes. *de Graaf, G., + , T-IM Aug 97* 933-936
molar mass meas. for better Avogadro const. *Gonfiantini, R., + , T-IM Apr 97* 566-571
molar vol. rel., Avogadro const. determ. *De Bievre, P., + , T-IM Apr 97* 592-595
Si analog Hall probe, magnetometry, vert. Hall devices. *Schott, C., + , T-IM Apr 97* 613-616
sphere dimens. meas., Avogadro's no. determ. *Nicolaus, R.A., + , T-IM Apr 97* 563-565
sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575
spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587

Silicon alloys
FeSiB mag. field sens., magnetostrictive delay lines. *Hristoforou, E., + , T-IM Apr 97* 632-635

Silicon compounds
SiF_4, Avogadro const. determ. *Gonfiantini, R., + , T-IM Apr 97* 566-571

Simulation
ADC fast/accurate testing, sine wave fitting algm. *Giaquinto, N., + , T-IM Aug 97* 1020-1025
camera calib. method, three-step, for machine vision. *Bacakoglu, H., + , T-IM Oct 97* 1165-1172
differential amplifer, common-mode rejection ratio redefined. *Koide, F.T., T-IM Jun 97* 737-739
electron wave reconstruction, param. estim. *vand den Bos, A., T-IM Aug 97* 826-830
nonlin. delay elements determ., NARMA models, using dispersion fns. *Ho-En Liao, + , T-IM Aug 97* 868-872
posn.-sensitive detectors, noise anal. *Narayanan, C., + , T-IM Oct 97* 1137-1144
sinewave fit algm., ADC effective bits meas. appl. *Jian Qiu Zhang, + , T-IM Aug 97* 1026-1030

Simulation; cf. Circuit simulation

Simulation software
smart sens. output handling, noniterative polynomial 2D calib. *Lyahou, K.F., + , T-IM Aug 97* 752-757

Size measurement
Si sphere dimens. meas., Avogadro's no. determ. *Nicolaus, R.A., + , T-IM Apr 97* 563-565

Slot antennas
meas. of input impedance and radiation pattern. *Roy, L., + , T-IM Aug 97* 1000-1004

Software; cf. Simulation software
Software engineering; cf. Programming environments

Soil measurements
irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990

Solid lasers; cf. Semiconductor lasers

Sonar navigation
plane reflectors localization, wide-beamwidth US transducer. *Ming Yang, + , T-IM Jun 97* 711-716

SONET
two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211

Special issues and sections
selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
selected papers CPEM'96 (special issue intro.). *Cook, R.J., T-IM Apr 97* 95-96

Spectral analysis
correction to "comments on 'The modulo time plot: A useful data acquisition diagnostic tool'" (Dec 96 959). *Papay, Z., T-IM Jun 97* 739
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
direct digital synthesizer, jittered clock. *Yih-Chyun Jenq, T-IM Jun 97* 653-655
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
freq. estim., drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
Poisson sampled meas., spectral anal. methods. *Banning, R., T-IM Aug 97* 882-887
Ramsey lineshapes anal., vel. distrib. calc. by FT. *Shirley, J.H., T-IM Apr 97* 117-121
reconstruction of digital spectrum from nonuniformly sampled sigs. *Yih-Chyun Jenq, T-IM Jun 97* 649-652
sinewave optimized test of waveform digitizers, DFT approach. *Bertocco, M., + , T-IM Aug 97* 970-974
spectrogram interp., deconvolution/iter. optim. *Miekina, A., + , T-IM Aug 97* 1049-1053
speech codecs, objective test. *Bucci, G., + , T-IM Aug 97* 831-835
time-resolved spectra global anal., param. precision. *van Stokkum, I.H.M., T-IM Aug 97* 764-768

Spectral analysis; cf. Cepstral analysis

Spectrochemical analysis
PbSe photoconductor array, low-cost interface. *Chavez, J.A., + , T-IM Aug 97* 817-821
time-resolved spectra global anal., param. precision. *van Stokkum, I.H.M., T-IM Aug 97* 764-768

Spectroscopy
Kalman-filter-based algms., spectrometric data correction. *Massicotte, D., + , T-IM Jun 97* 678-684
OsO_4 saturated dispersion spectrosc. *Tyurikov, D., + , T-IM Apr 97* 174-177
spectrophotometric data correction, Kalman-filter, use of splines. *Slima, M.B., + , T-IM Jun 97* 685-689

Spectroscopy; cf. Gamma-ray spectroscopy; Infrared spectroscopy; Mass spectroscopy; Neutron spectroscopy
Speech codecs
  distortion meas., objective test. *Bucci, G., + , T-IM Aug 97* 831-835
Speech processing
  sound localization in reverberant environ., precedence effect model. *Huang, J., + , T-IM Aug 97* 842-846
Spheres
  Si sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575
  Si spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587
SPICE
  2D micromachined CMOS accelerometer. *Ahmad, H., + , T-IM Feb 97* 18-26
Spline functions
  spectrophotometric data correction, Kalman-filter, use of splines. *Slima, M.B., + , T-IM Jun 97* 685-689
Spread spectrum communication
  two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
Sputtering
  AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390
SQUID magnetometers
  HTSC DC SQUID-based magnetometer, direct-coupled electronics. *Gudoshnikov, S.A., + , T-IM Apr 97* 624-628
  sens., 3D positioning setup. *Willenberg, G.-D., + , T-IM Apr 97* 621-623
SQUIDs
  AC resist. bridge based on cryogenic current comparator. *Seppa, H., + , T-IM Apr 97* 463-466
  externally shielded cryogenic current comparator, sensitivity meas., QHR bridges. *Early, M.D., + , T-IM Apr 97* 459-462
Stability
  bifilar AC-DC resistor, microwire. *Semyonov, Yu.P., + , T-IM Apr 97* 333-336
  clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
  IEN primary group of std. resistors, working temp. *Boella, G., + , T-IM Apr 97* 311-313
  NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
  offset charge noise in SET devices. *Wolf, H., + , T-IM Apr 97* 303-306
  RF-DC differences of micropotentiometers. *De Xiang Huang, + , T-IM Apr 97* 337-341
Stability; cf. Absolute stability; Circuit stability; Frequency stability; Laser stability
Standards; cf. IEEE standards; Measurement standards
State estimation; cf. Kalman filtering
Statistics
  Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
  autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
  CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730
  DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
  scan conversion-based transient digitizers, improved sig. extraction. *Arpaia, P., + , T-IM Aug 97* 893-898
Steel
  microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
Stochastic circuits
  autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
Stochastic differential equations
  Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
Stochastic processes
  calib. status of measuring instrum. monitoring, stochastic model. *Bobbio, A., + , T-IM Aug 97* 747-751
  nonlin. delay elements determ., NARMA models, using dispersion fns. *Ho-En Liao, + , T-IM Aug 97* 868-872
Stochastic processes; cf. Gaussian processes; Poisson processes
Stochastic systems
  autoscaling feedback in mixed-sig. ccts., stat. anal. *Hejn, K., + , T-IM Aug 97* 913-917
Strain measurement
  current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
Stripline
  Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
Substation measurements
  transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
Subtraction
  current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
Superconducting cavity resonators
  high-T_c resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
  sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
Superconducting device fabrication; cf. Josephson device fabrication
Superconducting device measurements
  cracks eval. in superconductive cylinder by impedance meas. *Yamazaki, S., + , T-IM Aug 97* 873-876
Superconducting device noise; cf. Josephson device noise
Superconducting devices
  MAGLEV syst., buoyancy-free mass comparator. *Fujii, Y., + , T-IM Apr 97* 609-612
Superconducting devices; cf. Josephson devices; Superconducting microwave devices; Superconductor-insulator-superconductor devices; Superconductor-normal-superconductor devices
Superconducting films
  high-T_c resonators as freq. stds., dielec. loaded. *Gallop, J.C., + , T-IM Apr 97* 122-125
  microwave surface resist., calorimetric meas. *Andreone, D., + , T-IM Apr 97* 535-538
Superconducting magnet mechanical factors
  superconductive cylinder cracks eval. by impedance meas. *Yamazaki, S., + , T-IM Aug 97* 873-876
Superconducting materials; cf. High-temperature superconductors; Superconducting films
Superconducting microwave devices
  Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
Superconducting resonators; cf. Superconducting cavity resonators
Superconductor-insulator-superconductor devices
  AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
  Josephson jn. array, 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
  Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
Superconductor-normal-superconductor devices
  AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
Surface acoustic wave detectors
  wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
Surfaces; cf. Rough surfaces
Surface treatment
  Si sphere fab. for Avogadro const. determ., Young's modulus effect on roundness. *Collins, J.G., + , T-IM Apr 97* 572-575
Surface treatment; cf. Etching
Switched capacitor circuits
  capacitive press. sens. interface, oversampling sigma delta demodulation. *Yamada, M., + , T-IM Feb 97* 3-7
Switched resistor circuits
  resist. thermometry bridges, calib., resist. network. *White, D.R., + , T-IM Oct 97* 1068-1074
Switching transients
  monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
  voltage transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921
Synchronization
  chaotic behavior expts., DMA methods. *Lorrondo, H.A., + , T-IM Oct 97* 1183-1188
  freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
  metastability measurement, effect on commun. sig. proc. systs. *Brown, C., + , T-IM Feb 97* 61-64
Synchronous Digital Hierarchy
  clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
  two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211

T

Tactile systems (nonbiological); cf. Robot tactile systems
Telerobotics
3D meas. using video camera and range finder. *Chavand, F., + , T-IM Dec 97* 1229-1235
Temperature control
permitt. meas. of rice weevils, RF/microwave freq. *Nelson, S.O., + , T-IM Aug 97* 941-946
sapphire cryogenic dielec. resonators, perform. and pot. *Langham, C.D., + , T-IM Apr 97* 130-132
Temperature measurement
bridges, calib., resist. network. *White, D.R., + , T-IM Oct 97* 1068-1074
current loop, analog meas. cct. topol., act. subtraction. *Anderson, K.F., T-IM Oct 97* 1061-1067
resist. thermometry bridges, calib., resist. network. *White, D.R., + , T-IM Oct 97* 1068-1074
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
Test equipment
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825
Test equipment; cf. Automatic test equipment
Test facilities
portable E-field strength meter, traceable calib., µTEM cell. *Munter, K., + , T-IM Apr 97* 549-550
Test facilities; cf. Anechoic chambers (acoustic); Anechoic chambers (electromagnetic)
Testing
nonlinearity of data-acquisition syst. with interleaving/multiplexing. *Simoes, J.B., + , T-IM Dec 97* 1274-1279
Testing; cf. Analog system testing; Automatic testing; Circuit testing; Crack detection; Electronic equipment testing; Logic circuit testing; Semiconductor device testing
Textile industry
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
Text processing
spec. for common IEEE styles. *Plett, G.L., + , T-IM Dec 97* 1217-1223
Thermal converters
AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390
AC-DC voltage transfer std., freq. depend. *Pogliano, U., + , T-IM Apr 97* 373-376
AC-DC voltage transfer stds., lowest uncertainty level, CCE comparison. *Klonz, M., T-IM Apr 97* 342-346
AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
alternating voltage meas., ac-dc transfer stds., micropotentiometer-based calib. *Budovsky, I., T-IM Apr 97* 356-360
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
LV stds., 10 Hz, 1 MHz range. *Oldham, N.M., + , T-IM Apr 97* 395-398
multiconverter modules, thin-film multijunction thermal converters. *Kinard, J.R., + , T-IM Apr 97* 391-394
NIST thin-film multijunction thermal converters, micropotentiometers. *Kinard, J.R., + , T-IM Apr 97* 347-351
NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
thermal power transfer std., resistive voltage divider, comparator. *Shapiro, E.Z., + , T-IM Apr 97* 412-415
thermal voltage converters, LF perform., cct. models. *Oldham, N.M., + , T-IM Apr 97* 352-355
thin-film ac-dc converter with thermoresistive sens., temp. sens. *Katzmann, F.L., + , T-IM Apr 97* 382-386
Thermal factors
IEN primary group of std. resistors, working temp. *Boella, G., + , T-IM Apr 97* 311-313
microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
Thermal factors; cf. Power transformer thermal factors; Thermoelectricity; Thermoresistivity
Thermal variables control; cf. Temperature control
Thermal variables measurement
sapphire opt. cavity, thermal expansion coeff. meas. *Taylor, C.T., + , T-IM Apr 97* 183-185
Si spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587
Thermal variables measurement; cf. Temperature measurement
Thermoelectric devices
multiconverter modules, thin-film multijunction thermal converters. *Kinard, J.R., + , T-IM Apr 97* 391-394
Thermoelectric devices; cf. Thermal converters
Thermoelectricity
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
sens. for meas. thermal cond. of fluids. *Machut, C., + , T-IM Oct 97* 1128-1132
Thermoresistivity
Peltier sens. for meas. thermal cond. of fluids. *Machut, C., + , T-IM Oct 97* 1128-1132
Thickness measurement
multilayers permitt./permeab./thickness meas., waveguide. *Tantot, O., + , T-IM Apr 97* 519-522
Thin film devices
AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390
multiconverter modules, thin-film multijunction thermal converters. *Kinard, J.R., + , T-IM Apr 97* 391-394
Time dissemination
Allan modified variance, third-difference approach. *Greenhall, C.A., T-IM Jun 97* 696-703
std. time/freq. sig. broadcast via INSAT, differential mode. *Gupta, A.S., + , T-IM Apr 97* 212-215
Time domain analysis
power meter for highly distorted three-phase systs. *Carullo, A., + , T-IM Dec 97* 1262-1267
Time domain measurements
clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
K-factor hand-held meter, air-core CT. *Chih-Hsien Kung, + , T-IM Aug 97* 811-816
opt. digital correlator for solid surfaces vel. meas. *Zeitler, R., T-IM Aug 97* 803-806
phase noise and jitter meas., time domain anal./appl. *Cosart, L.D., + , T-IM Aug 97* 1016-1019
Time measurement
freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
num. method for transit time meas. in US sensor appls. *Bucci, G., + , T-IM Dec 97* 1241-1246
TOF pulsed integrated laser radar. *Palojarvi, P., + , T-IM Aug 97* 996-999
two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211
Time synchronization
clock stabil. charactn. and meas. in telecomms. *Bregni, S., T-IM Dec 97* 1284-1294
Timing jitter
sinewave fitting procedure for data acquisition channels characterization. *Schoukens, J., + , T-IM Aug 97* 1005-1010
time-resolved spectra global anal., param. precision. *van Stokkum, I.H.M., T-IM Aug 97* 764-768
Topology; cf. Circuit topology
Torque measurement
magnetoelastic transducer for torque and force meas. *Zakrzewski, J., T-IM Aug 97* 807-810
SAW sens., wirelessly interrogable, vehicular appls. *Pohl, A., + , T-IM Aug 97* 1031-1038
Tracking; cf. Radar tracking
Tracking loops; cf. Phase locked loops
Transceivers
posn.-sensitive detectors in atmos. turbulence, retroreflected beam. *Makynen, A., + , T-IM Oct 97* 1133-1136
Transducers
beam pick-up, versatile transducer for nuc. sci. *Sonck, M., + , T-IM Aug 97* 857-861
bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710
calib. of power transducers, PC-based adaptive software. *Chern-Lin Chen, + , T-IM Oct 97* 1145-1149
magnetoelastic transducer for torque and force meas. *Zakrzewski, J., T-IM Aug 97* 807-810
simple built-in current sensor for current monitoring in mixed-sig. ccts. *Siskos, S., + , T-IM Dec 97* 1301-1304

Transducers; cf. Acoustic transducers; Capacitance transducers; Intelligent sensors; Magnetic transducers; Microsensors; Multisensor systems; Optical transducers; Piezoelectric transducers; Robot sensing systems

Transfer functions
- direct digital synthesizer, jittered clock. *Yih-Chyun Jenq, T-IM Jun 97* 653-655
- LTI systs., nonstandard conditions, freq.-domain ident. *Pintelon, R., + , T-IM Feb 97* 65-71
- multisine synchronized meas. via DSP methods. *Varkonyi-Koczy, A.R., T-IM Aug 97* 929-932
- thermal voltage converters, LF perform., cct. models. *Oldham, N.M., + , T-IM Apr 97* 352-355

Transfer standards
- AC-DC voltage transfer std., freq. depend. *Pogliano, U., + , T-IM Apr 97* 373-376
- AC-DC voltage transfer stds., lowest uncertainty level, CCE comparison. *Klonz, M., T-IM Apr 97* 342-346
- AC voltage precision meas., sampling voltmeter. *Pogliano, U., T-IM Apr 97* 369-372
- alternating voltage meas., ac-dc transfer stds., micropotentiometer-based calib. *Budovsky, I., T-IM Apr 97* 356-360
- bifilar AC-DC resistor, microwire. *Semyonov, Yu.P., + , T-IM Apr 97* 333-336
- calculable HF AC-DC transfer std. *Van Mullem, C., + , T-IM Apr 97* 361-364
- FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
- freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219
- NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
- portable E-field strength meter, traceable calib., μTEM cell. *Munter, K., + , T-IM Apr 97* 549-550
- selected papers CPEM'96 (special issue). *T-IM Apr 97* 94-646
- thermal power transfer std., resistive voltage divider, comparator. *Shapiro, E.Z., + , T-IM Apr 97* 412-415
- time/freq. sig. broadcast via INSAT, differential mode. *Gupta, A.S., + , T-IM Apr 97* 212-215
- transportable compact Josephson voltage std. *Hamilton, C.A., + , T-IM Apr 97* 237-241
- two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208
- two-way time/freq. transfer, opt. fibers. *Jefferts, S.R., + , T-IM Apr 97* 209-211

Transforms; cf. Fourier transforms; Hilbert transforms

Transient analysis
- LTI systs., nonstandard conditions, freq.-domain ident. *Pintelon, R., + , T-IM Feb 97* 65-71
- scan conversion-based transient digitizers, improved sig. extraction. *Arpaia, P., + , T-IM Aug 97* 893-898

Transient response
- FIR differentiators with optimum noise atten., recursive implement. *Vainio, O., + , T-IM Oct 97* 1202-1207
- Poisson filtered procs., intens./impulse response fns. estim. *Mino, H., + , T-IM Oct 97* 1189-1195
- predictive IIR filters design, FIR predictors feedback extension. *Ovaska, S.J., + , T-IM Oct 97* 1196-1201
- sound localization in reverberant environ., precedence effect model. *Huang, J., + , T-IM Aug 97* 842-846

Transistors; cf. Heterojunction bipolar transistors; Microwave FETs; MODFETs; Power MESFETs; Tunnel transistors

Transition metal alloys; cf. Gold alloys; Iron alloys; Nickel alloys

Transition metal compounds; cf. Yttrium compounds

Transition metals; cf. Copper; Niobium

Transmission lines; cf. Coaxial transmission lines; Coupled transmission lines; Stripline; Waveguides

Transmission line theory; cf. Waveguide theory

Transmitters; cf. Optical transmitters

Transponders
- two-way time/freq. transfer, earth station errors. *Ascarrunz, F.G., + , T-IM Apr 97* 205-208

Tunable circuits and devices; cf. Laser tuning

Tuning
- seven-jn. electron pump, design, fab., and operation. *Keller, M.W., + , T-IM Apr 97* 307-310

Tunneling
- microwave filters atten., single-electron tunneling expts. *Fukushima, A., + , T-IM Apr 97* 289-293
- NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
- seven-jn. electron pump, design, fab., and operation. *Keller, M.W., + , T-IM Apr 97* 307-310

Tunneling; cf. Josephson effect

Tunnel transistors
- NIST charged-capacitor expt., SET pump. *Zimmerman, N.M., + , T-IM Apr 97* 294-298
- offset charge noise in SET devices. *Wolf, H., + , T-IM Apr 97* 303-306

TV cameras
- 3D meas. using video camera and range finder. *Chavand, F., + , T-IM Dec 97* 1229-1235

Two-port circuits
- noise params. meas., microwave freqs. *Bareau, P., + , T-IM Aug 97* 1044-1048

U

UHF amplifiers
- NIST amp. noise meas., noise-fig. meas. service. *Wait, D.F., + , T-IM Apr 97* 482-485

UHF measurements
- NIST amp. noise meas., noise-fig. meas. service. *Wait, D.F., + , T-IM Apr 97* 482-485

User interfaces
- calib. of power transducers, PC-based adaptive software. *Chern-Lin Chen, + , T-IM Oct 97* 1145-1149

User interfaces; cf. Graphical user interfaces

V

Vacuum systems
- refractometer, vac. cell/double-pass Michelson interferometer, air refr. index meas. *Fujii, K., + , T-IM Apr 97* 191-195

Vacuum technology
- supercond. mag. levitation syst., buoyancy-free mass comparator. *Fujii, Y., + , T-IM Apr 97* 609-612

Velocity measurement
- low-speed meas., multiple-electrode capacitive sens. *Xianjun Li, + , T-IM Apr 97* 636-639

Velocity measurement; cf. Optical velocity measurement

Very-large-scale integration
- fault online detect., DSP-based meas. *Baccigalupi, A., + , T-IM Jun 97* 731-736
- IC metallization meas. ultralow-noise data acquisition. *Ciofi, C., + , T-IM Aug 97* 789-793
- spectrometric data correction, Kalman-filter-based algms. *Massicotte, D., + , T-IM Jun 97* 678-684

VHF devices
- GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104

VHF measurements
- GaAlAs/GaAs HBTs, low VHF band, wideband on-wafer noise meas. *Roux, J.-P., + , T-IM Oct 97* 1100-1104

Vibration measurement
- laser displacement sens. for modal anal./defect detect. *Servagent, N., + , T-IM Aug 97* 847-850

Video signal processing
- freq. transfer, geostationary broadcasting satellite. *Morikawa, T., + , T-IM Apr 97* 216-219

Visual system
- cornea shape meas., pseudorandom color coding. *Vos, F.M., + , T-IM Aug 97* 794-797

Voltage controlled oscillators
- Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
- liq. level and leakage detect., planar capacitive precision gauge. *Toth, F.N., + , T-IM Apr 97* 644-646
- low-speed meas., multiple-electrode capacitive sens. *Xianjun Li, + , T-IM Apr 97* 636-639

Voltage dividers
- act. HV divider with 20 μV/V uncertainty, compressed-gas capacitor. *Petersons, O., + , T-IM Apr 97* 430-434
- bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710
- capacitance scaling syst., four-terminal-pair LCR meter, inductive voltage divider. *Aoki, T., + , T-IM Apr 97* 474-476
- digital impedance bridge based on two-phase generator. *Muciek, A., T-IM Apr 97* 467-470
- inductive voltage divider, ac-power meas., in-phase errors. *Zinkernagel, J., T-IM Oct 97* 1075-1080
- series-resistors-type voltage divider, common error sources. *Kyu-Tae Kim, + , T-IM Aug 97* 776-780

thermal power transfer std., resistive voltage divider, comparator. *Shapiro, E.Z., + , T-IM Apr 97* 412-415
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783

Voltage measurement
AC/DC thermal converter, quartz cryst. temp. sens. *Kampik, M., + , T-IM Apr 97* 387-390
AC-DC voltage transfer std., freq. depend. *Pogliano, U., + , T-IM Apr 97* 373-376
AC-DC voltage transfer stds., lowest uncertainty level, CCE comparison. *Klonz, M., T-IM Apr 97* 342-346
AC Josephson voltage std. for fast dc meas. and ac waveform synthesis. *Hamilton, C.A., + , T-IM Apr 97* 224-228
act. HV divider with 20 µV/V uncertainty, compressed-gas capacitor. *Petersons, O., + , T-IM Apr 97* 430-434
AC voltage precision meas., sampling voltmeter. *Pogliano, U., T-IM Apr 97* 369-372
alternating voltage meas., ac-dc transfer stds., micropotentiometer-based calib. *Budovsky, I., T-IM Apr 97* 356-360
bridge-transducer interface, continuous autocalibration. *van der Goes, F.M.L., + , T-IM Jun 97* 704-710
calculable HF AC-DC transfer std. *Van Mullem, C., + , T-IM Apr 97* 361-364
comments on “Accurate measurement of power, energy, and true RMS voltage using synchronous counting” by J.K. Kolanko (Jun 93 752-754). *Mauritzen, D.W., + , T-IM Dec 97* 1300-1301
FRDC, fast-reversed DC transfer difference meas., thermal converters, time consts. *Sasaki, H., + , T-IM Apr 97* 377-381
HF meas. procedure for differential building blocks. *Peeters, E.J.E.A., + , T-IM Aug 97* 1039-1043
Josephson array voltage std., high-Tc harmonic mixer. *Xue, S.Q., + , T-IM Apr 97* 250-252
Josephson array voltage stds., microwave phase-noise influence. *Godone, A., + , T-IM Apr 97* 246-249
Josephson-array voltage stds. of SP and BIPM, comparison. *Reymann, D., + , T-IM Apr 97* 220-223
Josephson jn. array, 10 V voltage std. syst. *Murayama, Y., + , T-IM Apr 97* 233-236
Josephson jn. array voltage std., null-balancing. *Yoshida, H., + , T-IM Apr 97* 260-263
Josephson-jn. array voltage std., step no. determ. *Ogita, E., + , T-IM Apr 97* 253-255
Josephson series array voltage std., hybrid IC. *Hebrank, F.X., + , T-IM Apr 97* 242-245
Josephson voltage std., 1 V/10 V, array cct. optim. *Muller, F., + , T-IM Apr 97* 229-232
LV stds., 10 Hz, 1 MHz range. *Oldham, N.M., + , T-IM Apr 97* 395-398
mobile cryocooled primary voltage std. without liq. He. *Yi-Hua Tang, + , T-IM Apr 97* 256-259
Nb/Al-AlO$_x$/Nb Josephson jn. array based on LF designs scaled up, 94 GHz. *Yoshida, H., + , T-IM Feb 97* 72-78
NIST thin-film multijunction thermal converters, micropotentiometers. *Kinard, J.R., + , T-IM Apr 97* 347-351
NRC AC-DC transfer capabilities, automated difference comparator. *Clark, R.F., + , T-IM Apr 97* 365-368
RF-DC differences of micropotentiometers. *De Xiang Huang, + , T-IM Apr 97* 337-341
selected papers CPEM’96 (special issue). *T-IM Apr 97* 94-646
series-resistors-type voltage divider, common error sources. *Kyu-Tae Kim, + , T-IM Aug 97* 776-780
seven-jn. electron pump, design, fab., and operation. *Keller, M.W., + , T-IM Apr 97* 307-310
thermal voltage converters, LF perform., cct. models. *Oldham, N.M., + , T-IM Apr 97* 352-355
thin-film ac-dc converter with thermoresistive sens., temp. sens. *Katzmann, F.L., + , T-IM Apr 97* 382-386
transients meas. in distributed const. syst. *Kawamata, K., + , T-IM Aug 97* 918-921
transients monitoring probe for gas insulated substation. *Osmokrovic, P., + , T-IM Feb 97* 36-44
transportable compact Josephson voltage std. *Hamilton, C.A., + , T-IM Apr 97* 237-241
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783
Zener voltage std. calib. at 10 V, KRISS vs ETL. *Kyu-Tae Kim, + , T-IM Apr 97* 314-317

Voltage transformers
compressed-gas capacitors meas., pot. transformer bridge. *Castelli, F., T-IM Aug 97* 822-825

Voltmeters
AC voltage precision meas., sampling voltmeter. *Pogliano, U., T-IM Apr 97* 369-372
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
wideband sampling voltmeter. *Souders, T.M., + , T-IM Aug 97* 947-953
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783

Volume measurement
Si spheres, precision vol. meas., Avogadro const. determ. *Sacconi, A., + , T-IM Apr 97* 584-587

W

Water
CZ cryst. growing furnaces, laser melt-level monitoring. *Zhixin Li, + , T-IM Jun 97* 722-730

Water resources
irrigation control, computerized water detect. *Turnell, D.J., + , T-IM Aug 97* 986-990

Wattmeters
PF calibrator using precise wattmeter, autocalibration procedure. *Zupunski, I.Z., + , T-IM Apr 97* 408-411
power measuring stds., automatic zero-PF/sampling wattmeter std. *Simonson, P., + , T-IM Apr 97* 423-425
thermal wattmeter, power comparator, ac power meas. *Laiz, H., + , T-IM Apr 97* 420-422
time-division watt-converter,frequency depend. systematic error, compensation. *Jovanovic, L.D., T-IM Apr 97* 416-419
wideband wattmeter based on RMS voltage meas. *Waltrip, B.C., + , T-IM Aug 97* 781-783

Waveguide components
K- and Ka-band waveguide microcalorimeters for microwave power standards. *Kang, T.W., + , T-IM Dec 97* 1247-1250
precision microwave testing of dielec. substrs. *Yushchenko, A.G., + , T-IM Apr 97* 507-510

Waveguide excitation
microwave meas. of semicond. waveguides, dielec. const. determ. *Platte, W., T-IM Jun 97* 717-721

Waveguides
microwave pulse meas., resistive sens. *Dagys, M., + , T-IM Apr 97* 499-502

Waveguides; cf. Circular waveguides; Planar waveguides; Rectangular waveguides; Semiconductor waveguides

Waveguide theory
precision microwave testing of dielec. substrs. *Yushchenko, A.G., + , T-IM Apr 97* 507-510

Wavelength measurement
extended-cavity LD stabilized on I$_2$, intracavity saturation spectrosc. *Zarka, A., + , T-IM Apr 97* 145-148

Weight measurement
NIST watt bal., kilogram monitoring, meas. uncertainties. *Steiner, R.L., + , T-IM Apr 97* 601-604
NPL moving-coil apparatus, Planck’s const. meas., kg stabil. monitoring. *Robinson, I.A., + , T-IM Apr 97* 596-600
paper basis-wt./ash-content meas., nuc. method. *Yi Shen, + , T-IM Aug 97* 937-940
supercond. mag. levitation syst., buoyancy-free mass comparator. *Fujii, Y., + , T-IM Apr 97* 609-612

White noise
freq. estim., drift rate, difference and least sq. methods. *Guo Wei, T-IM Feb 97* 79-82
HTSC DC SQUID-based magnetometer, direct-coupled electronics. *Gudoshnikov, S.A., + , T-IM Apr 97* 624-628

Windings
mutual inductance independent of primary winding posn. and ambient fields. *Miljanic, P.N., T-IM Apr 97* 471-473

Wire; cf. Amorphous magnetic wires

X

X-ray measurements
Si (220) lattice spacing, scanning X-ray interf., mm baseline. *Bergamin, A., + , T-IM Apr 97* 576-579
Si fine struct. const. determ. *Kruger, E., + , T-IM Apr 97* 101-103
Si, lattice spacing d(220), X-ray/opt. interferometry meas. *Nakayama, K., + , T-IM Apr 97* 580-583

Y

Yttrium compounds
YBCO resonators, freq. stds. *Gallop, J.C.,* + , *T-IM Apr 97* 122-125

Z

Zener diodes
DC nanovoltmeters and voltage ref. stds., spectral anal. *Witt, T.J., T-IM Apr 97* 318-321
voltage std. calib. at 10 V, KRISS vs ETL. *Kyu-Tae Kim,* + , *T-IM Apr 97* 314-317